

CARDIAC RHYTHM DISEASE MANAGEMENT

Product Performance Report

Important Patient Management Information for Physicians



A Message from the Vice President

Physicians are the foundation of our Quality efforts. For many years, Medtronic has involved independent physicians in our quality reporting process. Building on this model of manufacturer and physician collaboration, the Heart Rhythm Society (HRS) has now established formal guidelines for our entire industry. In full support of HRS recommendations, I am pleased to report that our Independent Physician Panel has recently convened and reviewed this 56th issue of Medtronic's Product Performance Report. We welcome and appreciate their valued insight, direction, and dedicated support.

In this issue, you will find new articles and data explaining how we estimate and perform relative to device battery longevity and ICD and CRT-D charge times. By striving to meet your expectations, we hope to continue to improve in these areas with each new device. In a third party study published in the October 2006 issue of Pacing and Clinical Electrophysiology¹, Medtronic was the only manufacturer whose devices met and even exceeded our longevity estimates. Since 1996, we have focused on charge time performance and have shown a progression toward shorter mean charge times and less variation of these charge times over the battery life of a device. We hope this added information will be helpful.

Our mission since 1960 has been "to strive without reserve for the greatest possible reliability and quality in our products, to be the unsurpassed standard of comparison, and to be recognized as a company of dedication, honesty, integrity, and service." Your participation in our quality process is valued and appreciated. Medtronic tests and evaluates returned product to measure and report the performance of our devices and improve our technologies. Please contact CRDM Returned Product Quality at 1 (800) 328-2518, extension 44800 or ask your local Medtronic representative to help facilitate the return of explanted Medtronic devices.

We also welcome your collaboration, insight, and recommendations. Please contact our Technical Services Department at 1 (800) 723-4636 with your feedback, comments, and any questions.

With appreciation and warm regards,

Reggie Groves

Vice President, Quality and Regulatory

Medtronic Cardiac Rhythm Disease Management

Medtronic, Inc.

¹ Senaratne J, Irwin ME, Senaratne MP. Pacemaker longevity: Are we getting what we are promised? Pacing Clin Electrophysiol. October 2006;29(10):1044-1054.

Contact Information

We invite our customers to use these telephone numbers to call with suggestions, inquiries, or specific problems related to our products.

US Technical Services Department

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For questions related to returning explanted product or returning product that shows signs of malfunction, please contact:

Outside the United States:

Your Medtronic representative or international technical center at the number above.

Within the United States:

Your Medtronic representative or

CRDM Returned Product Analysis Laboratory

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This report is available online at www.CRDMPPR.medtronic.com

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Consistent Performance of CRT-D and ICD Charge Time page 145

New Products

Adapta Concerto CRT-D Sensia Versa Virtuoso ICD

Introduction

All product performance reports are not created equal. For over 20 years, Medtronic has monitored performance via both returned product analysis and multicenter clinical studies.

This Product Performance Report (PPR) presents device survival estimates, advisory summaries, performance notes, and other information pertinent to assessing the performance of Medtronic implantable pulse generators (IPGs), implantable cardioverter defibrillators (ICDs), Cardiac Resynchronization Therapy (CRT) devices, and implantable pacing and defibrillation leads.

This Product Performance Report has been prepared in accordance with International Standard ISO 5841- 2:2000(E).

The survival estimates provided in this report are considered to be representative of worldwide performance.

Survival Estimates

Medtronic Cardiac Rhythm Disease Management (CRDM) uses both returned product analysis and multicenter clinical studies to monitor performance.

Medtronic, like other companies, monitors CRT, ICD, and IPG device performance using returned product analysis. We also monitor CRT, ICD, and IPG device performance using an active multicenter clinical study. Medtronic CRDM is unique in the industry in that we track CRT, ICD, and IPG device survival using both methods.

Returned product analysis is a passive approach to assessing product performance. This approach provides a suitable measure of product performance only when a significant number of explanted products are returned to the manufacturer. Returned product analysis provides a measure of hardware performance, but not necessarily the total clinical performance (e.g., the incidence of complications such as infection, erosion, muscle stimulation, etc. are not estimated).

The survival estimates provided in this report for CRT, ICD, and IPG devices are based on returned product analysis. This approach is suitable because a significant number of explanted generators are returned for analysis.

Lead performance is monitored differently. In contrast to CRT, ICD, and IPG devices, a very small percentage of leads are returned to the manufacturer due to the difficulty of explanting them. For leads, an active clinical study provides more accurate survival estimates compared to estimates based solely on returned product analysis.

Survival estimates for leads are based on clinical observations recorded via Medtronic CRDM's System Longevity Study. This multicenter clinical study is

designed to record clinical observations representative of the total clinical experience. Therefore, the lead survival estimates include both lead hardware failure and lead related medical complications, and do not differentiate a lead hardware failure from other clinical events such as exit block, perforation, dislodgement, or concurrent pulse generator failure.

The actuarial life table method is applied to the data collected for CRT, ICD, and IPG devices and leads to provide the survival estimates included in this report. A general introduction to understanding this method of survival analysis is given later in this introduction.

ICD Charge Times

For several years, Medtronic has provided important information on charge time performance of ICDs. The information provided in this report shows how ICD charge time can vary during the time a device is implanted. The information is presented in graphical format showing charge time as a function of implant time. The data for charge times are collected from devices enrolled in the System Longevity Study.

Advisory Summaries

This Product Performance Report includes summaries of all advisories applicable to the performance of the products included in the report. An advisory is added to the report when any product affected by the advisory remains in service and at risk of experiencing the behavior described in the advisory. The advisory will remain in the report until Medtronic estimates no product affected by the advisory remains active, or the risk of experiencing the behavior described in the advisory has passed.

For most advisories, the products subject to the advisory retain essentially the same survival probability as the products of the same model(s) not affected by the advisory. For those advisories where the survival probabilities of the affected and non-affected populations do differ significantly Medtronic will provide separate survival data for each population. The separate survival data will remain in the report until Medtronic estimates no affected product remains in active service.

Performance Notes

This report concludes with a number of Performance Notes developed by Medtronic to provide additional product performance information relevant to follow-up practice and patient management.

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

How You Can Help

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of the reason for explant or removal from use. The procedures for returning product vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRTs, ICDs, IPGs, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of explanted product from non-clinical sources such as funeral homes, and will assume responsibility for storage and disposal of the product once received. For return of larger quantities of explanted products than the mailer can accommodate, Medtronic has handling and shipping guidelines available upon request.

Both mailers and guidelines can be requested by contacting the Returned Product Lab. For information on how to contact the Lab, refer to Contact Information on page 2 of this report.

We continually strive to improve this CRDM Product Performance Report. In keeping with this philosophy, we ask for your suggestions on the content and format of this report, as well as any information you have regarding the performance of Medtronic products. For information on how to comment on this report, see Contact Information on page 2 of this report.

Overview of Survival Analysis

Medtronic uses the Cutler-Ederer actuarial life table method to estimate the length of time over which devices and leads will perform within performance limits established by Medtronic. This probability to perform within performance limits over time is called the *survival probability*.

Devices and leads are followed until an *event* occurs where the device or lead ceases to operate within performance limits. The length of time from implant to the event is recorded for each individual device and lead in the *population sample*. The population sample for CRT, ICD, and IPG devices is made up of patients whose devices are registered as implanted in the United States. For leads, the population sample is the patients enrolled in the System Longevity Study.

For IPGs and ICDs, the events can be normal battery depletion or a device malfunction. For leads, the events are complications as defined for the study.

The actuarial life table method allows Medtronic to account for devices and leads removed from service for reasons unrelated to performance. Devices and leads removed for these reasons are said to be *suspended*. Examples include devices and leads:

- still in service at the time the analysis is performed
- removed to upgrade the device or lead
- no longer in service due to the death of the patient for reasons unrelated to the device or leads, or
- implanted in patients who are lost to follow-up.

For each suspension, the device or lead has performed within performance limits for a period of time, after which its performance is unknown.

An Example

The following example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads. The example is intended to provide an overview of the analysis process. The definitions of malfunctions and complications, and other details specific to calculating device and lead survival estimates, are provided in the articles *Method for Estimating CRT, ICD, and IPG Device Performance (page 9)* and *Method for Estimating Lead Performance (page 79)*.

This simple example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads.

Figure 1

Implant times for devices of 16 patients. Gray bars with an orange X indicate devices removed from service due to an event. Blue bars indicate suspended devices.

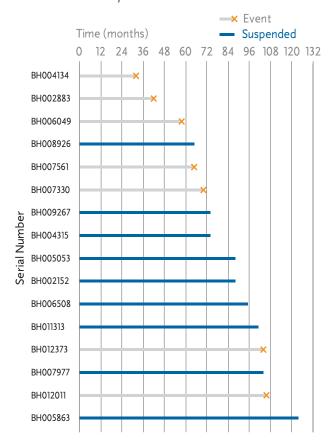


Figure 1 illustrates 16 patients who have implanted devices. The first patient's device (serial number BH004134) operated within performance limits for 32 months. At that time an event occurred. The fourth patient's device (serial number BH008926) did not have an event but is suspended, perhaps because it was still in service at the time of the analysis. This patient had 66 months of implant experience. In this example, Figure 1 shows that 7 of the 16 devices suffered events, and 9 are suspended.

The first step in the life table method is to divide the implant time into intervals of a specific length. This example will use 12-month intervals. The number of devices entered, suspended, and removed due to an event are counted and summarized as shown in Table 1. For the first two intervals, all 16 devices survived and none were removed. In the interval (24-36 months), device BH004134 was removed due to an event. Therefore the table entries show that 16 entered the interval, none were suspended, and one was removed due to an event.

For interval from 36-48 months, only 15 devices entered the interval and one was removed for an event. The remaining intervals are examined and the data entered in columns A, B, and C in like manner. The rest of the columns are filled in using calculations on the data in columns A, B, and C.

The Effective Sample Size (D) is the number of devices with full opportunity to experience a qualifying event in the interval. This is computed by subtracting one half the number suspended in the interval from the number that entered the interval. This calculation more accurately reflects the number of devices that could have experienced a qualifying event than simply using the number that entered the interval. Using the number of devices that enter an interval over-estimates the sample size because the suspended devices do not complete the interval. Ignoring the suspended devices under-estimates the sample size because suspended devices are not credited with their full service time. Using one half the number of suspended devices effectively splits the difference.

The next column in the table is the *Proportion with Event* (E). This is the proportion of devices that had an event in the interval. It is calculated by dividing the *Number of Events* (C) by the *Effective Sample Size* (D). The number can be interpreted as the estimated rate at which events occur in the time interval.

The *Interval Survival Probability* (**F**) is the estimate of probability of surviving to the end of the interval assuming the device was working at the beginning of the interval. It is calculated as 1 minus the *Proportion With Event* (**E**). This number can be interpreted as the estimated rate at which events **do not** occur in the time interval.

The Cumulative Survival Probabilities from (G) the last column of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data shown in Table 1.

Table 1 Life Table for Figure 1

	A	В	С	D	E	F	G
Interval in Months	Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
0	16	0	0	16	0.000	1.000	1.000
0-12	16	0	0	16	0.000	1.000	1.000
12-24	16	0	0	16	0.000	1.000	1.000
24-36	16	0	1	16	0.063	0.938	0.938
36-48	15	0	1	15	0.067	0.933	0.875
48-60	14	0	1	14	0.071	0.929	0.813
60-72	13	1	2	12.5	0.160	0.840	0.683
72-84	10	2	0	9	0.000	1.000	0.683
84-96	8	3	0	6.5	0.000	1.000	0.683
96-108	5	2	2	4	0.500	0.500	0.341
108-120	1	0	0	1	0.000	1.000	0.341
120-132	1	1	0	0.5	0.000	1.000	0.341

Definitions:

A Number Entered	B Number Suspended	C Number of Events	D Effective Sample Size	E Proportion with Event	F Interval Survival Probability	G Cumulative Survival Probability
Number of devices active at the start of the interval	Number of devices removed from service for reasons other than an event	Number of units removed from service due to an event	Number of units with full opportunity to experience a qualifying event in the interval. Computed by subtracting one half the Number Suspended from the Number Entered	Proportion of devices that had an event in the interval. Computed by dividing the Number of Events by the Effective Sample Size	The probability of surviving to the end of the interval, assuming the device was working at the beginning of the interval. Computed as 1 minus the Proportion With Event	The overall probability of surviving to the end of the interval. Computed by multiplying the Interval Survival Probability by the previous interval's Cumulative Survival Probability

Cumulative Survival Probability (G) is the estimate of the unconditional probability of surviving to the end of the interval. It is computed by multiplying the *Interval Survival Probability* (F) by the previous interval's Cumulative Survival Probability. The probability of surviving to 132 months in the example is estimated for the table to be 0.341, or 34.1%.

The *Cumulative Survival Probabilities* (**G**) of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data in Table 1.

Cumulative Survival Probability (%)

100 90 80 70 60 50 40 30 24 36 48 96 108 0 12 60 72 84 120 Time (months) 0 12 36 48 60 72 84 96 108 120 132 93.8 87.5 81.3 68.3 68.3 68.3 34.1 34.1 100 100 100 34.1 % 16 16 16 15 12.5 6.5 0.5 Effective Sample Size

Figure 2 Survival Curve for Data Given in Table 1

Confidence Intervals

Since survival curves are based on a sample of the device and lead population, they are only estimates of survival. The larger the effective sample size, the more confident the estimate. A confidence interval can be calculated to assess the confidence in an estimate. In the Product Performance Report, Medtronic provides a 95% confidence interval. This can be interpreted as meaning that 95% of the time, the true survival of the device will fall somewhere in the interval.

Survival Curves in the Product Performance Report

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRTs, ICDs, and IPGs, and when the number entered is less than 50 for leads. The survival charts in the Product Performance Report show the effective sample size for each year interval where Medtronic has experience. When the effective sample size reaches 100 for CRTs, ICDs, and IPGs or when the number entered reaches 50 for leads, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals (for CRT, ICD, and IPG devices) or three-month intervals (for leads).

A number of references are available for additional information on survival analysis using the Cutler-Ederer life table method.¹

Lee, Elisa T.(2003) Statistical Methods for Survival Data Analysis
 3rd Edition (Wiley Series in Probability and Statistics)

Method for Estimating CRT, ICD, and IPG Device Performance

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

The performance of CRT, ICD, and IPG devices is expressed in terms of device survival estimates, where "survival" refers to the function of the device, not the survival of the patient. These survival estimates are intended to illustrate the probability that a device will survive for a given number of years with neither malfunction nor battery depletion.

The survival estimates are determined from the analysis of Medtronic CRDM's device registration data and returned product analysis data. These data are presented graphically and numerically.

Because this analysis is based on returned product analysis, the performance data does not reflect any device-related medical complications, such as erosion, infection, muscle stimulation, or muscle inhibition.

Categorization of Depleted and Malfunctioning Devices for Survival Analysis

For survival estimation, every device returned to Medtronic CRDM and analyzed in the CRDM Returned Product Analysis laboratory is assigned to one of three categories. The device 1) has functioned normally, 2) has reached normal battery depletion, or 3) has malfunctioned. This categorization is combined with data from our device registry for the total number of implants and the implant durations to create the survival curves presented on the following pages.

Medtronic CRDM considers a device as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction or battery depletion, the device must have been returned to Medtronic and analyzed.

Devices damaged after explant, damaged due to failure to heed warnings or contraindications in the labeling, or damaged due to interaction with other implanted devices (including leads) are not considered device malfunctions.

A device subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

Not all malfunctions expose the patient to a loss of pacing or defibrillation therapy. Some malfunctions included in the following survival estimates may not have been detected at all by the physician or the patient. These malfunctions, however, are included in the survival estimates and provide important feedback to our product development organization.

To provide insight into the nature of malfunctions, each malfunction is categorized as Malfunction with Compromised Therapy Function or Malfunction without Compromised Therapy Function. A summary of these malfunctions is presented for the most recently market-released models.

For this report, Normal Battery Depletion, Malfunction with Compromised Therapy Function and Malfunction without Compromised Therapy Function are defined as follows:

Normal Battery Depletion - The condition when

- (a) A device is returned with no associated complaint and the device has reached its elective replacement indicator(s) with implant time that meets or exceeds the nominal (50 percentile) predicted longevity at default (labeled) settings, or
- (b) A device is returned and the device has reached its elective replacement indicator(s) with implant time exceeding 80% of the expected longevity calculated using the available device setting information.

Medtronic CRDM establishes expected longevity by statistically characterizing the power consumed by the device and the power available from the device battery. This characterization is applied to a number of parameter configurations to derive a statistical mean longevity value and standard deviation for each parameter configuration. The statistical mean value minus three standard deviations is used as the expected longevity for determining if a battery depleted normally.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

The Standard Actuarial Method is used to estimate IPG and ICD survival. This product performance report has been prepared in accordance with International Standard ISO 5841-2:2000(E).

For reference purposes, the following pages include an estimated longevity for each model. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from this estimate.

Malfunction with Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that compromised pacing or defibrillation therapy (including complete loss or partial degradation), while implanted and in service, as confirmed by laboratory analysis.

Examples: Sudden loss of battery voltage; accelerated current drain such that low battery was not detected before loss of therapy; sudden malfunction during defibrillation therapy resulting in aborted delivery of therapy, intermittent malfunction where therapy is compromised while in the malfunction state.

Malfunction without Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that *did not* compromise pacing or defibrillation therapy, while implanted and in service, as confirmed by laboratory analysis.

Examples: Error affecting diagnostic functions, telemetry function, data storage; malfunction of a component that causes battery to lose power quickly enough to cause premature battery depletion, but slowly enough that the condition is detected through normal follow-up before therapy is lost; mechanical problems with connector header that do not affect therapy.

Laboratory Analysis Process

Analysis of returned product is performed according to written procedures. These procedures determine the minimum analysis required. The analysis required varies depending on the type of device, age of the device, the associated information received with the device, actual experience with models of similar design, and other factors. Additional analysis is performed as necessary to investigate a performance concern from a customer, or to collect specific reliability data.

When a device is returned with a performance concern from a customer, the general analysis process includes a preliminary analysis of the device in its as-received condition, followed by an automated functional test using test equipment equivalent to the equipment used in manufacturing.

When a malfunction is identified, failure analysis is performed to provide the detailed information necessary to investigate possible causes and actions. Medtronic CRDM maintains in-house expertise and performs its failure analysis using facilities it owns and supports. This capability permits detailed failure analysis.

Statistical Methods for Survival Analysis

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of IPG and ICD survival. This method is commonly used by medical researchers and clinicians.

Implant times are calculated from the implant date to the earlier of the explant date or the cutoff date of the report. From this data an estimate of the probability of device survival is calculated at each monthly interval.

On the following pages, each graph includes an all-cause survival curve, where events include malfunctions and battery depletions. The all-cause survival is a good representation of the probability a device will survive a period of time without malfunction and without battery depletion. For example, if a device survival probability is 95% after 5 years of service, then the device has a 5% chance of being removed due to battery depletion or malfunction in the first five years following implant.

In addition to the all-cause survival curve, a second curve is included to show malfunction-free survival. Malfunction-free survival is a good representation of the probability for a device to survive without malfunction. This curve includes only malfunctions as events and excludes normal battery depletion.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRT, ICD, and IPG devices. The survival charts in the Product Performance Report show the effective sample size for each year interval where we have experience. When the effective sample size reaches 100, the next data point is added to the survival curve.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

Medtronic CRDM adjusts all-cause survival estimates to account for underreporting. While this lowers our all-cause survival estimates, we feel it gives a more accurate perspective on real performance.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have 1 or more malfunctions or battery depletions. This occurs because even with the malfunctions or battery depletions, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors and the complementary log-log method is used to produce the confidence bounds.

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the devices registered as implanted in the United States as of the report cutoff date. The number of registered implants, as well as an estimate of the number that remain in active service, is listed for each model. To be included in the population, the device must have been registered with Medtronic's registration system and implanted for at least one day.

This sample based on US implants is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

In general, a model or model family will be included in this report when it has accumulated at least 10,000 implant months, and will remain in the report as long as at least 500 devices remain active.

Methods Used to Adjust for Underreporting of Malfunction and Battery Depletion

The tables on the following pages show the actual number of malfunctions and battery depletions recorded by the analysis lab for US registered devices. Since not all devices are returned to Medtronic CRDM for analysis, these numbers underestimate the true

number of malfunctions and battery depletions. To more accurately estimate the all-cause device survival probabilities, the number of malfunctions and battery depletions used to plot each interval of the all-cause survival curves is adjusted (multiplied) by a factor that is based on an estimate of the magnitude of underreporting. The magnitude of underreporting is estimated by analyzing experience in clinical studies (including the System Longevity Study) and the device registration system.

However, at this time, no adjustment for underreporting is applied to the malfunction-free survival curve because a method for estimating malfunction-only underreporting has not been developed.

Adjustments to Registered Implants to Compensate for Unreported Devices Removed from Service

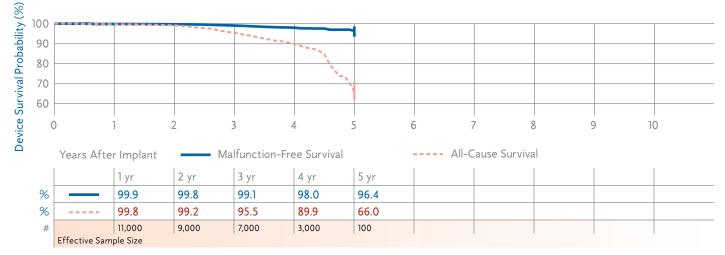
Devices are at times removed from service for reasons other than device malfunction or battery depletion. Examples are devices removed from service due to non-device related patient mortality and devices removed due to changes in the patient's medical condition. Because an accurate estimate of device survival depends on an accurate estimate of the number of devices in service, it is important not to overstate the number of devices in service.

To ensure the number of devices in service is not overstated, the patient mortality rate derived from our device registration system is monitored and compared to published mortality rates for comparable patient populations. If, during calculation of the survival curves, the patient mortality indicated by the data in our device registration is significantly different from published rates, an adjustment is applied to correct the difference.

7272 InSync ICD

Product Characteristics

US Market Release	Jul-02	NBD Code	VVED
Registered US Implants	13,000	Serial Number Prefix/X-ray ID	PJP
Estimated Active US Implants	5,000	Max Delivered Energy	34 J
Normal Battery Depletions	261	Estimated Longevity	See page 19
Malfunctions	153		
Therapy Function Not Compromised Therapy Function Compromised	140 13		
Advisories	None		



7277 InSync Marquis

Product Characteristics

	US Market R	elease		Mar-03			NBD Code			VVED	
	Registered L	JS Implants		7,000			Serial Numb	oer Prefix/X-r	ay ID	PLT	
	Estimated A	ctive US Impl	ants	2,000			Max Deliver	ed Energy		30 J	
	Normal Batt	ery Depletion	s	175			Estimated L	ongevity		See page	19
	Malfunction	s		69	(8 related to	advisory)					
			Not Compromion Comprom		(0 related to						
	Advisories			1	see page 15	6 – 2005 Pote	ential Prematu	re Battery De	pletion D	ue to Batte	ry Short
100 90			-								
80			***								
80	Years Afte	r Implant	2 Ma	3 Ilfunction-Fro	ee Survival	5	6 All-0	7 Cause Surviv	8 al	9	10
(r Implant 1 yr	2 Ma	3 Ifunction-Fro	ee Survival	5				9	10
		r Implant	2 Ma	3 Ilfunction-Fro	ee Survival	5				9	10

Effective Sample Size



Device Survival Probability (%)

7289 InSync II Marquis

Product Characteristics

-,									
US Market	Release		Jul-	-03		NBD Code		VVED	
Registered	US Implants	S	28,0	000		Serial Numb	oer Prefix/X-ray I	O PRJ	
Estimated	Active US In	nplants	15,0	000		Max Deliver	red Energy	30 J	
Normal Ba	ttery Deplet	ions	:	315		Estimated L	ongevity	See page	19
Malfunctio	ns			87 (5 related	d to advisory)				 '
The		on Not Comp nction Comp		64 (0 related 23 (5 related					
Advisories				1 see page	<u>156</u> – 2005 Po	<mark>tential Prematu</mark>	<mark>ire Battery Deple</mark> t	ion Due to Batte	ry Short
Advisories		***		1 see page	156 – 2005 Po	tential Prematu	re Battery Deplet	ion Due to Batte	ry Short
Advisories	1	2	3	1 see page	156 – 2005 Po	tential Prematu	re Battery Deplet	ion Due to Batte	ry Short
0	1 er Implant	2		4	5	6			
0	1	2	3	4	5	6	7 8		
0	1 er Implant	2	3 Malfunction-	4 Free Surviva	5	6	7 8		
0	1 er Implant	2 2 yr	3 Malfunction-	4 Free Surviva	5	6	7 8		

7297 InSync Sentry

Effective Sample Size

	US Market R	Release		Nov-04		NBD Code			VVED)	
	Registered l	JS Implants		9,000		Serial Numb	er Prefix/X-r	ay ID	PRK		
	Estimated A	ctive US Impl	ants	7,000		Max Deliver	ed Energy		35 J		
	Normal Batt	ery Depletion	s	10		Estimated L	ongevity		See p	age 19	
	Malfunction	s		7							
			Not Comprom ion Comprom								
	Advisories			None							
Oevice Survival Probability (%) % % % 0 0 0											10
e Surviva	0 Years Afte	r Implant	1	 function-Fre	e Survival	6 All-C	/ Cause Surviv	8 al 	9		10
evice %		1 yr	at 23 mo								
å %		99.9	99.3								
/o #		7,000	300								
,,	Effective Sam	1 '					1		1		



Device Survival Probability (%)

100 90 80

7299 InSync Sentry

Product Characteristics

US Market Release	Apr-05		NBD Code		VVEI	D	
Registered US Implants	28,000		Serial Number Prefix	c/X-ray ID	PRK		
Estimated Active US Implants	25,000		Max Delivered Energ	gy	35 J		
Normal Battery Depletions	5		Estimated Longevity	1	See	page 19	
Malfunctions	8						
Therapy Function Not Compromised Therapy Function Compromised	5 3						
Advisories	None						
· · · · · · · · · · · · · · · · · · ·							
1 2 3	1						0
1 2 3	4	2	6 /	8	9	I	0

Years After Implant ---- Malfunction-Free Survival ---- All-Cause Survival 1 yr at 18 mo 100.0 100.0 99.8 99.8 300 9,000 Effective Sample Size

7303 InSync Maximo

	•						1 TOUGET C			
	US Market R	Release		Jun-04	!		NBD Code		VVED	
	Registered l	JS Implants		17,000)		Serial Numb	er Prefix/X-ray ID	PRL	
	Estimated A	ctive US Imp	lants	13,000)		Max Deliver	ed Energy	35 J	
	Normal Batt	ery Depletion	ns	64	ļ		Estimated L	ongevity	See page 1	9
	Malfunction	s		16	5					_
		apy Function Therapy Func								
	Advisories			None	2					
90										
80		1	2	2	4 5	:	6	7 8		10
	Years Afte			3 1alfunction-Fr	4 5 ee Survival	;	6 All-0	7 8 Cause Survival	9	10
80	Years Afte	1 yr	2 yr	lalfunction-Fr	4 5 ee Survival	;			9	10
80 (%	Years Afte	1 yr	2 yr 99.9	lalfunction-Front at 29 mo	4 5	j			9	10
80	Years Afte	1 yr	2 yr	lalfunction-Fr	4 5 ee Survival	5			9	10

Therapy Function Compromised

100.0

99.9

100



7304 InSync Maximo

Advisories

%

Device Survival Probability (%)

100.0

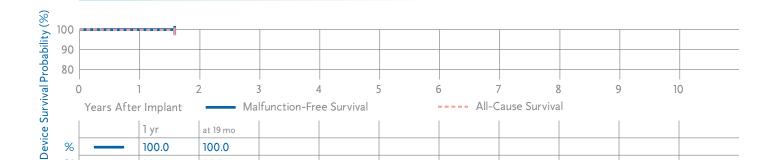
99.9

6,000

Effective Sample Size

Product Characteristics

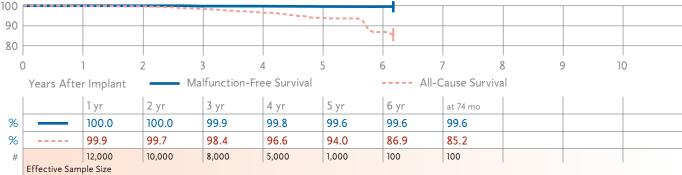
US Market Release	Apr-05	NBD Code	VVED
Registered US Implants	14,000	Serial Number Prefix/X-ray ID	PRL
Estimated Active US Implants	12,000	Max Delivered Energy	35 J
Normal Battery Depletions	3	Estimated Longevity	See page 19
Malfunctions	3		
Therapy Function Not Compromised	2		



8040 InSync **Product Characteristics**

None

	US Market Release		Aug-01		NBG Code		DD	DR	
	Registered US Implants		15,000		Serial Numb	er Prefix/X-ra	y ID PIN	I	
	Estimated Active US Im	plants	6,000		Estimated Lo	ongevity	See	e page 19	
	Normal Battery Depletion	ons	161						
	Malfunctions		20						
		n Not Compromised ction Compromised	5 15						
	Advisories		None						
					_				
100				 ,					





8042 InSync III

Product Characteristics

	noyne in						Product	.naracteristics		
	US Market R	elease		Feb-0)3		NBG Code		DDDR	
	Registered L	JS Implants		21,00	0		Serial Num	ber Prefix/X-ray ID	PKF	
	Estimated A	ctive US Imp	lants	14,00	0		Estimated	Longevity	See page 19)
	Normal Batt	ery Depletion	15	2	2					
	Malfunction	s			5					
			Not Compror tion Compror		2					
	Advisories			Non	e					
90						-+-1				
C)	1	2	3	4	5	6	7 8	9	10
	Years After	r Implant	M	alfunction-F	ree Survival		All-	Cause Survival		
		1 yr	2 yr	3 yr	4 yr	5 yr	at 62 mo			
%		100.0	100.0	99.9	99.9	99.9	99.9			
%		100.0	99.9	99.5	98.0	95.8	95.8			
#		14,000	10,000	4,000	200	100	100			
	Effective Sam									

C154DWK, C164AWK, C174AWK Concerto

٠.,	WK, C164	AWK, CI	/4AWK	Concer	10		Proc	luct Charac	teristics			
	US Market F	Release		Ma	ау-06		NBD	Code		VVE	D	
	Registered I	JS Implants		(6,000		Seria	l Number Pr	efix/X-ray ID	PVU	, PVT, PVR	
	Estimated A	ctive US Imp	lants	(6,000		Max	Delivered En	iergy	35 J		
	Normal Batt	ery Depletio	ns		0		Estir	nated Longe	vity	See	page 19	
	Malfunction	S			0							
		apy Function Therapy Func			0							
	Advisories				None							
90 80												
(0	1	2	3	4	5	6	7	8	9	' 1	0
%	Years Afte	r Implant at 5 mo			4 on-Free Surv		6	7 All-Caus	e Survival	9		0
		at 5 mo						7 - All-Caus		9		0



Device Survival Summary (95% Confidence Interval)

The following table shows CRT device survival estimates with 95% confidence intervals. Estimates are shown for both malfunction-free survival (which excludes normal battery depletion).

Family US Market Release US Implants US Implants 13,000	S pa		р											
	ətsmi U əvi etnsl	snoitelo	rapy Fund npromise rapy ction Not	ubromisea		Years Af	Years After Implant	nt						
	Esti Act Imp	Dep	Con	Con		l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
	2,000	261	13 + 140	0 = 153	Malfunction- free	99.9	99.8	99.1 +0.2/-0.2	98.0 +0.3/-0.4	96.4 +1.2/-1.7				
					All-cause	99.8	99.2	95.5	89.9 +0.7/-0.8	66.0				
Mar-03 7,000	2,000 175	75	09 + 6	69 = 0	Malfunction- free	100.0	98.9 +0.3/-0.4	98.1 +0.4/-0.5	97.9 +0.5/-0.6 at 44 mo					
Advisories: see page 156 – 2005 Potential Premature Battery Depletion Due to Battery Short	S Potential ue to Battery Shor		$\frac{(8)}{(advisory-related subset)}$) = (8) ited subset)	All-cause	99.9 +0.1/-0.1	92.5	87.1 +1.1/-1.2	86.7 +1.1/-1.2 at 44 mo					
Jul-03 28,000	15,000	315	23 + 64	1 = 87	Malfunction- free	99.9	99.7 +0.1/-0.1	99.3	99.2 +0.3/-0.4 at 39 mo					
Advisories: see page 156 – 2005 Potential Premature Battery Depletion Due to Battery Short	S Potential ue to Battery Shor		$\frac{(5)}{(advisory-related subset)} = (5)$) = (5) ited subset)	All-cause	99.8	97.5 +0.2/-0.2	94.0	93.6 +0.6/-0.7 at 39 mo					
Nov-04 9,000	2,000	10	1 + 6	_ 7	Malfunction- free	100.0+	99.8 +0.1/-0.2 at 23 mo							
					All-cause	99.9	99.3 +0.2/-0.3 at 23 mo							
Apr-05 28,000	00 25,000	2	3 + 5	∞ II	Malfunction- free	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 18 mo							
					All-cause	99.8 +0.1/-0.1	99.8 +0.1/-0.1 at 18 mo							
Jun-04 17,000	13,000	64	3 + 13	= 16	Malfunction- free	100.0+0.0/-0.0	99.9	99.9 +0.1/-0.1 at 29 mo						
					All-cause	99.9 +0.0/-0.1	98.4 +0.3/-0.3	97.6 +0.5/-0.6 at 29 mo						
Apr-05 14,000	0 12,000	ю	1 + 2		Malfunction- free	100.0+0.0/-0.0	100.0 +0.0/-0.1 at 19 mo							
					All-cause	99.9 +0.0/-0.1	99.9 +0.1/-0.1 at 19 mo							

C	R

					ı	Malfunctions	ctions				Device S	Device Survival Probability (%)	obability	(%)					
7		Market sase	berered stnslqm	bətsm ZU əvi stnsl	mal Battery detions	rapy Function promised	rapy ction Not	npromised	la 		Years Af	Years After Implant	ınt						
Number	Family			tэА	Nor	The Con	un⊴		τοτ		l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
8040	InSync	Aug-01	15,000	000'9	161	15 +	5	= 2	20	Malfunction- free	100.0+0.0/-0.0	100.0	99.9 +0.0/-0.1	99.8 +0.1/-0.1	99.6 +0.2/-0.3	99.6	99.6 +0.2/-0.3 at 74 mo		
										All-cause	99.9 +0.0/-0.1	99.7 +0.1/-0.1	98.4 +0.2/-0.3	96.6	94.0 +0.7/-0.8	86.9	85.2 +4.0/-5.3 at 74 mo		
8042	InSync III	Feb-03	21,000	14,000	22	3 +	2	Ш	2	Malfunction- free	100.0+0.0/-0.0	100.0+0.0/-0.0	99.9 +0.0/-0.1	99.9 +0.1/-0.3	99.9 +0.1/-0.3	99.9 +0.1/-0.3 at 62 mo			
										All-cause 100.0 +0.0/-0.0	100.0+0.0/-0.0	99.9 +0.0/-0.1	99.5 +0.1/-0.2	98.0 +1.0/-2.2	95.8 +1.9/-3.6	95.8 +1.9/-3.6 at 62 mo			
C154DWK, C164AWK, C174AWK	Concerto	May-06	000'9	000'9	0	+	0	0		Malfunction- free	100.0 +0.0/-0.0 at 5 mo								
										All-cause 100.0 +0.0/-0.0 at 5 mo	100.0 +0.0/-0.0 at 5 mo								



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

						stimate	d Longe	vity		Flective I	Replacement	
					·***						RI)***	End of Life
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	(EOL) Battery Voltage
7272	InSync ICD	DR+LV	66 cc 117 g	34 J	Monthly Quarterly Semiannual	5.4 6.5 6.9	6.3 8.0 8.5	7.3 9.4 10.3	7.8 10.3 11.2	≤ 4.91 V	-	≤ 4.57 V
7277	InSync Marquis	DR+LV split	38 cc 77 g	30 J	Monthly Quarterly Semiannual	3.7 5.0 5.5	4.3 6.0 6.7	4.7 7.0 8.0	4.9 7.5 8.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7289	InSync II Marquis	DR+LV true	38 cc 76 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.6 4.9 5.4	4.0 5.5 6.1	4.2 5.8 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7295	InSync II Protect	DR+LV true	38 cc 77 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.7 4.9 5.4	4.0 5.5 6.2	4.2 5.9 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7297	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7299	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7303	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7304	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI

		Estimated Lo	ngevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Time Indicators
InSync	8040	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	11.9 8.9 6.6	13.7 11.4 9.1	**
InSync III	8042	Low 2.5 V (A, RV, LV) Nominal 3.5 V (A, RV, LV) High 5.0 V (A, RV, LV)	8.3 5.9 4.1	9.9 7.8 6.0	**

						Estimate	d Longe	vity		Repla	nmended acement	
					,**					(RF	(T)***	_
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
C154DWK, C164AWK, C174AWK		DR+LV true	38 cm 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.3	4.3 6.8 8.0	4.8 8.0 9.8	5.0 8.8 11.0	≤ 2.62 V	-	3 month after RRT or > 16-second charge time

^{*} Volume and mass differ by connector style.

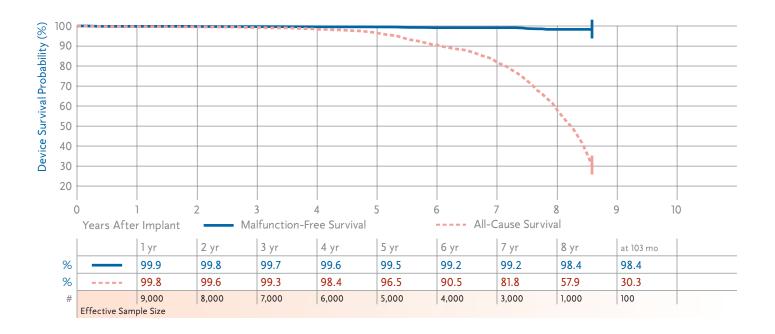
^{**} A full charge is a full energy therapeutic shock or capacitor reformation.

^{***} The minimum time between ERI and EOL (or RRT and EOS) is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is DDD for CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510 ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

7223 Micro Jewel II

US Market Release	Nov-96	NBD Code	VVEV
Registered US Implants	10,000	Serial Number Prefix/X-ray ID	PFR
Estimated Active US Implants	1,000	Max Delivered Energy	30 J
Normal Battery Depletions	781	Estimated Longevity	See page 33
Malfunctions	68		
Advisories	None		

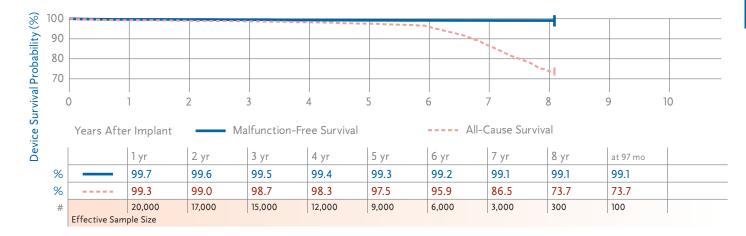




7227 GEM

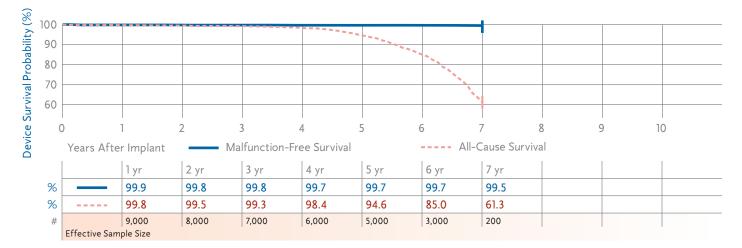
Product Characteristics

US Market Release	Oct-98	NBD Code	VVEV
Registered US Implants	22,000	Serial Number Prefix/X-ray ID	PIP, PLN, PLP, PLR
Estimated Active US Implants	8,000	Max Delivered Energy	35 J
Normal Battery Depletions	459	Estimated Longevity	See page 33
Malfunctions	135		
Advisories	1 see page 158	3 – 1999 Potential Circuit Overload	



7229 GEM II VR

US Market Release	Jul-99	NBD Code	VVEV
Registered US Implants	11,000	Serial Number Prefix/X-ray ID	PJJ
Estimated Active US Implants	3,000	Max Delivered Energy	30 J
Normal Battery Depletions	522	Estimated Longevity	See page 33
Malfunctions	26		
Advisories		<mark>8 – 1999 Potential Circuit Overload</mark> ge 167 <mark>– Performance note on ICD Battery Disc</mark>	charge Behavior





7230 Marquis VR

Product Characteristics

Market Release istered US Implants mated Active US Imp mal Battery Depletio functions		Dec-02 19,000 11,000			NBD Code Serial Numb	er Prefix/X-ray	ID PKD), PLW, PLY	
mated Active US Imp mal Battery Depletio		11,000							
	ns				Max Delivere	ed Energy	30 J		
C +:		6			Estimated Lo	ongevity	See	page 33	
runctions		19	(0 related to	advisory)					
Therapy Function Therapy Fund			(0 related to (0 related to						
risories		1	see page 156	_ 2005 Pot	<mark>ential Prematu</mark> r	e Battery Depl	etion Due to	Battery Sho	rt
1	2 3	4		5	6 7	7 8		9 .	10
rs After Implant	- Mal	function-Fre	e Survival		All-C	ause Survival		1	
1 yr	2 yr	3 yr	at 47 mo						
100.0	99.9	99.9	99.9						
99.9	99.7	99.6	99.6						
17,000	11,000	5,000	200						
ı	Therapy Fundisories 1 rs After Implant 1 yr 100.0 99.9	Therapy Function Compromisionies 1 2 3 rs After Implant	Therapy Function Compromised 6 isories 1 1 2 3 4 rs After Implant	Therapy Function Compromised 6 (0 related to isories 1 see page 156) 1 see page 156 1 see page 156 1 see page 156 2 at 47 mo 1 yr 2 yr 3 yr at 47 mo 1 100.0 99.9 99.9 99.9 1 17,000 11,000 5,000 200	Therapy Function Compromised 6 (0 related to advisory) isories 1 see page 156 - 2005 Pot 1 see page 156 - 2005 Pot 1 see page 156 - 2005 Pot 2 yr 3 yr 4 5 1 yr 2 yr 3 yr at 47 mo 100.0 99.9 99.9 99.9 100.0 11,000 11,000 5,000 200	Therapy Function Compromised 6 (0 related to advisory) isories 1 see page 156 - 2005 Potential Prematur 1 2 3 4 5 6 7 rs After Implant — Malfunction-Free Survival All-C 1 yr 2 yr 3 yr at 47 mo	Therapy Function Compromised 6 (0 related to advisory) isories 1 see page 156 – 2005 Potential Premature Battery Deple 1 2 3 4 5 6 7 8 rs After Implant — Malfunction-Free Survival 1 yr 2 yr 3 yr at 47 mo 100.0 99.9 99.9 99.9 17,000 11,000 5,000 200	Therapy Function Compromised 6 (0 related to advisory) 1 see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Premature Battery Depletion Due to see page 156 – 2005 Potential Prematur	Therapy Function Compromised 6 (0 related to advisory) 1 see page 156 – 2005 Potential Premature Battery Depletion Due to Battery Shore 1 2 3 4 5 6 7 8 9 1 1 2 yr Malfunction-Free Survival 1 yr 2 yr 3 yr at 47 mo 100.0 99.9 99.9 99.9 17,000 11,000 5,000 200

7231 GEM III VR

_	<u> </u>	•					Troduct C	nar acteristics		
	US Market R	elease		Dec-00)		NBD Code		VVEV	
	Registered U	JS Implants		17,000)		Serial Num	ber Prefix/X-ray ID	PJL	
	Estimated A	ctive US Impl	ants	10,000)		Max Delive	red Energy	30 J	
	Normal Batt	ery Depletior	ıs	97	7		Estimated I	ongevity	See page 33	
	Malfunction	s		24	1					
			Not Compron							
	Advisories			None	see page 1	67 – Perform	nance note on I	CD Battery Discharge	Behavior	
100 90 80										
(0 Years Afte	1 r Implant	2 Ma	3 alfunction-Fr	4 ee Survival	5	6 All-	7 8 Cause Survival	9	10
		1 yr	2 yr	3 yr	4 yr	5 yr	at 68 mo			
%		99.9	99.9	99.8	99.8	99.8	99.8			
%		99.8	99.5	99.1	98.7	97.6	91.4			
#		15,000	12,000	10,000	8,000	2,000	200			
	Effective Sam	ple Size								



7232 Maximo VR

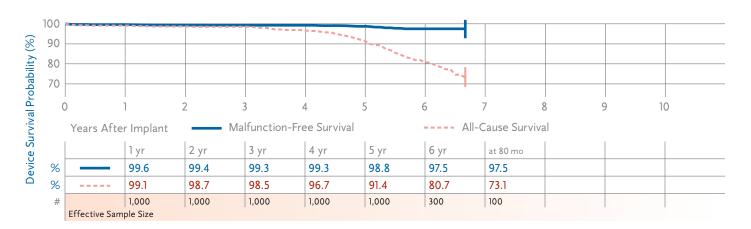
Product Characteristics

US Market	Release		Oct	t-03		NBD Code			VVED	
Registered	US Implants		37,0	000		Serial Num	ber Prefix/X-ra	ay ID	PRN	
Estimated i	Active US Impl	lants	32,0	000		Max Delive	red Energy		35 J	
Normal Bat	tery Depletion	ıs		4		Estimated I	ongevity		See page 3	33
Malfunction	ıs			11 (0 rela	ated to advisory)					
	rapy Function I Therapy Funct				ated to advisory) ated to advisory)					
Advisories				1 see pa	age 156 – 2005 Po	tential Prematu	re Battery De	pletion Di	ue to Batte	ry Short
90										
90		2	3	4	5	6	7	8	9	10
90	1 :	2	3 1alfunction	4 -Free Surv	5 vival	•	7 S		9	10
80	1 :	2	3 falfunction	4 -Free Surv	5 vival	•	•		9	10
80	1 :er Implant	2 M		4 -Free Surv	5 vival	•	•		9	10
90 80 0 Years Afte	1 :er Implant	2 N	3 yr	4 -Free Surv	5 vival	•	•		9	10

7250 Jewel AF

Effective Sample Size

US Market Release	Jun-00	NBD Code	VVED
Registered US Implants	1,000	Serial Number Prefix/X-ray ID	PID
Estimated Active US Implants	200	Max Delivered Energy	27 J
Normal Battery Depletions	67	Estimated Longevity	See page 33
Malfunctions	18		
Advisories	None		





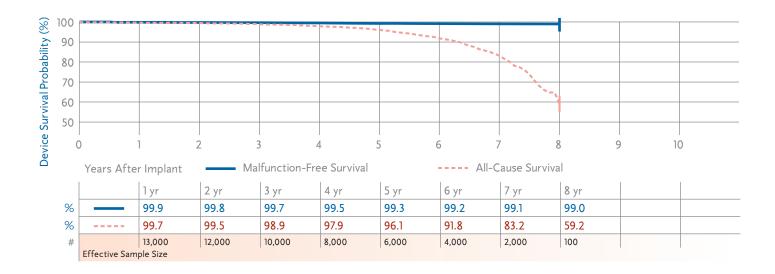
7271 GEM DR

Advisories

Product Characteristics

US Market Release	Oct-98	NBD Code	VVED
Registered US Implants	15,000	Serial Number Prefix/X-ray ID	PID
Estimated Active US Implants	5,000	Max Delivered Energy	27 J
Normal Battery Depletions	405	Estimated Longevity	See page 33
Malfunctions	78		

None



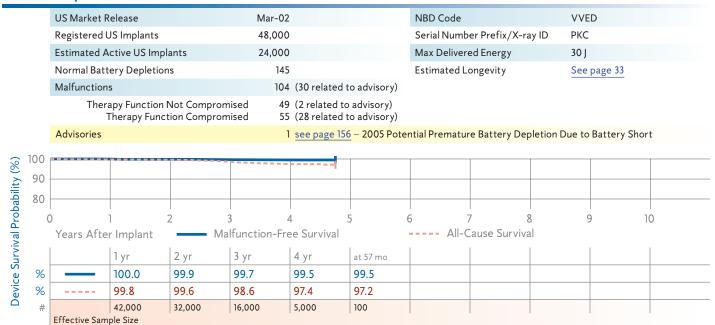
7273 GEM II DR

	US Market R	telease		Feb-99			NBD Code		VVED	
	Registered l	JS Implants		15,000			Serial Numbe	r Prefix/X-ray ID	PJK	
	Estimated A	ctive US Imp	lants	40			Max Delivered	d Energy	30 J	
	Normal Batt	ery Depletion	ıs	2,219			Estimated Lo	ngevity	See page 33	
	Malfunction	S		52						
	Advisories			None	see page 16	<u>7</u> – Performa	nce note on ICD	Battery Discharge	Behavior	
00				, L						
90										
80				**						
70										
60										
50										
					1					
40						1				
30						1				
20						1				
10										
(1	2	3	4	5	6 7	8	9	10
	Years Afte	r Implant	Ma	alfunction-Fre	ee Survival		All-Ca	ause Survival		
		1 yr	2 yr	3 yr	4 yr	5 yr	at 66 mo			
%		99.8	99.7	99.6	99.6	99.6	99.6			
%		99.5	98.7	95.6	82.3	45.6	13.0			
#		13,000	12,000	9,000	6,000	2,000	200			



7274 Marquis DR

Product Characteristics



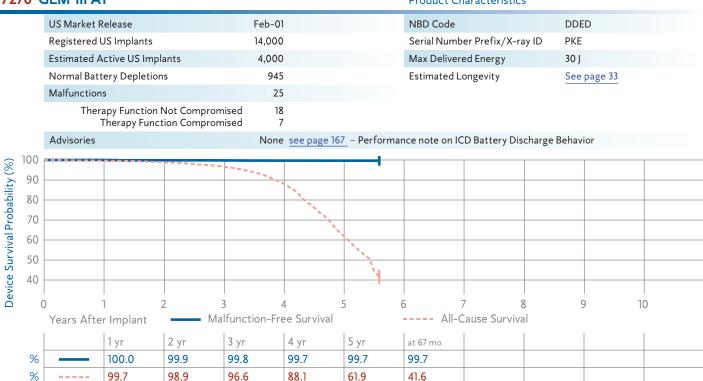
7275 GEM III DR

							T TOUGET CHA	racteristics		
	US Market R	Release		Nov-00)		NBD Code		VVED	
	Registered l	JS Implants		20,000)		Serial Number	Prefix/X-ray ID	PJM	
	Estimated A	ctive US Impl	ants	7,000)		Max Delivered	l Energy	30 J	
	Normal Batt	ery Depletion	ıs	1,256	5		Estimated Lon	ngevity	See page 33	
	Malfunction	S		35	5					
		apy Function Therapy Func								
	Advisories			None	e see page 16	7_ – Performa	nce note on ICD	Battery Discharge	Behavior	
00										
90						_				
30										
						,				
70										
50										
50										
40						1				
0)	1	2	3	4	5	6 7	8	9	10
	Years Afte		_	alfunction-Fr		3		use Survival		
		1 yr	2 yr	3 yr	4 yr	5 yr	at 69 mo			
%		99.9	99.9	99.8	99.8	99.7	99.7			
%		99.7	99.0	96.9	91.0	70.2	42.1			
#		17,000	14,000	11,000	8,000	3,000	200			
	Effective Sam	ple Size								



7276 GEM III AT

Product Characteristics



1,000

100

7278 Maximo DR

12,000

Effective Sample Size

10,000

8,000

5,000

	US Market R	Release		Oct-	03		NBD Code		VVED	
	Registered l	US Implants		33,00	00		Serial Numb	er Prefix/X-ray II) PRM	
	Estimated A	Active US Imp	lants	27,00	00		Max Delivere	ed Energy	35 J	
	Normal Batt	tery Depletio	ns		8		Estimated Lo	ongevity	See page	33
	Malfunction	ıs			8 (0 related t	o advisory)				
		apy Function Therapy Func			3 (0 related to 5 (0 related to 5)					
	Advisories				1 see page 15	66 – 2005 Pot	<mark>ential Premat</mark> ur	e Battery Depleti	ion Due to Batte	ery Short
00 90 80										
90	O Years Afte	1	1		4 Free Survival	5	6 7	7 8 Fause Survival	9	10
90 80 (O Years Afte	1 yr	2 yr	3 yr	at 37 mo	5		7 8 Tause Survival	9	10
90 80 (O Years Afte	1 yr	2 yr	3 yr 100.0	at 37 mo	5		7 8 Gause Survival	9	10
90 80 (O Years Afte	1 yr	2 yr	3 yr	at 37 mo	5		7 8 Tause Survival	9	10



7288 Intrinsic

Product Characteristics

00	ritrinsic						Product Cr	naracteristic	:S			
	US Market R	Release		Aug-04			NBD Code			VVEI	D	
	Registered l	JS Implants		29,000)		Serial Numb	er Prefix/X-r	ay ID	PUB		
	Estimated A	ctive US Impl	ants	26,000)		Max Deliver	ed Energy		35 J		
	Normal Batt	ery Depletion	s	5	j		Estimated L	ongevity		See	page 33	
	Malfunction	S		18	3							
		apy Function I Therapy Funct										
	Advisories			None								
100 90 80 %												
()	1 :	2	3	4	5	6	7	8	9		10
	Years Afte	r Implant	—— Ма	lfunction-Fre	ee Survival		All-(Cause Surviv	al			
		1 yr	2 yr	at 27 mo								
%		100.0	99.9	99.9								
%		99.9	99.7	99.7								
#		21,000	2,000	100								

7290 Onyx

Effective Sample Size

	US Market R	Release		Ma	r-04		NBD	Code		VVEV		
	Registered L	JS Implants		1,	000		Seria	l Number Pre	ix/X-ray ID	PRP		
	Estimated A	ctive US Imp	lants	1,	000		Max	Delivered Ene	rgy	30 J		
	Normal Batt	ery Depletion	1 s		0		Estin	nated Longevi	ty	See pag	e 33	
	Malfunction	S			1							
		apy Function Therapy Func			1 0							
	Advisories			N	lone							
100			 1									
90 80												
90		1 r Implant		3 Malfunction	4 -Free Surv	5 ival	6	7 - All-Cause	8 Survival	9	10	
90 80)	1 r Implant	2 yr	Malfunction	4 -Free Surv		6	7 - All-Cause		9	10	
90 80 0)	1 r Implant 1 yr 99.9	2 yr 99.9	lalfunction at 26 mo	4 -Free Surv		6	7 - All-Cause		9	10	
90 80)	1 r Implant	2 yr	Malfunction	4 -Free Surv		6	7 - All-Cause		9	10	



D153ATG, D153DRG EnTrust

Product Characteristics

	,											
	US Market R	elease		Jun-05			NBD Code			DDED, VV	'ED	
	Registered L	JS Implants		400			Serial Numb	er Prefix/X-ra	ay ID	PNR		
	Estimated A	ctive US Impl	ants	300			Max Deliver	ed Energy		30 J		
	Normal Batt	ery Depletion	s	0			Estimated L	ongevity		See page	34	
	Malfunction	s		1								
			Not Comprom									
	Advisories			None								
100 90 80												
()	1 2	2 3	3 4	1	5	6	7 8	3	9	10	
	Years Afte	r Implant	— Ма	lfunction-Fre	ee Survival		All-C	Cause Surviva	al			
		1 yr	2 yr	at 25 mo								
%		99.7	99.7	99.7								
%		99.4	99.4	99.4								
#		300	100	100								

D154ATG, D154DRG EnTrust

Effective Sample Size

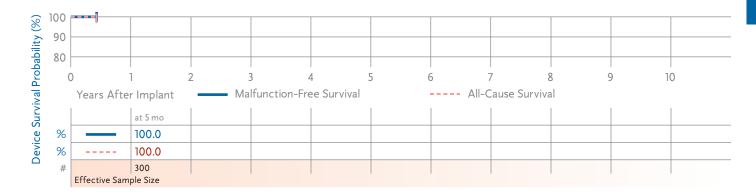
77	ו ס, טוס דר	OKO EIIII	ust				Product Ci	iaracteristics				
	US Market R	elease		Jun-05			NBD Code		DDI	ED, VVE	D	
	Registered l	JS Implants		23,000			Serial Numb	er Prefix/X-ray ID) PNF	₹		
	Estimated A	ctive US Impl	ants	21,000			Max Deliver	ed Energy	35 J			
	Normal Batt	ery Depletion	ıs	0			Estimated L	ongevity	See	page 34	4	
	Malfunction	S		2								
			Not Comprom tion Comprom									
	Advisories			None								
90 80												
(1	2 :	3	4 .	5	6	7 8		9	10)
	Years Afte	r Implant	Ma	lfunction-Fre	ee Survival		All-0	Cause Survival				
		1 yr	at 17 mo									
%		100.0	99.9									
%		100.0	99.8									
#	FCC 6	4,000	100									
	Effective Sam	ple Size										



D154AWG, D164AWG Virtuoso

Product Characteristics

US Market Release	May-06	NBD Code	VVED
Registered US Implants	5,000	Serial Number Prefix/X-ray ID	PVV, PUL
Estimated Active US Implants	5,000	Max Delivered Energy	35 J
Normal Battery Depletions	0	Estimated Longevity	See page 34
Malfunctions	0		
Advisories	None		



54V	RC Entru	st					Product Ch	naracteristic	cs			
	US Market R	elease		Jun-05			NBD Code			VVEV		
	Registered L	JS Implants		11,000)		Serial Numb	er Prefix/X-ı	ray ID	PNT		
	Estimated A	ctive US Imp	ants	11,000)		Max Deliver	ed Energy		35 J		
	Normal Batt	ery Depletion	ıs	0)		Estimated L	ongevity		See page	e 34	
	Malfunction	S		4								
			Not Compron tion Compron									
	Advisories			None								
100 90 80												
(0	1	_	3	4	5	6	7	8	9	,	10
	Years Afte	r Implant	Ma	lfunction-Fre	ee Survival		All-(Cause Surviv	/al			
		1 yr	at 15 mo									
%		99.9	99.9									
%		99.8	99.8									

99.8 300

1,000

Effective Sample Size



Device Survival Summary (95% Confidence Interval)

The following table shows ICD device survival estimates with 95% confidence intervals. Estimates are shown for both malfunction-free survival (which excludes normal battery depletion) and all-cause survival (which includes both malfunctions and normal battery depletion).

		8 yr 10 yr	98.4 98.4 +0.4/-0.5 +0.4/-0.5 at 103 mo	2 +1.8/-1.9 a0.3 at 103 mo	99.1 99.1 +0.2/-0.2 +0.2/-0.2 at 97 mo	73.7 73.7 5.9 +2.0/-2.2 +2.0/-2.2 at 97 mo	9.4	2.							ð. or	
		7 yr	99.2	81.8 +1.1/-1.2	99.1	86.5	99.5	61.3 +3.1/-3.2			0	2 0			97.5 +1.0/-1.6 at 80 mo	73.1
		6 yr	99.2 +0.2/-0.3	90.5	99.2	95.9 +0.4/-0.4	99.7	85.0 +1.0/-1.0			99.8 +0.1/-0.1 at 68 mo	91.4 +2.1/-2.7 at 68 mo			97.5	80.7
		5 yr	99.5	96.5	99.3	97.5	99.7	94.6 +0.5/-0.6			99.8	97.6			98.8 +0.6/-1.0	91.4 +1.9/-2.4
(%)		4 yr	99.6	98.4 +0.3/-0.3	99.4 +0.1/-0.1	98.3 +0.2/-0.2	99.7	98.4 +0.3/-0.3	99.9 +0.1/-0.1 at 47 mo	99.6	99.8 +0.1/-0.1	98.7 +0.2/-0.2			99.3	96.7
robability	ant	3 yr	99.7 +0.1/-0.1	99.3	99.5 +0.1/-0.1	98.7	99.8 +0.1/-0.1	99.3	99.9	99.6 +0.1/-0.1	99.8 +0.1/-0.1	99.1 +0.1/-0.2	99.9	99.8	99.3	98.5
Device Survival Probability (%)	Years After Implant	2 yr	99.8 +0.1/-0.1	99.6 +0.1/-0.2	99.6 +0.1/-0.1	99.0	99.8	99.5	99.9	99.7 +0.1/-0.1	99.9 +0.0/-0.1	99.5 +0.1/-0.1	99.9	99.8	99.4	98.7
Device :	Years A	l yr	99.9 +0.0/-0.1	99.8	99.7	99.3 +0.1/-0.1	99.9 +0.0/-0.1	99.8 +0.1/-0.1	100.0	99.9 +0.0/-0.1	99.9 +0.0/-0.1	99.8 +0.1/-0.1	100.0+0.0/-0.0	100.0	99.6 +0.3/-0.6	99.1 +0.4/-0.7
			Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause
	18		~		135		26		Φ.	(0) set)	24					
		10T	89		<u> </u>	1	2	ı	= 19	esqns p	= 2		=	= (0)	18	
unctions	rapy ction Not npromised	The run ToD	99			ı		ı		(0) (osory-related subse				(0) = (0)	- 18	
Malfunctions	rrapy Function npromised rrapy ction Mot mpromised	The Cor The Fun Fun Cor				1		1	13 =	ted sub	= 81		rv II	(0) = r-related subs	81	
Malfunctions	npromised etion Not npromised	The Cor The The Fun	781 — 6		459 – – 13	Nerload — — — —		verload; — — — — tery	+	(0) (0) (advisory-related sub:	- 18	ry	+ 5	(0) + (0) = (advisory-related subs	67 — — 18	
Malfunctions	srapy Function mpromised srapy ction Not onpromised	Act Imp Nor The Cor The Fun Fun	1		1	ial Circuit Overload — — — — —	1	ial Circuit Overload; on ICD Battery	6 + 13	(0) (0) (advisory-related sub:	6 + 18 =	n ICD Battery	9 + 9	(0) + (0) = (advisory-related subs	1	
Malfunctions	ive US illants imal Battery sillations strapy Function myromised repy Not ction Not ction Not	Esti Act Imp Mor Dep Cor The Cor	781 – –		459 — —	1999 Potential Circuit Overload — — — — —	522 – –	1999 Potential Circuit Overload; mance note on ICD Battery	6 + 13 ==	(0) (0) (advisory-related sub:	97 6 + 18 =	nce note on ICD Battery	4 6 + 5 + 1 = 1	(0) + (0) = (advisory-related subs		
Malfunctions	imated ive US ive US lants inal Battery stonis stonis stonised stonised stonised stonised stonised	Relation Con The Fundament Con			8,000 459	- page 158 – 1999 Potential Circuit Overload	3,000 522	page 158 – 1999 Potential Circuit Overload; 67 – Performance note on ICD Battery	11,000 6 6 + 13 =	(0) (0) (advisory-related sub:	= 81 + 9 76 000,01	Performance note on ICD Battery	32,000 4 6 + 5 =	(0) + (0) = (advisory-related subs	200 67	
Malfunctions	ristered implants in the US in the U	Relation Con The Fundament Con	<u>182</u> 000,1 000,01		22,000 8,000 459	Advisories: see page 158 – 1999 Potential Circuit Overload — — — —	11,000 3,000 522	Advisories: see page 158 – 1999 Potential Circuit Overload; also see page 167 – Performance note on ICD Battery Discharge Behavior	19,000 11,000 6 6 + 13 =	Advisories: see page 156 – 2005 Potential Premature Battery Depletion Due to Battery Short (advisory-related subse	17,000 10,000 97 6 + 18 =	see page 167 – Performance note on ICD Battery Discharge Behavior	37,000 32,000 4 6 + 5 =	Advisories: see page 156 – 2005 Potential Premature Battery Depletion Due to Battery Short (advisory-related subset)	1,000 200 67 — —	

		8 yr	99.0 +0.2/-0.3	59.2 +3.9/-4.2														
		7 yr	99.1 +0.2/-0.2	83.2 +1.2/-1.3														
		6 yr	99.2 +0.2/-0.2	91.8 +0.7/-0.7	99.6 +0.1/-0.1 at 66 mo	13.0 +1.9/-1.8 at 66 mo			99.7 +0.1/-0.1 at 69 mo	42.1 +3.0/-3.1 at 69 mo	99.7 +0.1/-0.1 at 67 mo	41.6 +3.5/-3.6 at 67 mo						
		5 yr	99.3 +0.1/-0.2	96.1 +0.4/-0.4	99.6	45.6 +1.4/-1.4	99.5 +0.1/-0.1 at 57 mo	97.2 +0.4/-0.4 at 57 mo	99.7 +0.1/-0.1	70.2 +1.2/-1.2	99.7 +0.1/-0.1	61.9 +1.6/-1.7						
Device Survival Probability (%)		4 yr	99.5 +0.1/-0.2	97.9 +0.3/-0.3	99.6 +0.1/-0.1	82.3 +0.8/-0.8	99.5 +0.1/-0.1	97.4 +0.3/-0.3	99.8 +0.1/-0.1	91.0	99.7 +0.1/-0.1	88.1 +0.7/-0.8	100.0 +0.0/-0.0 at 37 mo	99.9 +0.0/-0.1 at 37 mo				
	nt	3 yr	99.7 +0.1/-0.1	98.9 +0.2/-0.2	99.6	95.6	99.7 +0.1/-0.1	98.6 +0.1/-0.2	99.8 +0.1/-0.1	96.9 +0.3/-0.3	99.8	96.6 +0.3/-0.4	100.0+0.0/-0.0	99.9 +0.0/-0.1	99.9 +0.1/-0.2 at 27 mo	99.7 +0.1/-0.2 at 27 mo	99.9 +0.1/-0.8 at 26 mo	99.7 +0.2/-0.8 at 26 mo
Survival P	Years After Implant	2 yr	99.8 +0.1/-0.1	99.5 +0.1/-0.1	99.7	98.7 +0.2/-0.2	99.9	99.6 +0.1/-0.1	99.9 +0.0/-0.1	99.0 +0.1/-0.2	99.9	98.9 +0.2/-0.2	100.0	99.9 +0.0/-0.1	99.9	99.7 +0.1/-0.2	99.9	99.7 +0.2/-0.8
Device 5	Years A	l yr	99.9 +0.0/-0.1	99.7 +0.1/-0.1	99.8 +0.1/-0.1	99.5 +0.1/-0.1	100.0+0.0/-0.0	99.8	99.9	99.7 +0.1/-0.1	100.0	99.7 +0.1/-0.1	100.0+0.0/-0.0	99.9	100.0+0.0/-0.0	99.9	99.9	99.7 +0.2/-0.8
			Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause
	al	тоТ	78		52	T	104	(30) bset)	35		25		∞	(0) bset)	18		-	
ıctions	erapy ction Not npromised al	Fun Cor	_ 78		_ 52	I	49 =	(2) = (30) y-related subset)	25 =		= 8			$(0) = (0)$ η -related subset)	13		"	
Malfunctions	ction Mot npromised	The Fun Cor	78		52	1	Ш	= ed subs	п		П		Ш	= ed subs	п		Ш	
Malfunctions	rapy rapy ction Not npromised	The Cor The The Fun Cor	405 - 78		I	1	+ 49 =	(28) + (2) = (advisory-related subs	+ 25 =		 80 +		+	(0) + (0) = (advisory-related subs	+		+	
Malfunctions	srapy Function promised promised srapy ction Not mpromised	Mor Dep The Cor The Fun Fun Cor	1		1	D Battery — — — — —	55 + 49 =	(28) + (2) = (advisory-related subs	10 + 25 =	D Battery	7 + 18 =	D Battery	2 + 3	(0) + (0) = (advisory-related subs	5 + 13 =		+ 0	
Malfunctions	mal Battery shetions shetions hapy Function mpromised ction Not ction Not mpromised	Esti Mori Mori Dep The Cor	405 — —		2,219 — —	e note on ICD Battery — — — — —	145 55 + 49 =	(28) + (2) = (advisory-related subs	1,256 10 + 25 =	e note on ICD Battery	945 7 + 18 =	e note on ICD Battery	8 + 2 3 + 3 3 + 3 4 + 3	(0) + (0) = (advisory-related subs	5 + 13 =		H 0 0	
Malfunctions	mated ive US ive US lants mal Battery strions ive DS mal Battery repy Function promised ction Not ction Not bestion Not the Mot strion Not the Mot strion Not strion Not the Mot strion Not strion Not strion Not strion Not	Relation Con The Fundament Con	5,000 405 — —		40 2,219	Performance note on ICD Battery — — — — — — — — — — — — — — — — — — —	24,000 145 55 + 49 =	(28) + (2) = (advisory-related subs	7,000 1,256 10 + 25 =	– Performance note on ICD Battery navior	4,000 945 7 + 18 =	– Performance note on ICD Battery navior	27,000 8 5 + 3 =	(0) + (0) = (advisory-related subs	26,000 5 5 + 13 =		1,000 0 + 1 =	
Malfunctions	istered mplants in edge of my land of my lan	Relation Con The Fundament Con	15,000 5,000 405 — —		15,000 40 2,219 — —	see page 167 – Performance note on ICD Battery Discharge Behavior	48,000 24,000 145 55 + 49 =	Advisories: see page 156 – 2005 Potential Premature Advisories: see page 156 – 2005 Potential Premature Battery Depletion Due to Battery Short (advisory-related subset)	20,000 7,000 1,256 10 + 25 =	see page 167 – Performance note on ICD Battery Discharge Behavior	14,000 4,000 945 7 + 18 =	see page 167 – Performance note on ICD Battery Discharge Behavior	33,000 27,000 8 5 + 3 =	Advisories: see page 156 $-$ 2005 Potential Premature (0) + (0) = (0) Battery Depletion Due to Battery Short (advisory-related subset)	29,000 26,000 5 5 + 13 =		1,000 1,000 0 + 1 =	

-	

		8 yr								
		7 yr 8								
		6 yr								
		5 yr								
(%)		4 yr								
robability	ant	3 yr	99.7 +0.3/-1.8 at 25 mo	99.4 +0.4/-1.7 at 25 mo						
Device Survival Probability (%)	Years After Implant	2 yr	99.7 +0.3/-1.8	99.4	99.9 +0.1/-0.6 at 17 mo	99.8 +0.2/-0.6 at 17 mo			99.9 +0.1/-0.3 at 15 mo	99.8 +0.1/-0.3 at 15 mo
Device	Years A	1 yr	99.7 +0.3/-1.8	99.4 +0.4/-1.7	100.0	100.0	100.0 +0.0/-0.0 at 5 mo	100.0 +0.0/-0.0 at 5 mo	99.9 +0.1/-0.3	99.8
			Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause
	al	Tot	-		2		0		4	
suc	npromised	no⊃	Ш		= 2		Ш		Ш	
lfunctions	rapy ction Not npromised	The Fun Con								
Malfunctions	rapy Function npromised rapy ction Not ction not	The Con The The nun Con	0		" -		0		2 =	
Malfunctions	rapy rapy otion Mot periomaged	The Too The The noo	0		" -		0 +		+ 2 =	
Malfunctions	repy Function promised repy repy ction Not mpromised	Act Imp Mon Mon Dep The Con Th	0 +		+		0 +		2 + 2 =	
Malfunctions	ive US lants mal Battery stepy Function promised mapy Mot mapy mapy mapy mapy mapy mapy mapy mapy	Esti Morn Morn Morn Morn Morn Morn Morn The Con	0 +		+ - 0		II 0 + 0 0		0 2 + 2 =	
Malfunctions	mated jve US ive US lants mal Battery sniftions rapy Function rapy Function rapy Function rapy Function rapy Function rapy rapy mateur rapy rapy	Rela Nor Imp Mor Imp The Con The Con	300 0 1 + 0 0		21,000 0 1 + 1 =		= 0 + 0 0 000'5		11,000 0 2 + 2 =	
Malfunctions	istered mplants mated love US love US lants mal Battery mal Battery shetions rapy Function many Function rapy Function repy Function repy Function repy Function manual Battery	Rela Nor Imp Mor Imp The Con The Con	400 300 0 1 + 0 =		23,000 21,000 0 1 + 1 =		= 0 + 0 0 000'5		11,000 11,000 0 2 + 2 =	



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

						Stimate	d Longe	vity	Flootivo	Replacement		
					^**						RI)***	= 1 C1:C
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Life (EOL) Battery Voltage
7223	Micro Jewel II	Сх	54 cc 97 g	30 J	Monthly Quarterly Semiannual	4.9 6.3 6.8	5.4 7.1 7.7	5.8 7.8 8.5	6.0 8.1 9.0	≤ 4.91 V	-	≤ 4.57 V ^{‡‡}
7227	GEM	B, Cx, D, E	49 cc* 90 g	35 J	Monthly Quarterly Semiannual	5.3 7.7 8.8	5.7 8.5 10.0	6.0 9.3 11.0	6.1 9.6 11.5	≤ 2.55 V	_	≤ 2.40 V [§]
7229	GEM II VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.6 5.0 5.6	3.9 5.5 6.3	4.1 6.0 6.9	4.2 6.2 7.1	≤ 2.55 V	-	≤ 2.40 V
7230	Marquis VR	B, Cx, E	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.9 7.3 8.5	5.2 8.0 9.3	5.4 8.5 10.0	5.5 8.7 10.4	≤ 2.62 V	> 16-second charge time	3 months after ERI
7231	GEM III VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	4.3 6.0 6.6	4.7 6.8 7.5	5.0 7.4 8.5	5.2 7.8 8.9	≤ 2.55 V	-	≤ 2.40 V
7232	Maximo VR	B, Cx, E	39 cc 76 g	35 J	Monthly Quarterly Semiannual	4.4 7.0 8.2	4.7 7.5 9.0	4.8 8.0 9.7	4.9 8.3 10.0	≤ 2.62 V	> 16-second charge time	3 months after ERI
7250	Jewel AF	G, H	56 cc* 96 g	27 J	Monthly Quarterly Semiannual	5.3 6.5 7.0	6.1 7.6 8.2	6.7 8.7 9.4	7.0 9.2 10.0	≤ 4.94 V	-	≤ 4.50 V
7271	GEM DR	DR	62 cc 115 g	35 J	Monthly Quarterly Semiannual	6.0 7.4 7.9	6.9 8.4 9.0	7.5 9.3 10.0	7.8 9.8 10.6	≤ 4.91 V	_	≤ 4.57 V [§]
7273	GEM II DR	DR	39.5 cc 77 g	30 J	Monthly Quarterly Semiannual	2.8 3.7 4.0	3.2 4.3 4.7	3.5 4.8 5.4	3.7 5.1 5.8	≤ 2.55 V	-	≤ 2.40 V
7274	Marquis DR	DR+LV	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.6 6.2	4.4 6.4 7.2	4.8 7.1 8.1	4.9 7.5 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7275	GEM III DR	DR	39.5 cc 78 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.8 5.0 5.5	4.3 5.8 6.5	4.4 6.3 7.0	≤ 2.55 V	-	≤ 2.40 V
7276	GEM III AT	DR	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.3 4.3 4.5	3.8 5.1 5.5	4.3 5.9 6.5	4.5 6.3 7.0	≤ 2.55 V	_	≤ 2.40 V
7278	Maximo DR	DR	39 cc 77 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7287	Intrinsic 30	DR	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.5 6.2	4.3 6.3 7.2	4.7 7.0 8.2	4.8 7.4 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7288	Intrinsic	DR	38 cc 76 g	35 J	Monthly Quarterly Semiannual	3.7 5.4 6.1	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7290	Onyx	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.8 5.0 5.4	4.1 5.6 6.1	4.3 6.2 6.7	4.5 6.4 7.0	≤ 2.55 V	> 16-second charge time	≤ 2.40 V

^{*} Volume and mass differ by connector style.

^{**} A full charge is a full energy therapeutic shock or capacitor reformation.

^{***} The minimum time between ERI and EOL is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber and CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510 ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

^{‡‡} For Model 7223 devices, if charge time exceeds 60 seconds, the devices are at EOL. If 2 consecutive charge cycles exceed 60 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency output VVI pacing are disabled.

[§] For Model 7271 and 7227 devices, if charge time exceeds 30 seconds, the device is at EOL. Immediate replacement is recommended. If 3 consecutive charge cycles exceed 30 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency VVI pacing are disabled.



Reference Chart continued

						stimate	d Longe	vity	Recommended Replacement			
					λ***						RT)***	_
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
D153ATG, D153DRG	EnTrust	DR	33 cc 63 g	30 J	Monthly Quarterly Semiannual	3.5 4.8 5.3	3.8 5.4 6.1	4.1 6.0 6.9	4.2 6.3 7.2	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D153VRC	EnTrust	Сх	32 cc 63 g	30 J	Monthly Quarterly Semiannual	4.4 6.8 7.9	4.7 7.4 8.7	4.9 7.9 9.5	5.0 8.1 9.8	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154ATG, D154DRG	EnTrust	DR	35 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.1	4.2 6.1 7.0	4.4 6.8 7.9	4.6 7.0 8.3	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154AWG, D164AWG	Virtuoso	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.1 6.3 7.3	4.5 7.3 8.7	4.8 8.3 10.1	5.0 8.8 11.0	≤ 2.62 V	_	3 months after RRT or > 19-second charge time
D154VRC	EnTrust	Сх	35 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 7.5 9.0	5.0 8.3 10.0	5.2 8.8 10.7	5.3 9.0 11.0	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154VWC, D164VWC	Virtuoso	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 8.1 10.0	5.1 9.0 11.2	5.3 9.6 12.3	5.4 10.0 12.9	≤ 2.62 V	_	3 months after RRT or > 19-second charge time

^{*} Volume and mass differ by connector style.

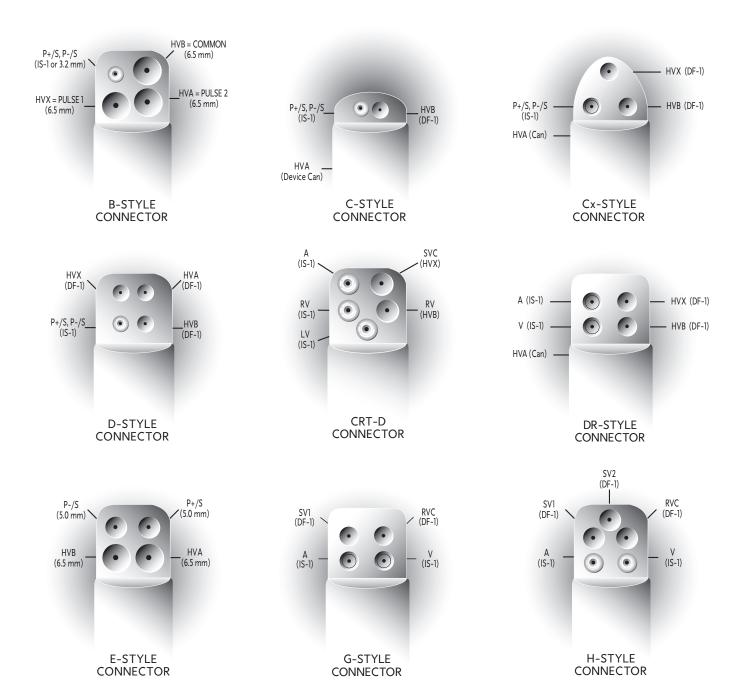
 $[\]ensuremath{^{**}}$ A full charge is a full energy the rapeutic shock or capacitor reformation.

^{***} The minimum time between RRT and EOS is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510 ohm pace load per applicable channel.



ICD Connector Styles



Adapta DR ADDR01, ADDR03, ADDR06, ADD01

Product Characteristics

pru Bit 715.	J. 101, 7155110	5,71BB1100,1	10001		T TO GUEL CIT	ar acteriotics			
US Market I	Release		Jul-06		NBG Code		DD	DR, DDD	
Registered	US Implants		6,000		Serial Number Prefix/X-ray ID			PWB, PWD, PWC	
Estimated A	Active US Impla	nts	6,000		Estimated Longevity			e page 75	
Normal Bat	tery Depletions	5	0						
Malfunction	ıs		0						
	py Function No herapy Functio								
Advisories			None						
90 80	1	2 3	3 2	. 5	6	7	8	9	10
Years Aft	er Implant	Mal	function-Fre			Cause Surviv			
%	100.0								
%	100.0								
#	500								
Effective Sa			1			1		1	'

Adapta SR ADSR01, ADSR03, ADSR06

•												
U	JS Market R	elease			Jul-06			NBG Code			SSIR	
R	Registered U	S Implants			1,000			Serial Numb	er Prefix/X-r	ay ID	PWM, P	WP, PWN
Е	stimated A	ctive US Impl	ants		1,000			Estimated L	ongevity		See page	e 75
Ν	Normal Batte	ery Depletion	ıs		0							
N	Malfunctions	3			0							
		y Function N erapy Function			0							
Δ	Advisories				None							
90									7			
0 Y	ا ears After)	Implant	_	3 //alfunctio	4 on-Free Su	5 urvival	6		/ Cause Surviv	8 ral	9	10
		at 2 mo										
%		100.0										
%		100.0										
#		300										
E	ffective Sam	ple Size										



AT500 AT501, 7253

Product Characteristics

AI.	300	A1501, 725	53					Product Characteristics	
		US Market R	elease		Mar-03			NBG Code	DDDRP
		Registered L	JS Implants		11,000			Serial Number Prefix/X-ray ID	IJF
		Estimated A	ctive US Impl	ants	8,000			Estimated Longevity	See page 75
		Normal Batt	ery Depletion	ıs	127				
		Malfunctions	S		7				
				Not Compromis					
		Advisories			None	see page 165	– Performa	nce note on AT500 Pacing System	n Follow-Up Protocol
<u></u>	100						1		
%									
<u>=</u>	90								
Survival Probability	80								
7	70								
٧I٧a	60								
Sur	50								
9	40						•		
Device		0	1	1 1			 -	6 7 8	9 10
	,	Years Afte	r Implant	- Malf	unction-Fre	ee Survival)	All-Cause Survival	9 10
			1 yr	2 yr	3 yr	4 yr	5 yr	at 61 mo	
	%		100.0	100.0	100.0	99.3	99.3	99.3	
	%		100.0	99.9	99.7	91.7	56.3	50.6	

200

100

Elite 7074, 7075, 7076, 7077

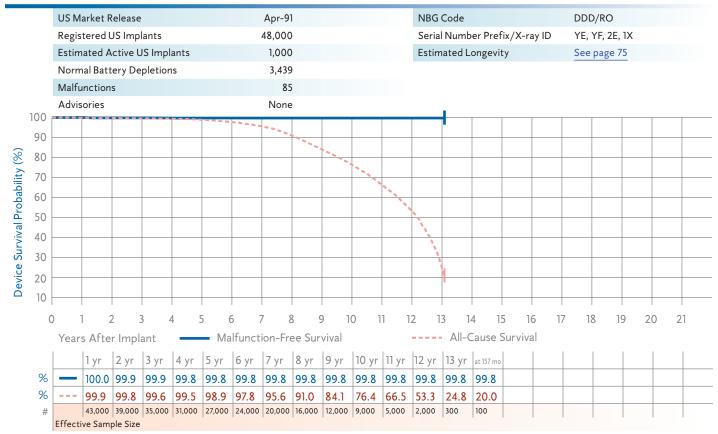
Effective Sample Size

10,000

8,000

3,000

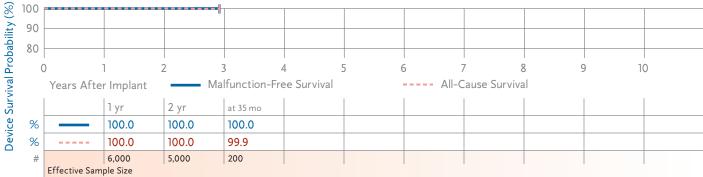
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EnPulse DR EIDRO1, EIDRO3, EIDRO6

Product Characteristics

US Market Release	Dec-03	NBG Code	DD	DR	
Registered US Implants	7,000	Serial Number Prefix/X-	ay ID PR	A	
Estimated Active US Implants	5,000	Estimated Longevity	See	e page 75	
Normal Battery Depletions	1				
Malfunctions	1				
Therapy Function Not Compromised Therapy Function Compromised	1 0				
Advisories	None				
)					
,					



EnPulse DR EIDR21

iruis	SE DK EID	RZI					Prodi	uct Characte	eristics		
	US Market F	Release		Dec-03	3		NBG	Code		DDDR	
	Registered	US Implants		2,000)		Serial	Number Pref	ix/X-ray ID	PPT	
	Estimated A	Active US Imp	lants	1,000)		Estim	ated Longevi	ty	See page	75
	Normal Bat	tery Depletion	ns	()						
	Malfunction	ıs		()						
		apy Function Therapy Func									
	Advisories			None	9						
90 80 %											
	0	1	2	3	4	5	6	7	8	9	10
	Years Afte	er Implant	M	alfunction-Fr	ee Survival			All-Cause S	Survival		
2		1 yr	2 yr	at 34 mo							
%		100.0	100.0	100.0							
<u>%</u>		100.0	100.0	100.0							
#		2,000	1,000	100							
	Effective Sam	iple Size									



EnPulse 2 DR E2DR01, E2DR03, E2DR06

Product Characteristics

US Market Release	Feb-04	NBG Code	DDDR
Registered US Implants	98,000	Serial Number Prefix/X-ray ID	PNB, PNC, PNH
Estimated Active US Implants	85,000	Estimated Longevity	See page 75
Normal Battery Depletions	0		
Malfunctions	4		
Therapy Function Not Compromised Therapy Function Compromised	2 2		
Advisories	None		



EnPulse 2 DR E2DR21

Product Characteristics

	uis	C Z DIC LA	DRZI					rioduct Ci	iai acteristic	3		
		US Market R	elease		Feb-04			NBG Code			DDDR	
		Registered L	JS Implants		12,000			Serial Numb	er Prefix/X-r	ay ID	PMU	
		Estimated A	ctive US Impl	ants	10,000			Estimated L	ongevity.		See page 75	
		Normal Batt	ery Depletion	S	3							
		Malfunction	S		0							
				Not Compromion Comprom								
		Advisories			None							
(%)	100											
oilit	90											
obał	80											
al Pr	()	i 1 :	2 3	3 4	4	5	6	7	8	9	10
Survival Probability		Years Afte	r Implant	Ма	function-Fre	ee Survival		All-(Cause Surviv	al		
e S			1 yr	2 yr	at 30 mo							
evice	%		100.0	100.0	100.0							
_												

100.0

6,000

Effective Sample Size

99.9

2,000

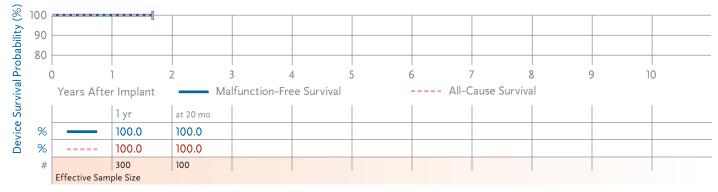
99.9

200

EnPulse 2 DR E2DR31, E2DR33

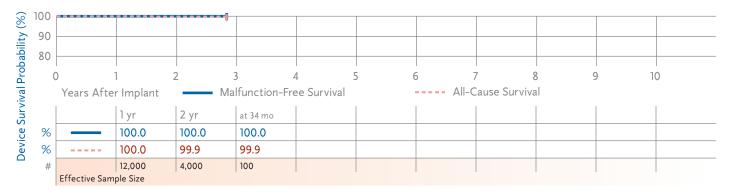
Product Characteristics

US Market Release	Feb-04	NBG Code	DDDR
Registered US Implants	1,000	Serial Number Prefix/X-ray ID	PNL
Estimated Active US Implants	1,000	Estimated Longevity	See page 75
Normal Battery Depletions	0		
Malfunctions	0		
Therapy Function Not Compromised Therapy Function Compromised	0 0		
Advisories	None		



EnPulse 2 SR E2SR01, E2SR03, E2SR06

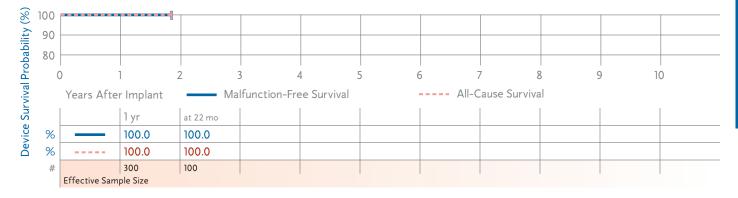
US Market Release	Dec-03	NBG Code	SSIR
Registered US Implants	24,000	Serial Number Prefix/X-ray ID	PMW, PMY, PNA
Estimated Active US Implants	20,000	Estimated Longevity	See page 75
Normal Battery Depletions	2		
Malfunctions	3		
Therapy Function Not Compromised Therapy Function Compromised	2 1		
Advisories	None		





EnPulse 2 VDD E2VDD01

US Market Release	Dec-03	NBG Code	VDD
Registered US Implants	1,000	Serial Number Prefix/X-ray ID	PMV
Estimated Active US Implants	500	Estimated Longevity	See page 75
Normal Battery Depletions	0		
Malfunctions	0		
Therapy Function Not Compromised Therapy Function Compromised	0		
Advisories	None		



EnRhy	thm DR P	1501DR						Product C	haracteristic	S			
	US Market R	elease		May	-05			NBG Code			DDDRP		
	Registered U	IS Implants		48,0	000			Serial Numl	oer Prefix/X-r	ay ID	PNP		
	Estimated A	ctive US Imp	lants	44,0	000			Estimated L	ongevity		See page 75		
	Normal Batte	ery Depletio	ns		0								
	Malfunctions	5			9								
			Not Compror		2 7								
	Advisories			N	one								
<u> </u>													
Probability 08 06													
obal 08													
۲	0 1		2	3	4	5)	6	7	8	9	10	



Kappa 400 DR KDR401, KDR403

Product Characteristics

۳-	100 511	REICTON, RE	14105				TTOGGC	Characteris	1100		
	US Market I	Release		Jan-98	3		NBG Cod	e		DDD/RO	
	Registered	US Implants		46,000)		Serial Nu	Serial Number Prefix/X-ray ID		PER, PET	
	Estimated A	Active US Imp	lants	13,000)		Estimated	d Longevity		See page 75	
	Normal Bat	tery Depletio	ns	2,009)						
	Malfunction	ıs		2	1						
	Ther	apy Function Therapy Fund	Not Compro tion Compro	mised 12 mised 9							
	Advisories			None	•						
100											
										•	
90								****			
80											
70											
60											
50									1		
40									1		
30									1		
20											
10		1		1	1	-					10
()	I	2	3	4	5	6	7	8	9	10
	Years Afte	er Implant	M	alfunction-Fr	ee Survival		Al	ll-Cause Surv	vival		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 103 mo	
%		100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	
%		99.9	99.9	99.8	99.6	99.2	97.8	91.0	64.9	16.0	
#		41,000	37,000	32,000	28,000	23,000	17,000	11,000	3,000	100	

Kappa 400 SR KSR401, KSR403

Effective Sample Size

	US Market F	Release		Feb-98			NBG Cod	e		SSI/R	
	Registered	JS Implants		15,000			Serial Nur	mber Prefix/X	(-ray ID	PEU, PGD	
	Estimated A	active US Imp	lants	5,000			Estimated	d Longevity		See page 75	
	Normal Bat	tery Depletio	ns	256							
	Malfunction	s		4							
			Not Comprom								
	Advisories			None							
100											
90										•	
80											
70									111		
60										1	
		_						_			
	O Years Afte	! r Implant	Ma	Ifunction-Fre	ee Survival	5	6 Al	l-Cause Surv	vival	9	10
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 103 mo	
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	
		99.9	99.9	99.8	99.6	99.5	98.8	96.0	79.6	68.0	
%					7,000	6,000	4,000	3,000	1,000	100	



Kappa 600 DR KDR601, KDR603, KDR606

Product Characteristics

	US Market R	elease		Jan-99)		NBG Code			DDD/RO		
	Registered U	JS Implants		24,000)		Serial Num	ber Prefix/X-	ray ID	PHF, PHH, I	PHG	
	Estimated A	ctive US Impl	ants	10,000)		Estimated	Longevity		See page 7	6	
	Normal Batt	ery Depletion	ıs	333	}							
	Malfunctions	S		16	(11 related t	o advisory)						
			Not Comprom tion Comprom		(0 related to (11 related to							
	Advisories			1	see page 15	7 – 2002 Pot	ential Fracture	ed Power Sup	ply Wires			
00												
30			2	2	4	5		7	9	9	10	
30	0 Years After	I Z		3 Ifunction-Fre	4 ee Survival	5	6	7 Cause Survi	8 val	9	10	
30		1 2 r Implant			4 ee Survival	5 5 yr	6	7		1	10	
30			Ma	 function-Fre	I		6 All-	7 Cause Survi	val	1	10	
90 30 (1 yr	Ma	function-Fre	4 yr	5 yr	6 All-	7 Cause Survi	val at 91 mo	1	10	

Kappa 600 DR KDR651, KDR653

Effective Sample Size

арра	OUU DK	KDR651, KDI	R653				Product C	naracteristics				
	US Market R	Release		Mar-0	1		NBG Code		DD	D/RO		
	Registered l	JS Implants		14,000		Serial Number Prefix/X-ray ID		ID PL	PLJ, PLK			
	Estimated A	ctive US Imp	lants	8,000)		Estimated L	ongevity	Se	e page 76	5	
	Normal Batt	ery Depletion	ns	47	7							
	Malfunction	S		3	3 (0 related t	o advisory)						
			Not Comprontion Compron		2 (0 related t 1 (0 related t	, ,						
	Advisories				1 see page 1!	57 – 2002 Pot	ential Fracture	d Power Supply	Wires			
90 80												
0)	1	2	3	4	5	6	7 8		9	10	
	Years Afte	r Implant	Ma	lfunction-Fr	ee Survival		All-	Cause Survival				
5		1 yr	2 yr	3 yr	4 yr	5 yr	at 67 mo					
%		100.0	100.0	100.0	100.0	100.0	100.0					
% %		100.0	99.9	99.8	99.5	98.9	98.4					
#	Effective Sam	13,000 ple Size	11,000	10,000	9,000	4,000	200					

Kappa 700 D KD701, KD703, KD706

Product Characteristics

		, ,									
	US Market R	elease		Jan-9	9		NBG Code			DDD	
	Registered l	JS Implants		30	0		Serial Num	ber Prefix/X-ı	ay ID	PHK	
	Estimated A	ctive US Imp	ants	100	0		Estimated I	Longevity		See page 76	
	Normal Batt	ery Depletion	ıs		4						
	Malfunction	S		(0 (0 related t	o advisory)					
			Not Compron tion Compron		0 (0 related t 0 (0 related t						
	Advisories			Non	e see page 15	7 – 2002 Pot	ential Fracture	ed Power Supp	ly Wires		
100 90 80											
	0	1	2	3	4	5	6	7	8	9	10
	Years Afte	r Implant	Ma	alfunction-Fr	ee Survival		All-	Cause Surviv	al		
	1	1	1	1	L	1	1	1	1	1	1
		1 yr	2 yr	3 yr	4 yr	5 yr	at 69 mo				
%		1 yr 100.0	2 yr	3 yr	100.0	5 yr	100.0				
% %		,	-	· ·		<u> </u>					

100

100

Kappa 700 DR KDR701, KDR703, KDR706

300

Effective Sample Size

200

200

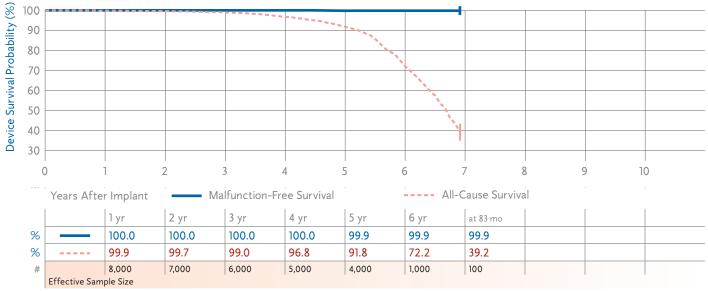
200

Pu	700 DK 1	CDIC/OI, KDI	K703, KDK70	•			T TOUGET C	nai acteristic	.3	
	US Market R	elease		Feb-99			NBG Code			DDD/RO
	Registered L	JS Implants		192,000			Serial Numb	per Prefix/X-r	ay ID	PGU, PGY, PGW
	Estimated A	ctive US Imp	lants	104,000			Estimated L	ongevity		See page 76
	Normal Batt	ery Depletio	ns	1,799						
	Malfunction	S		169	(117 related	to advisory)				
			Not Comprontion Compron		(0 related to (117 related	,				
	Advisories			None	see page 15	7 – 2002 Pote	ential Fracture	d Power Supp	ly Wires	
90 80 70								21		
(Years Afte	,	Ma	3 Alfunction-Fre	ee Survival	5	1	7 Cause Surviv	ı	9
			2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 94 mo	
0/		1 yr	1	00.0	00.0	000	00.0	00.0	00.0	
%		100.0	100.0	99.9	99.9	99.9	99.8	99.8	99.8	
% % #			1	99.9 99.7 116,000	99.9 99.3 90,000	99.9 98.5 65,000	99.8 96.6 33,000	99.8 90.9 10,000	99.8 75.8	

Kappa 700 DR KDR721

Product Characteristics

US Market Release	Feb-99	NBG Code	DDD/RO
Registered US Implants	10,000	Serial Number Prefix/X-ray ID	PGR
Estimated Active US Implants	2,000	Estimated Longevity	See page 76
Normal Battery Depletions	548		
Malfunctions	5 (4 related to advisory)		
Therapy Function Not Compromised Therapy Function Compromised	1 (0 related to advisory) 4 (4 related to advisory)		
Advisories	None see page 157 – 2002 Pote	ential Fractured Power Supply Wires	5



Kanna 700 SR KSR701 KSR703 KSR706

Product Characteristics

	700 SIC I	CORTON, ROICE	/03, KSR/06				Product Cr	iai acteristic	-3		
	US Market R	Release		Feb-99)		NBG Code			SSI/R	
	Registered l	JS Implants		55,000)		Serial Numb	er Prefix/X-r	ray ID	PHT, PHW, I	PHU
	Estimated A	ctive US Impl	lants	24,000)		Estimated L	ongevity		See page 76	5
	Normal Batt	ery Depletion	ıs	513	3						
	Malfunction	S		9)						
			Not Comprom tion Comprom								
	Advisories			None	2						
100 90								•			
80 70								11			
70	0	1	2	3	4	5	6	7	8	9	10
70) Years Afte			3 Ifunction-Fre		5	_	7 Cause Surviv		9	10
70						5 5 yr	_	7 Cause Surviv		1	10
70		r Implant	Ma	 function-Fre	ee Survival	_	All-0	1	/al	1	10

14,000

7,000

2,000

34,000

27,000

20,000

43,000

Effective Sample Size

100

3

2 yr

99.9

99.9

1,000

3 yr

99.9

99.6

1,000

Malfunction-Free Survival

4 yr

99.8

99.0

1,000

Kappa 700 VDD KVDD701

Device Survival Probability (%)

%

Product Characteristics

1	US Market Release	Jan-99	NBG Code		VDD/RO	
		•			,	
F	Registered US Implants	2,000	Serial Numbe	r Prefix/X-ray ID	PHP	
E	Estimated Active US Implants	1,000	Estimated Lo	ngevity	See page 76	
1	Normal Battery Depletions	42				
1	Malfunctions	3 (3 related to a	dvisory)			
	Therapy Function Not Compromised Therapy Function Compromised	0 (0 related to a 3 (3 related to a				
1	Advisories	None see page 157 –	2002 Potential Fractured	Power Supply Wires		
100 =						
90						
80			\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \			
70			1			
, ,						

5 yr

99.8

98.8

1,000

Kappa 800 DR KDR801, KDR803

Effective Sample Size

Years After Implant

1 yr

99.9

99.9

1,000

Product Characteristics

---- All-Cause Survival

at 82 mo

99.7

75.6

100

6 yr

99.7

95.5

500

10

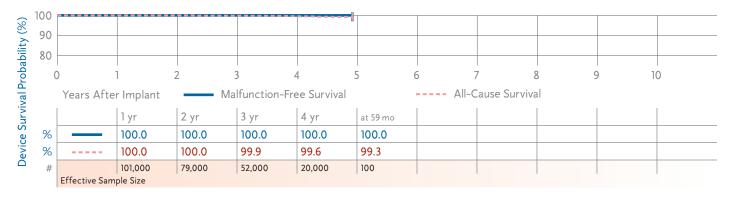
	US Market R	Release		Jan-02	2		NBG Code			DDD/RO		
	Registered l	JS Implants		4,000)		Serial Numb	er Prefix/X-ra	ay ID	PKW, PKY		
	Estimated A	ctive US Impl	ants	3,000)		Estimated L	ongevity		See page 76	5	
	Normal Batt	ery Depletion	ıs	3	3							
	Malfunction	S		C)							
			Not Comprom tion Comprom									
	Advisories			None								
90	0		2	3	4	-	6	7	8	9	10	
,	Years Afte			olfunction-Fr	ee Survival			Zause Surviva			10	
		1 yr	2 yr	3 yr	4 yr	at 51 mo						
%		100.0	100.0	100.0	100.0	100.0						
70		1	1	1	00.0	99.8						
%		100.0	99.9	99.8	99.8	99.0						



Kappa 900 DR KDR901, KDR903, KDR906

Product Characteristics

US Market Release	Jan-02	NBG Code	DDD/RO
Registered US Implants	124,000	Serial Number Prefix/X-ray ID	PKM, PKN, PKP
Estimated Active US Implants	90,000	Estimated Longevity	See page 76
Normal Battery Depletions	87		
Malfunctions	16		
Therapy Function Not Compromised Therapy Function Compromised	9 7		
Advisories	None		



Kappa 920 DR KDR921

Product Characteristics

	US Market R	Release		Jan-02	2		NBG Code		DDD/RO	
	Registered l	JS Implants		16,000)		Serial Numb	er Prefix/X-ray ID	PKR	
	Estimated A	ctive US Imp	lants	11,000)		Estimated Lo	ongevity	See page 76	
	Normal Batt	ery Depletion	ıs	60)					
	Malfunction	s			l					
			Not Compron tion Compron) I					
	Advisories	тпегару гипс	tion compron	None	1					
00		T								
90										
80										
()	1	2	3	4	5	6 7	7 8	9	10
	Years Afte	r Implant	Ма	alfunction-Fro	ee Survival		All-C	ause Survival		
		1 yr	2 yr	3 yr	4 yr	at 56 mo				
%		100.0	100.0	100.0	100.0	100.0				
% %		100.0	100.0 99.8	100.0 99.5	100.0 98.1	100.0 97.1				

200

11,000

8,000

3,000

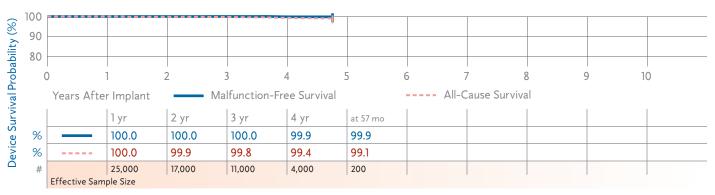
13,000

Effective Sample Size

Kappa 900 SR KSR901, KSR903, KSR906

Product Characteristics

US Market Release	Jan-02	NBG Code	SSI/R
Registered US Implants	36,000	Serial Number Prefix/X-ray ID	PLF, PLG, PLH
Estimated Active US Implants	24,000	Estimated Longevity	See page 76
Normal Battery Depletions	28		
Malfunctions	8		
Therapy Function Not Compromised Therapy Function Compromised	7 1		
Advisories	None		



Kappa 900 VDD KVDD901

ppa	900 VDL	KVDD901					Product C	naracteristics		
	US Market R	Release		Jan-02	2		NBG Code		VDD	
	Registered l	JS Implants		1,000)		Serial Numl	oer Prefix/X-ray ID	PLE	
	Estimated A	ctive US Impl	lants	400)		Estimated L	ongevity	See page 76	
	Normal Batt	ery Depletion	ıs	()					
	Malfunction	S		()					
			Not Comprom tion Comprom							
	Advisories			None	e					
90 80										
()	1	2 3	3	4	5	6	7 8	9	10
	Years Afte	r Implant	Ma	lfunction-Fr	ee Survival		All-	Cause Survival		
		1 yr	2 yr	3 yr	4 yr	at 50 mo				
%		100.0	100.0	100.0	100.0	100.0				
%		100.0	100.0	100.0	100.0	100.0				
#		1,000	500	300	100	100				
	Effective Sam	ple Size								



Legend 8416, 8417, 8417M, 8418, 8419

Product Characteristics

5011	0 11	0, 0417	, 04171	ivi, 0-11	0, 0 11.								1100	uct Ci	iaract	CHISTIC	3					
	US M	arket R	elease					Aug-89)				NBG	Code				SSIR	20			
	Regis	tered l	JS Impl	lants				57,000)				Seria	Numb	er Pref	ix/X-ra	ay ID	XT,	WJ, W	N, ZT		
	Estim	ated A	ctive U	JS Impl	ants			3,000)				Estim	ated L	ongevi	ty		See	page 7	76		
	Norm	nal Batt	ery De	pletion	ıs			2,603	3													
	Malfu	ınction	S					145	;													
	Advis	ories						None	·													
100																						
100																						
80																					1	
70																					_	+
60																				-	+	+
50																				-		
C)	1 :	2 3	3 4	4	5 (5 7	7	8	9 1	0	1 1	2 1	3 1	4 1	5 1	6 1	7 1	8 1	19	20	21
	Year	s Afte	r Impla	ant		Ma	lfunct	ion-Fr	ee Sur	vival				All-C	Cause S	Surviva	al					
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	at 200 mo				
%	_	99.9	99.9	99.8	99.8	99.7	99.7	99.6	99.6	99.6	99.6	99.6	99.6	99.6	99.6	99.6	99.6	99.6				
%		99.9	99.7	99.4	98.9	98.3	97.2	94.7	90.7	86.0	81.4	76.8	73.1	69.0	64.5	61.3	57.2	55.2				
#		51,000	46,000	41,000	36,000	31,000	26,000	21,000	17,000	14,000	11,000	8,000	6,000	4,000	3,000	2,000	1,000	100				

Legend II 8424 8426 8427

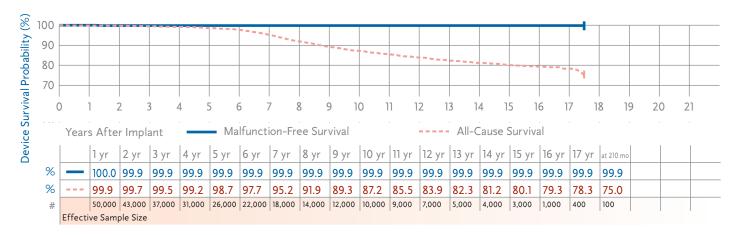
Effective Sample Size

egen	u II a	424, 8	420, 8	42/									Prod	uct Cr	iaracti	eristic	.5						
	US M	arket R	elease					Nov-91					NBG	Code					SSIRC)			
	Regis	tered (JS Impl	ants				59,000)				Seria	Numb	er Pref	fix/X-r	ay ID		2P, 2T	ī, 2U			
	Estim	ated A	ctive U	IS Impl	ants			6,000)				Estim	ated L	ongevi	ty			See p	age 76	5		
	Norm	al Batt	ery De	pletion	ıs			1,671															
	Malfu	nction	s					37	,														
	Advis	ories						None	•														
100																							
, , , ,																							
90																							
90 80 70																							
70																						1	
()	1 2	2 3	3 4	4 5	5 6	5 7	7 8	3 9) 1	0 1	1 1	2 1	3 1	4 1	5 1	16	17	18	19	2	20	21
5	V	A C1 .	. 1 1			Ma	I£	a.a. F		اميني				۸۱۱ ۵	ause :	Ci	اء						
	rear	s Arte	r Impla			- IVIA	lfuncti										1						
Š		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	at 177 m	0						
%	_	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9							
%		99.9	99.7	99.5	99.2	98.8	98.1	97.2	94.8	91.9	89.2	86.1	83.3	79.9	75.3	72.2							
#		l .	1	41,000	35,000	31,000	27,000	23,000	20,000	16,000	12,000	10,000	7,000	4,000	1,000	200							
	Effecti	Effective Sample Size																					

Minix/Minix ST 8330, 8331, 8331M, 8340, 8341, 8341M, 8342

Product Characteristics

US Market Release	Dec-89	NBG Code	SSIRO									
Registered US Implants	58,000	Serial Number Prefix/X-ray ID	2P, 2T, 2U									
Estimated Active US Implants	5,000	Estimated Longevity	See page 76									
Normal Battery Depletions	1,446											
Malfunctions	49											
Advisories	ries 1 see page 162 – 1991 Potential Delayed Restoration of Permanent Settings											



Minuet 7107, 7108

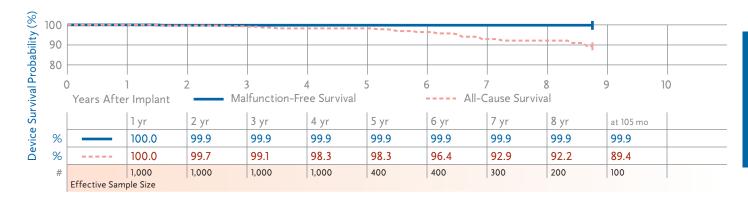
		US M	arket R	elease					Mar-92					NBG	Code					DDDC	0		
			tered l						17,000						l Numb	er Pre	fix/Xra	ay ID		IZ1, 20			
		Estim	nated A	ctive U	IS Impl	ants			2,000)				Estim	nated L	ongevi	ty			See pa	age 76		
		Normal Battery Depletions Malfunctions Advisories				s			552	!													
								4	ļ														
									None	:													
<u>%</u>	100															-							
Survival Probability (%)	90																						
abili	80														**.								
roba	70														**	**							
al P	() [1 2) 7	 }	1 5	5 6	 7	7 9	Ι }	l 9 1() 1	l 1 1:	l 2 1:	l 3 1,	l 4 1	l 5 1	1 16	17	18	19	20	1 21
ĬŽ				_															17	10		20	
e St		Year	s Afte	r Impla	ant	_	Ma	lfuncti	on-Fre	ee Sur	vival				All-C	Cause :	Surviv	al					
Device			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	at 173 m	0					
Ŏ	%	_	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0						
	%		100.0	100.0				98.2			92.1				78.8	73.8	72.4						
	#	Effecti	1	I	12,000	11,000	9,000	8,000	7,000	6,000	5,000	4,000	3,000	2,000	1,000	400	100						
		Effecti	ve Sam	ole Size																			



Preva D 7068

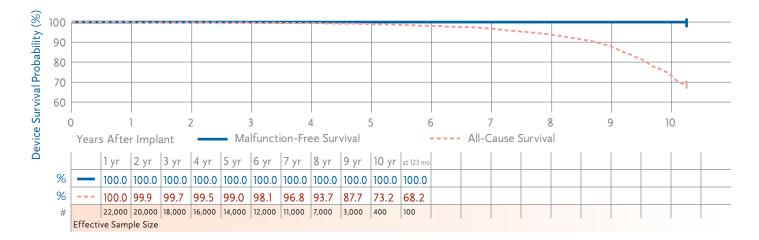
Product Characteristics

US Market Release	Nov-96	NBG Code	DDDCO
Registered US Implants	1,000	Serial Number Prefix/X-ray ID	PIE
Estimated Active US Implants	200	Estimated Longevity	See page 76
Normal Battery Depletions	19		
Malfunctions	1		
Advisories	None		



Preva DR 7088, 7089

US Market Release	Jul-96	NBG Code	DDD/RO
Registered US Implants	26,000	Serial Number Prefix/X-ray ID	PGJ, PGK
Estimated Active US Implants	7,000	Estimated Longevity	See page 77
Normal Battery Depletions	628		
Malfunctions	3		
Advisories	None		



15,000 12,000 11,000 9,000 8,000 6,000 5,000 3,000 1,000 200

Preva SR 8088, 8089

Device Survival Probability (%)

#

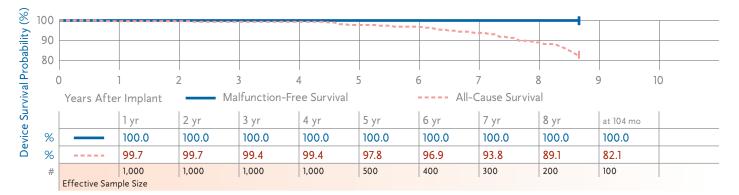
Effective Sample Size

Product Characteristics

-va	31\ o	000, 0	009								Prou	uct Cr	iaracti	eristic	.5							
	US M	arket R	elease					Jul-96					NBG	Code				S	SI/R			
	Regis	tered (JS Impl	ants				18,000					Seria	l Numb	er Pref	ix/X-r	ay ID	Р	GL, F	PGM		
	Estim	nated A	ctive U	IS Impl	ants			4,000					Estim	ated L	ongevi	ty		S	ee pa	age 77		
	Norm	nal Batt	ery De	pletion	S			288	,													
	Malfu	ınction	s					1														
	Advis	ories						None														
100																		T				
90																						
80										****												
()]	1 2) 2		l 1 5	i 6	 	ا 7 8	3 9	ا)[(D 1	 1 12	 (l 3 1₄	ا 4 1:	5 1	l 6	 17	18	19	20	21
																-			10		20	
	Year	s Afte	r Impl	ant		Ma	lfuncti	ion-Fre	ee Sur	vival				All-C	Cause S	Surviv	al					
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 121 mo										
%	_	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0										
%		99.9	99.9	99.6	99.3	98.6	97.6	95.3	93.2	89.5	82.2	81.0										

Preva ST DR 7078

US Market Release	Nov-96	NBG Code	DDD/RO
Registered US Implants	1,000	Serial Number Prefix/X-ray ID	PIF
Estimated Active US Implants	200	Estimated Longevity	See page 77
Normal Battery Depletions	32		
Malfunctions	0		
Advisories	None		

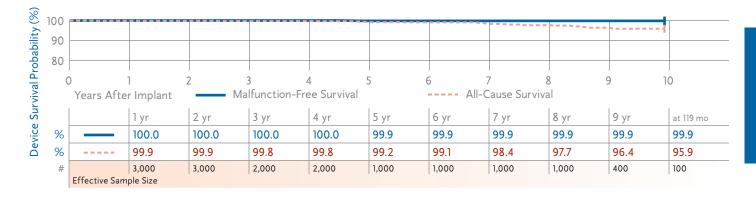




Prevail S 8085, 8086

Product Characteristics

US Market Release	Oct-95	NBG Code SSI
Registered US Implants	4,000	Serial Number Prefix/X-ray ID PGL, PGM
Estimated Active US Implants	1,000	Estimated Longevity See page 77
Normal Battery Depletions	19	
Malfunctions	1	
Advisories	None	



Prodigy D 7864, 7865, 7866

Product Characteristics

	IIS Ma	arkat R	elease					Oct-95					NBG	Code				D	DDCC)		
			JS Impl					3,000							er Prefi	w /V	ov ID) DM, PD	NI	
																	ay ID				IN	
				IS Impla				1,000					Estim	ated Lo	ongevit	у		Se	ee pag	ge 77		
	Norm	al Batt	ery De	pletion	S			64														
	Malfu	nction	S					0														
	Advis	ories						None														
											_											
00																						
90									****												_	_
80																						
											•											
70																			_	_	_	
O)]	2	. 3	3 4	. 5	5 6	5 7	7 8	3	9 1	0 1	1 1:	2 13	3 14	4 15	1	6	17	18	19	20	21
	Voors	\ Afta	r Impla	ant		_ Ma	lfunct	ion_Fr	a Sur	leviv				Δ11_C	ause S	rviv	اد					
	. I Cars	Alle	. IIIIpi	aiii		. IVIA			. Jui	vivai					. ausc s	JUI VIV						
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 121 mo										
%		1000	7000	1000	1000	1000	1000	1000	1000	1000	1000	1000								\neg	\neg	\neg

82.6 82.6

100

%

99.9

Effective Sample Size

99.7

2,000 2,000

100.0 | 100.0 | 100.0 | 100.0 | 100.0 | 100.0 | 100.0 | 100.0 | 100.0 | 100.0 | 100.0

2,000 2,000 2,000 1,000 1,000 1,000 1,000 100

97.1

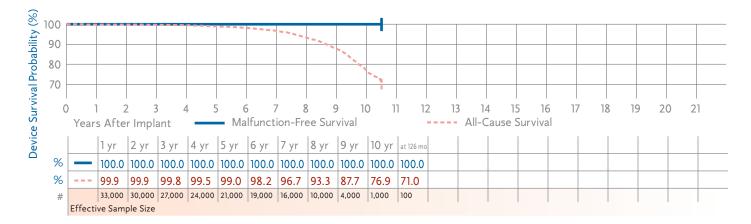
95.9 91.4

99.4 98.8 98.6 97.7

Prodigy DR 7860, 7861, 7862

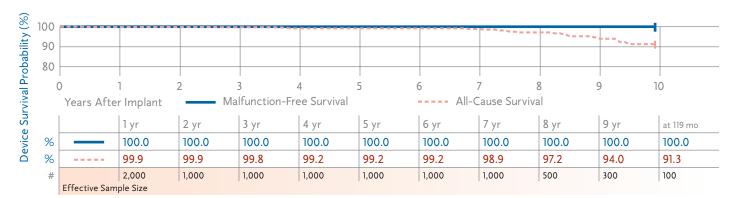
Product Characteristics

US Market Release	Oct-95	NBG Code DDD/RO
Registered US Implants	37,000	Serial Number Prefix/X-ray ID PDH, PDJ, PDK
Estimated Active US Implants	11,000	Estimated Longevity See page 77
Normal Battery Depletions	868	
Malfunctions	11	
Advisories	None	



Prodigy S 8164, 8165, 8166

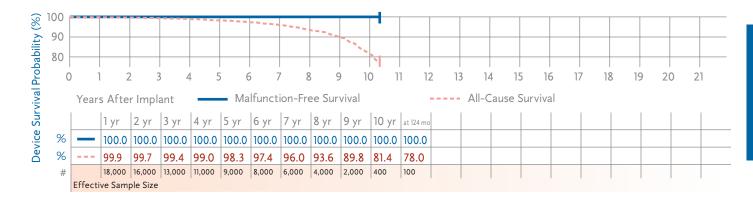
US Market Release	Oct-95	NBG Code SSIC
Registered US Implants	2,000	Serial Number Prefix/X-ray ID PEG, PEH, PEJ
Estimated Active US Implants	400	Estimated Longevity See page 77
Normal Battery Depletions	22	
Malfunctions	0	
Advisories	None	



Prodigy SR 8158, 8160, 8161, 8162

Product Characteristics

US Market Release	Oct-95	NBG Code SSI/R
Registered US Implants	22,000	Serial Number Prefix/X-ray ID PEM, PED, PEE, PEF
Estimated Active US Implants	5,000	Estimated Longevity See page 77
Normal Battery Depletions	354	
Malfunctions	5	
Advisories	None	



Sensia DR SEDRO1. SED01

Product Characteristics

Jei	ISIA	DK SEDRI	JI, SEDUI					Product Cr	iaracteristic	5			
		US Market R	elease		Jul-06			NBG Code			DDD, DDDR		
		Registered L	JS Implants		2,000			Serial Numb	er Prefix/X-ra	ay ID	PWL, PWK		
		Estimated A	ctive US Impl	ants	1,000			Estimated L	ongevity		See page 77	,	
		Normal Batt	ery Depletion	ıs	0							-	
		Malfunction	5		0								
		Thera	y Function N	ot Compromi	sed 0								
		Tł	nerapy Functi	on Compromi	sed 0								
		Advisories			None								
y (%)	100	-											
ij	90												
bal	80												
Pro	()	1 :	2 :	3 4	1 5	(5	7	8	9	10	
Device Survival Probability		Years Afte	r Implant	— Ма	lfunction-Fre	ee Survival		All-C	Cause Surviva	al			
Su			at 2 mo										
vice.	%		100.0										
De	%		100.0										<u> </u>

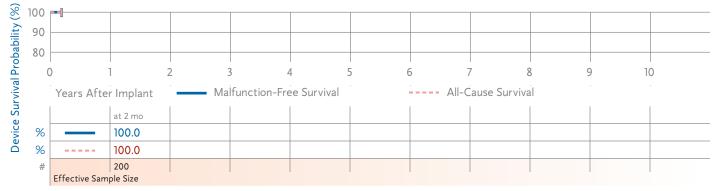
100.0 300

Effective Sample Size

Sensia SR SESRO1, SESO1

Product Characteristics

US Market Release Jul-06 NBG Code SSIR, SSI Registered US Implants 1,000 Serial Number Prefix/X-ray ID PWR, PWS Estimated Active US Implants 1,000 Estimated Longevity See page 77 Normal Battery Depletions 0 Malfunctions 0 Therapy Function Not Compromised 0 Therapy Function Compromised 0 Advisories None				
Estimated Active US Implants 1,000 Estimated Longevity See page 77 Normal Battery Depletions 0 Malfunctions 0 Therapy Function Not Compromised 0 Therapy Function Compromised 0	US Market Release	Jul-06	NBG Code	SSIR, SSI
Normal Battery Depletions 0 Malfunctions 0 Therapy Function Not Compromised 0 Therapy Function Compromised 0	Registered US Implants	1,000	Serial Number Prefix/X-ray ID	PWR, PWS
Malfunctions 0 Therapy Function Not Compromised 0 Therapy Function Compromised 0	Estimated Active US Implants	1,000	Estimated Longevity	See page 77
Therapy Function Not Compromised 0 Therapy Function Compromised 0	Normal Battery Depletions	0		
Therapy Function Compromised 0	Malfunctions	0		
Advisories				
	Advisories	None		



Sigma 100 S SS103, SS106

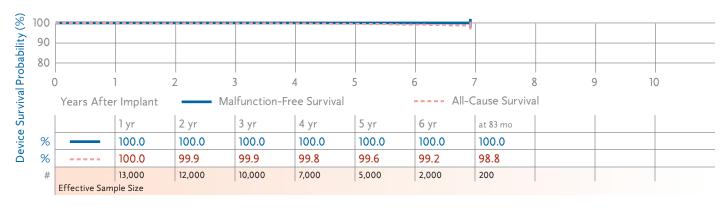
		. ,								
	US Market R	Release		Aug-99)		NBG Code		SSI	
	Registered l	JS Implants		1,000)		Serial Num	ber Prefix/X-ray II	O PJG, PJH	
	Estimated A	ctive US Impl	ants	200)		Estimated I	ongevity	See page 77	
	Normal Batt	ery Depletion	ıs	3	1					
	Malfunction	s		C	(0 related to	o advisory)				
			Not Comprontion Compron		(0 related to					
	Advisories			None	see page 15	<u>5</u> – 2005 Pote	ential Separati	on of Interconnec	t Wires	
90										
()	1	· · · · · · · · · · · · · · · · · · ·	3	4	5	6	7 8	9	10
	Years Afte	: r Implant	Ma	lfunction-Fr	ee Survival			Cause Survival		10
		1 yr	2 yr	3 yr	4 yr	5 yr	at 70 mo			
%		100.0	100.0	100.0	100.0	100.0	100.0			
%		100.0	100.0	99.5	99.5	98.4	98.4			
#		1,000	500	300	200	200	100			
	Effective Sam	ple Size								



Sigma 200 DR SDR203

Product Characteristics

US Market Release	Aug-99	NBG Code	DDD/RO
Registered US Implants	16,000	Serial Number Prefix/X-ray ID	PJD
Estimated Active US Implants	8,000	Estimated Longevity	See page 77
Normal Battery Depletions	23		
Malfunctions	3 (0 related to advisory)		
Therapy Function Not Compromised Therapy Function Compromised	1 (0 related to advisory)2 (0 related to advisory)		
Advisories	None see page 155 – 2005 Pote	ential Separation of Interconnect W	ires



Sigma 200 SR SSR203

Normal Batte Malfunctions Thera	US Implants ctive US Impl ery Depletion s apy Function I		nised 0 nised 2	(2 related to (0 related to (2 related to	advisory) advisory)	Estimated	nber Prefix/X-ray ID Longevity	SSI/R PJG See page 7	77
Estimated Ad Normal Batte Malfunctions Thera T	ctive US Implery Depletions apy Function I	ns Not Compror	5,000 11 2 nised 0 nised 2	(2 related to	advisory) advisory)	Estimated	Longevity	See page 7	<u>777</u>
Normal Batte Malfunctions Thera T	ery Depletior s apy Function I	ns Not Compror	11 2 nised 0 nised 2	(2 related to	advisory) advisory)				77
Malfunctions Thera T	s apy Function I	Not Compror	nised 0 nised 2	(2 related to (0 related to (2 related to	advisory) advisory)				
Thera T	apy Function I		nised 0 nised 2	(0 related to	advisory) advisory)				
Т	. /		nised 2	(2 related to	advisory)				
Advisories			None	see page 15	200E Dat				
				occ page is.	- 2003 Pot	ential Separat	ion of Interconnect \	Wires	
							1		
1 Years After	l Implant	2 —— Ma	3 alfunction-Fre	4 ee Survival	5	6 All-	7 8 -Cause Survival	9	10
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 83 mo		
	100.0	100.0	100.0	100.0	100.0	100.0	100.0		
	100.0	99.9	99.8	99.8	99.6	99.5	99.5		
	10,000	8,000	6,000	4,000	3,000	1,000	100		
		100.0	1 yr 2 yr 100.0 100.0 100.0 99.9 10,000 8,000	1 yr 2 yr 3 yr 100.0 100.0 100.0 100.0 99.9 99.8 10,000 8,000 6,000	1 yr 2 yr 3 yr 4 yr 100.0 100.0 100.0 100.0 100.0 99.9 99.8 99.8 10,000 8,000 6,000 4,000	1 yr 2 yr 3 yr 4 yr 5 yr 100.0 100.	Pears After Implant Malfunction-Free Survival All- 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 100.0 100.0 100.0 100.0 100.0 100.0 100.0 99.9 99.8 99.8 99.6 99.5 10,000 8,000 6,000 4,000 3,000 1,000	1 yr 2 yr 3 yr 4 yr 5 yr 6 yr at 83 mo	1 yr

Sigma 300 DR SDR303, SDR306

Product Characteristics

	US Market R	elease		Aug-99			NBG Code			DDD/RO	
	Registered l	JS Implants		102,000			Serial Num	ber Prefix/	K-ray ID	PJD, PJE	
	Estimated A	ctive US Impl	ants	64,000			Estimated	Longevity		See page	77
	Normal Batt	ery Depletion	ıs	81							
	Malfunction	S		47	(20 related	to advisory)					
			Not Compromition Compromi		(0 related to						
	Advisories			None	see page 15!	5 – 2005 Pote	ential Separat	ion of Interd	onnect Wir	res	
00											
			2 3			5	6	7	8	9	10
	Years Afte	r Implant		function-Fre	1	5 vr	1	7 -Cause Surv	1	9	10
80) Years Afte	r Implant	Mal	function-Fre	4 yr	5 yr	All-	7 yr	vival at 86 mo	1	10
90 80 %	Years Afte	r Implant	Mal	function-Fre	1	5 yr 99.9	All-	1	vival	1	10

Sigma 300 SR SSR303, SSR306

Effective Sample Size

114	300 SIC 3											
	US Market R	elease		Sep-9	9		NBG Code			SSI/R		
	Registered L	JS Implants		51,00	0		Serial Number Prefix/X-ray ID			PJG, PJH		
	Estimated A	ctive US Impla	ants	26,00	0		Estimated Longevity			See page 77		
	Normal Batt	ery Depletion	S	4	4							
	Malfunctions	5			8 (5 related t	o advisory)						
		apy Function N Therapy Funct			1 (0 related t 7 (5 related t							
	Advisories			Nor	e see page 15	55 – 2005 Pot	ential Separa	tion of Intercor	nect Wi	res		
90								-				
90) Years After	,			4 ree Survival	5	1	7 -Cause Surviv	8 ral	9	10)
90) Years After	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 al	9	10)
90 80 6		1 yr	2 yr	3 yr 100.0	4 yr	100.0	6 yr	7 yr	8 al	9	10)
000 900 880 000 %	Years After	1 yr	2 yr	3 yr	4 yr	· ·	6 yr	7 yr	8 8 al	9	10)



Sigma 300 VDD SVDD303

Product Characteristics

gilla	300 VDD	3400303					Product C	naracteristics				
	US Market R	Release		Sep-99			NBG Code			VDDD		
	Registered l	JS Implants		1,000			Serial Numb	oer Prefix/X-ra	y ID	PJD		
	Estimated A	ctive US Impl	ants	300			Estimated L	ongevity		See page 7	7	
	Normal Batt	ery Depletion	15	0								
	Malfunction	s		0	(0 related to	advisory)						
			Not Comprom tion Comprom		(0 related to							
	Advisories			None	see page 155	5 – 2005 Pot	ential Separati	on of Interconi	nect Wir	es		
90 80												
C)	i :	2 3	4		5	6	7 8	}	9	10	
	Years Afte	r Implant	—— Ма	function-Fre	ee Survival		All-0	Cause Surviva	ıl			
		1 yr	2 yr	3 yr	4 yr	5 yr	at 68 mo					
%		100.0	100.0	100.0	100.0	100.0	100.0					
%		100.0	100.0	100.0	100.0	100.0	100.0					
#		1.000	500	400	300	200	100					

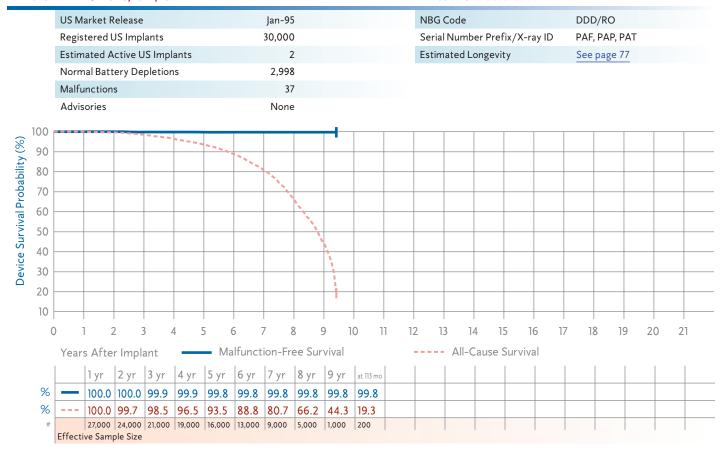
Thera D 7944, 7945, 7946

Effective Sample Size

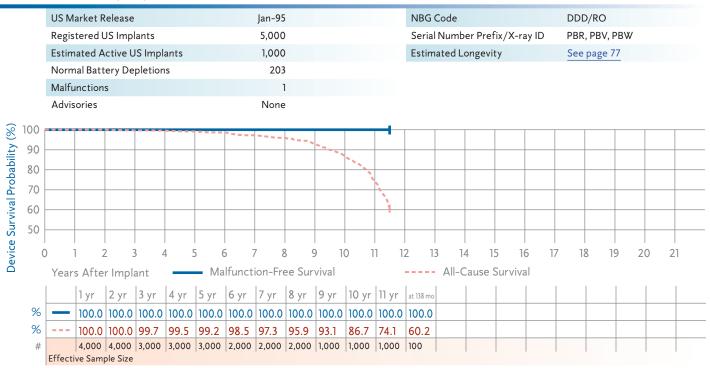
		US M	arket R	Release					Jan-95	5				NBG	Code				DDI	oco			
		Regis	tered l	JS Imp	lants				2,000)				Serial	Numb	er Prefi	ix/X-ra	y ID	PBD	, PBE,	PBF		
		Estim	ated A	ctive L	JS Impl	ants			2	2				Estim	ated L	ongevit	у		See	page	77		
		Norm	nal Batt	ery De	pletion	ıs			175	i													
		Malfu	ınction	S					2	2													
		Advis	ories						None	•													
(3)	100										_												
y (%)	90										<u> </u>												
Survival Probability	80							771.	~														
opa	70																						
al Pr																							
<u>×</u>	60									1													
Sul	50										'n												
Device	40																						
De	()	1 2	2 :	3 4	4 5	5 6	5 7	7 8	3 9	9 1	0 1	1 1	2 1:	3 1	4 15	5](5 17	7 1	8	19	20	21
		Year	s Afte	r Impl	ant		Ma	lfunct	ion-Fre	ee Sur	vival				All-C	Cause S	Surviva	ıl					
			1 yr		3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 111 mo											
	%		-	99.9	99.9	99.9	-	99.9		99.9	99.7	99.7											+
	%		99.9	99.8	98.9	97.3		90.0		66.7	53.3	47.2											+
	#				1,000			1,000		300	100	100											+
		Effecti	ve Sam	ple Size																			

Thera DR-40 7940, 7941, 7942

Product Characteristics

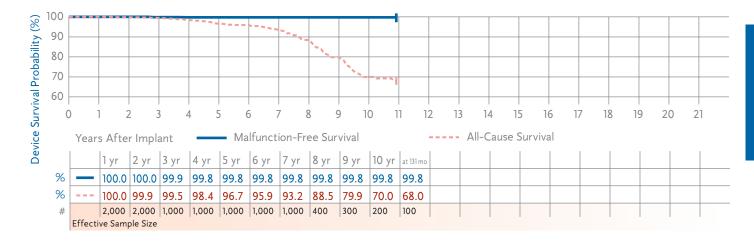


Thera DR-50 7950, 7951, 7952



Thera S 8944, 8945, 8946

US Market Release	Jan-95	NBG Code SSI/R
Registered US Implants	3,000	Serial Number Prefix/X-ray ID PBG, PBH, PBJ
Estimated Active US Implants	100	Estimated Longevity See page 78
Normal Battery Depletions	81	
Malfunctions	3	
Advisories	None	



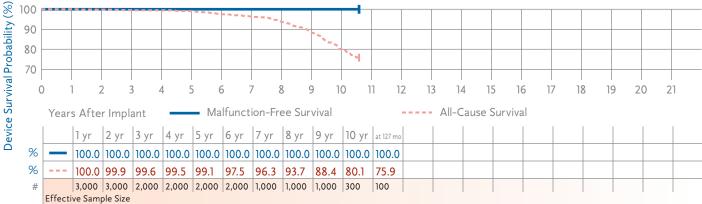
Thera	SR 8940	, 8941, 8	942									Р	Product	Chara	acteri	stics						
	US Marke	t Release	9				Jan-9	5				Ν	NBG Cod	e				SSI/	R			
	Registere	d US Imp	lants				14,000)				S	Serial Nu	mber F	Prefix/	X-ray I	D	PAU	, PAV, I	PAW		
	Estimated	Active U	JS Impl	ants			300)				Е	stimate	d Long	evity			See	page 7	8		
	Normal Ba	attery De	epletion	ıs			812	2														
	Malfunction	ons					16	5														
	Advisories	5					None	9														
<u>§</u> 100										1	-										_	
															_						-	-
Survival Probability 09 00 08 00 00							1														<u> </u>	
70 70								**														
<u>а</u> (
60																						
Su 50											۲-4											
Device 04												+									+	+
De (0 1	2	3 4	4 !	5 (5	7	8	9 1	0	11	12	13	14	15	16	17	18	3 19	9 2	20	21



Thera-i D 7964i, 7965i, 7966i

Product Characteristics

US Market Release	Oct-95	NBG Code DDDCO
Registered US Implants	3,000	Serial Number Prefix/X-ray ID PDE, PDF, P
Estimated Active US Implants	1,000	Estimated Longevity See page 78
Normal Battery Depletions	98	
Malfunctions	1	
Advisories	None	

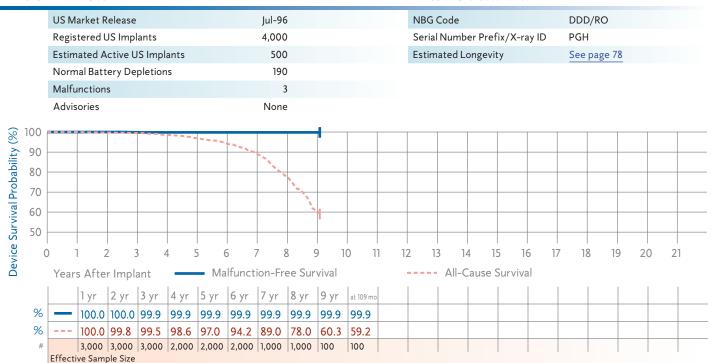


Thera-i DR 7960i, 7961i, 7962i

		,,,,,,	., , , , , , , ,	1, 7 302											iai acti							
	US Ma	arket R	elease					Oct-95					NBG	Code				D	DD/R	O		
	Regis	tered (JS Impl	ants			1.	22,000)				Serial	Numb	er Pref	ix/X-ra	ay ID	PΙ	OB, PC	C, PD	D	
	Estim	ated A	ctive U	S Impl	ants			28,000)				Estim	ated L	ongevi	y		Se	ee pag	ge 78		
	Norm	al Batt	ery De	pletion	s			4,217	,													
	Malfu	nction	S					50)													
	Advis	ories						None														
100																						
90																						
80										1	* .											
70																						
60											1											
50																						
() 1	2) 3	1 }	1. 5	5 6	5 7	1 7 {	3))]() 1	1 1:	2 1:	1 3 1,	4 1	5 1	6	17	18	19	20	21
	Years	Afte	r Impla	ant			Ifuncti							All-C	ause S	-	_					
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 7/2						1	1			
%		-	-	-						-		-							-	-	-	
							99.9					99.9										
%		100.0		99.7			98.2				75.0	54.0										
#	Let a a ti		ole Size	٥٩,000	80,000	71,000	62,000	33,000	38,000	22,000	7,000	100										

Thera-i DR 7968i

Product Characteristics



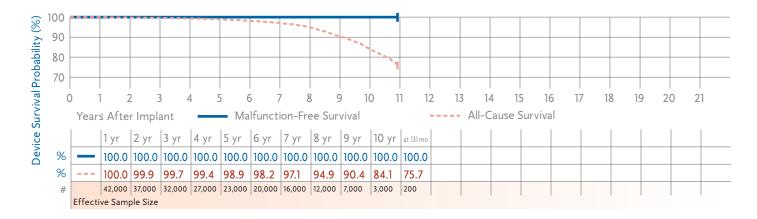
Thera-i S 8964i, 8965i, 8966i

	US M	arket R	elease				(Oct-95					NBG	Code				9	SSIR			
	Regis	tered (JS Impl	ants				4,000					Serial	Numb	er Pref	fix/X-ı	ray ID	F	DY, PE	A, PE	3	
	Estim	ated A	ctive U	S Impla	ants			1,000					Estim	ated L	ongevi	ty		9	ee pa	ge 78		
	Norm	al Batt	ery De	pletion	S			38														
	Malfu	nction	s					1														
	Advis	ories						None														
ourvival Probability (70) 08 06 001			2 3 r Impla	ant	1 5		5 7	on-Fre	ee Sur)](ı	1 12			4 1: Cause S		16 val	17	18	19	20	21
% % %	_			-	_	100.0			_													
% Ce						98.9					93.7	92.0										
#	Effecti		3,000			2,000					300	100										

Thera-i SR 8960i, 8961i, 8962i

Product Characteristics

US Market Release	Oct-95	NBG Code	SSIR
Registered US Implants	50,000	Serial Number Prefix/X-ray ID	PDU, PDV, PDW
Estimated Active US Implants	10,000	Estimated Longevity	See page 78
Normal Battery Depletions	920		
Malfunctions	7		
Advisories	None		



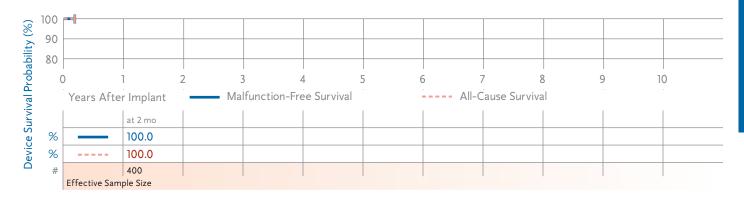
Thera-i VDD 8968i

Ine	era-	-ו עטט	8968	l										Produc	t Cha	racte	ristics	5						
		US Mark	et Rele	ase				Mar	-96					NBG Co	ode				VDI	D				
		Register	ed US I	mplants				5,0	000					Serial N	lumber	Prefix	x/X-ra	y ID	PEC	:				
		Estimate	ed Activ	ve US Im	plants	;		1,0	000					Estimat	ed Lor	ngevity	/		See	page	e 78			
		Normal I	Battery	Depleti	ons				49															
		Malfunc	tions						0															
		Advisori	es					N	one															
(%)	100										-													
	90										***													
Pilit	80										1													
oba			1					7	0		10	11	12	12	14	15	1		 	0	10	20	21	
val Probability		Years A	ب fter In	nplant	4	5	6 Malfun	ction-	8 -Free	9 Surviva	10 al	11	12	13	14 All-Ca	15 use Si	16 urviva		/ I	8	19	20	21	



Versa DR VEDR01

US Market Release	Jul-06	NBG Code	DDDR
Registered US Implants	2,000	Serial Number Prefix/X-ray ID	PWH
Estimated Active US Implants	2,000	Estimated Longevity	See page 78
Normal Battery Depletions	0		
Malfunctions	0		
Therapy Function Not Compromised	0		
Therapy Function Compromised	0		
Advisories	None		



Device Survival Summary (95% Confidence Interval)

The following table shows IPG device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

		s				Malfunctions sed to bes	to to bes			Device	Survival	Device Survival Probability (%)	lity (%)								
Market Jumber Selease	bessered barrend SI mplants stimsted SU sylvito. SU sylvito. Su satta standard standard su	batsmitzi CU avitzu CU avitzu stantique	ntive US mplants dormal Batt depletions pepletions my Fun derapy	depletions herapy Fun compromise	esimonqmo	herany	herapy unction No ompromise	lsto		Years A	<u> </u>	_	-	-	3			; ;	5	;	77. 71
DDR01, Jul-06 6,000 6,000 0 + DDR03, DDR06, DDR06, DD01	0000'9	+ 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0	† † † † † † † † † † † † † † † † † † †	0 0	+	L L		L 0	Malfunction- free	100.0 +0.0/-0.0 at 3 mo	-						_				2
									All-cause	100.0 +0.0/-0.0 at 3 mo											
ADSR03, Jul-06 1,000 1,000 0 + C ADSR03, ADSR06	+ 0 0 000'1 000'1	1,000 0 + 0 + 0	+ 0	+	+		0	0	Malfunction- free	100.0 +0.0/-0.0 at 2 mo											
									All-cause	100.0 +0.0/-0.0 at 2 mo											
AT501, Mar-03 11,000 8,000 127 4 + 3 7253	11,000 8,000 127 4 +	8,000 127 4 +	127 4 +	4	+	3	П	7	Malfunction- free	100.0+0.0/-0.1	100.0+	100.0+	99.3	99.3 +0.4/-1.2 a	99.3 +0.4/-1.2 at 61mo						
see page 165 – Performance note on ATS00 Pacing System Follow-Up Protocol	5 – Performance note on AT500 Pacing ow-Up Protocol	rmance note on AT500 Pacing	e on AT500 Pacing	acing					All-cause	100.0+0.0/-0.1	99.9	99.7	91.7	56.3 +5.4/-5.8	50.6 +5.7/-6.0 at 61mo						
7074, Apr-91 48,000 1,000 3,439 — — — 7075, 7076, 7077	48,000 1,000 3,439	1,000 3,439	3,439		1	1		85	Malfunction- free	100.0	99.9	99.9	99.8	99.8	99.8	99.8	99.8	99.8	99.8	99.8 +0.0/-0.1 at 157 mo	
									All-cause	99.9	99.8	99.6	99.5	98.9	97.8	95.6 +0.2/-0.3 +	91.0	76.4	53.3	20.0 +2.4/-2.3 at 157 mo	
EIDR01, Dec-03 7,000 5,000 1 0 + 1 EIDR03, EIDR06	7,000 5,000 1 0	5,000 1 0	1 0	0		-	П	-	Malfunction- free	100.0	100.0	100.0 +0.0/-0.1 at 35 mo									
									All-cause	100.0	100.0+0.0/-0.0	99.9 +0.1/-0.1 at 35 mo									
EIDR21 Dec-03 2,000 1,000 0 0 + 0	2,000 1,000 0 +	+ 0 0 000,1	+ 0	+	+	0	Ш	0	Malfunction- free	100.0	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 34 mo									
									All-cause	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 34 mo									
E2DR01, Feb-04 98,000 85,000 0 2 + 2 E2DR03, E2DR06	98,000 85,000 0 2 +	85,000 0 2 +	0 +	+	+	7	П	4	Malfunction- free	100.0	100.0	100.0 +0.0/-0.0 at 33 mo									
									All-cause	100.0	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 33 mo									

continuec	
Summary	
Survival	
Device	

		16 yr														
		14 yr														
		12 yr														
		10 yr											99.9 +0.0/-0.0 at 103 mo	16.0 +3.5/-3.2 at 103 mo	100.0 +0.0/-0.1 at 103 mo	68.0 +3.3/-3.6 at 103 mo
		8 yr											99.9	64.9 +1.1/-1.1	100.0+	79.6 +1.8/-2.0
		7 yr											99.9	91.0	100.0	96.0
		6 yr											99.9	97.8	100.0	98.8 +0.3/-0.3
		5 yr											99.9	99.2 +0.1/-0.1	100.0+0.0/-0.0	99.5 +0.1/-0.2
ility (%)		4 yr											100.0+0.0/-0.0	99.6	100.0	99.6 +0.1/-0.2
l Probab	plant	3 yr	100.0 +0.0/-0.0 at 30 mo	99.9 +0.1/-0.2 at 30 mo			100.0 +0.0/-0.0 at 34 mo	99.9 +0.1/-0.2 at 34 mo					100.0+0.0/-0.0	99.8	100.0	99.8
Device Survival Probability (%)	Years After Implant	2 yr	100.0+0.0/-0.0	99.9	100.0 +0.0/-0.0 at 20 mo	100.0 +0.0/-0.0 at 20 mo	100.0+0.0/-0.0	99.9	100.0 +0.0/-0.0 at 22 mo	100.0 +0.0/-0.0 at 22 mo	100.0 +0.0/-0.1 at 19 mo	99.9 +0.0/-0.1 at 19 mo	100.0+0.0/-0.0	99.9	100.0+0.0/-0.0	99.9
Device	Years /	l yr	100.0+0.0/-0.0	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0+0.0/-0.0	100.0	100.0+0.0/-0.0	100.0	99.9	100.0	99.9	100.0	99.9
			ion- free	use	tion- free	rse	ion- free	rse	ion- free	Ise	ion- free	ıse	ion- free	se	ion- free	nse
			Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause
	ļe	stoT	0 Malfuncti	All-ca	0 Malfuncti	All-ca	3 Malfunctio	All-ca	0 Malfunctio	All-car	9 Malfunctio	All-ca	21 Malfunctio	All-cau	4 Malfunctio	All-ca
ions	pesimorqu	Con	Malfunct	All-ca	Malfunci	All-ca	Malfunct	All-car	Malfunct	All-cau	Malfunct	All-cau	Malfunct	All-cau	Malfunct	All-ca
Aalfunctions	rapy rapy otion Mot noromised	Con Fund Con	= 0 Malfunct	All-ca	= 0 Malfunct	All-ca	= 3 Malfunct	All-ca	= 0 Malfunct	All-cau	= 9 Malfunct	All-cau	= 21 Malfunct	All-cau	= 4 Malfunct	All-ca
Malfunctions	rapy ction Not npromised	Dep The no on on on	+ 0 = 0 Malfunct	All-ca	+ 0 = 0 Malfunct	All-ca	+ 2 = 3 Malfunct	All-car	+ 0 = 0 Malfunct	All-cau	+ 2 = 9 Malfunct	All-car	+ 12 = 21 Malfunct	All-cau	+ 3 = 4 Malfunct	All-ca
Malfunctions	lants mal Battery mal Battery repy Function npromised repy repy mortion not	Act Imp Mor Dep The Con The The Con Tool	3 0 + 0 = 0 Malfunci	All-ca	0 + 0 = 0 Malfunci	All-ca	2 1 + 2 = 3 Malfunct	All-ca	0 + 0 = 0 Malfunct	All-cau	0 7 + 2 = 9 Malfunct	All-car	2,009 9 + 12 = 21 Malfunct	All-cau	256 1 + 3 = 4 Malfunct	All-ca
Malfunctions	mated ive US ive US lants mal Battery mal Battery rapy Function rapy Functi	Esti Act Imp Nor Dep The Con	10,000 3 0 + 0 = 0 Malfunct	All-ca	1,000 0 + 0 = 0 Malfunci	All-ca	20,000 2 1 + 2 = 3 Maifunct	All-ca	500 0 0 + 0 = 0 Malfunct	All-cau	44,000 0 7 + 2 = 9 Malfunct	All-car	13,000 2,009 9 + 12 = 21 Malfunct	All-cau	5,000 256 1 + 3 = 4 Malfunct	All-ca
Malfunctions	passed mplants mated ive US low ive lants mal Battery mal Battery notions rapy Function rapy Function repy Functio	Regg USI Esti Imp Nor The Con The Fun	12,000 10,000 3 0 + 0 = 0 Malfunct	All-ca	1,000 1,000 0 0 + 0 = 0 Malfunci	All-ca	24,000 20,000 2 1 + 2 = 3 Maifunct	All-ca	1,000 500 0 0 + 0 = 0 Malfunct	All-cau	48,000 44,000 0 7 + 2 = 9 Maifunct	All-car	46,000 13,000 2,009 9 + 12 = 21 Malfunci	All-cau	15,000 5,000 256 1 + 3 = 4 Malfunct	All-ca
Malfunctions	Market sase istered mplants ive US love US lants mal Battery lants rapy Function rapy Function rapy Function repy Function repy Function	USI Regg USI Mor Imp The Con	10,000 3 0 + 0 = 0 Malfunct	All-ca	1,000 0 + 0 = 0 Malfunci	All-ca	20,000 2 1 + 2 = 3 Maifunct	All-ca	500 0 0 + 0 = 0 Malfunct	All-cau	44,000 0 7 + 2 = 9 Malfunct	All-cau	13,000 2,009 9 + 12 = 21 Malfunct	All-cau	5,000 256 1 + 3 = 4 Malfunct	All-ca

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						Malfunctions		Device	Surviva	Device Survival Probability (%)	ility (%)								
λlir	del nber	Market sase	istered esplants	bətsm SU əvi stnsl	mal Battery snoiteld	reapy Function npromised srapy ction Mot opromised al		Years /	Years After Implant	plant									
Fam	ooM nuN		N2 I Keĝ	tэА		Con The		Jyr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Kappa 600 DR	KDR601, KDR603, KDR606	Jan-99	24,000	000,01	333	13 + 3 = 16	Malfunction- free	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	99.9	99.9 +0.0/-0.1	99.9 +0.0/-0.1	99.9 +0.0/-0.1	99.9 +0.0/-0.1 at 91 mo				
	Advisories Power Sup	see page ply Wires	157 – 2002	Advisories: see page 157 – 2002 Potential Fractured Power Supply Wires	tured	$\frac{(11)}{advisory-related subset}$	All-cause	100.0+0.0/-0.0	99.9	99.9	99.6 +0.1/-0.1	99.0	97.4 +0.3/-0.3	91.8	82.6 +2.3/-2.7 at 91 mo				
Kappa 600 DR	KDR651, KDR653	Mar-01	14,000	8,000	47	1 + 2 = 3	Malfunction- free	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0	100.0 +0.0/-0.1 at 67 mo						
	Advisories Power Sup	see page ply Wires	157 – 2002	Advisories: see page 157 – 2002 Potential Fractured Power Supply Wires	tured	(0) + (0) = (0) (advisory-related subset)	All-cause	100.0	99.9	99.8	99.5 +0.1/-0.2	98.9 +0.2/-0.3	98.4 +0.4/-0.4 at 67 mo						
Kappa 700 D	KD701, KD703, KD706	Jan-99	300	100	4	0 = 0 + 0	Malfunction- free	100.0	100.0+0.0/-0.0	100.0	100.0	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 69 mo						
	Advisories: see pag Power Supply Wires	see page ply Wires	<u>157</u> – 2002	see page 157 – 2002 Potential Fractured ly Wires	tured	(0) + (0) = (0) (advisory-related subset)	All-cause	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	98.9 +0.8/-3.1	97.6 +1.5/-3.9	95.7 +2.4/-5.2 at 69 mo						
Kappa 700 DR	KDR701, KDR703, KDR706	Feb-99	192,000	104,000	1,799	146 + 23 = 169	Malfunction- free	100.0+0.0/-0.0	100.0+	99.9	99.9	99.9	99.8	99.8	99.8 +0.0/-0.0 at 94 mo				
	Advisories: see page Power Supply Wires	see page ply Wires	<u> 157</u> – 2002	see page 157 – 2002 Potential Fractured ly Wires	tured	$\frac{(117)}{(advisory-related subset)}$	All-cause	99.9	99.9	99.7 +0.0/-0.0	99.3	98.5	96.6 +0.1/-0.2	90.9	75.8 +1.7/-1.8 at 94 mo				
Kappa 700 DR	KDR721	Feb-99	10,000	2,000	548	4 + 1 = 5	Malfunction- free	100.0	100.0+0.0/-0.1	100.0+0.0/-0.1	100.0	99.9	99.9	99.9 +0.0/-0.1 at 83 mo					
	Advisories Power Sup	see page ply Wires	157 – 2002	Advisories: see page 157 – 2002 Potential Fractured Power Supply Wires	tured	(4) + (0) = (4) (advisory-related subset)	All-cause	99.9	99.7 +0.1/-0.2	99.0	96.8	91.8	72.2 +1.8/-1.9	39.2 +4.2/-4.3 at 83 mo					
Kappa 700 SR	KSR701, KSR703, KSR706	Feb-99	55,000	24,000	513	6 + 3 = 9	Malfunction- free	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.1	100.0 +0.0/-0.1 at 93 mo				
							All-cause	100.0+0.0/-0.0	99.9	99.6	99.0	97.8 +0.2/-0.2	95.7 +0.3/-0.4	89.5 +0.9/-0.9	74.6 +3.3/-3.6 at 93 mo				
Kappa 700 VDD	KVDD701	Jan-99	2,000	1,000	42	3 + 0 = 3	Malfunction- free	99.9	99.9 +0.1/-0.4	99.9 +0.1/-0.4	99.8	99.8	99.7 +0.2/-0.6	99.7 +0.2/-0.6 at 82 mo					
	Advisories Power Sup	see page ply Wires	157 – 2002	Advisories: see page 157 – 2002 Potential Fractured Power Supply Wires	ctured	(3) + (0) = (3) (advisory-related subset)	All-cause	99.9	99.9	99.6	99.0	98.8	95.5	75.6 +4.9/-5.8 at 82 mo					

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Years After Implant Years Years After Implant Years Ye						—	Malfunctio	tions		Device	Survival	Device Survival Probability (%)	llity (%)						
All-cause 100.0	del mber ease jistered implants ive US ive US allants see US see	gistered Implants imated sive US slants smal Battery oletions	Implants imated sive US slants smal Battery oletions	ive US blants rmal Battery oletions erapy Function	oletions Prapy Function				al	Years A	vfter Im	plant		,	,				
Maffunction 100.00 100.0	US Ref. Regular Nor Imph Imph Imph	Reg Imp Mor Mor Imp	Esti Act Imp Noi Dep	Act Imp Noi Dep	Dep				юТ										16 yr
Malfunction 100.00 100.0	KDR801, Jan-02 4,000 3,000 3 0 KDR803	4,000 3,000 3	3,000 3 0	3	0		+			0.0	100.0+0.0+		0.0	100.0 +0.0/-0.0 at 51 mo					
All-cause												~		99.8 +0.1/-0.2 at 51 mo					
Maifunction-	KDR901, Jan-02 124,000 90,000 87 7 KDR903, KDR906	124,000 90,000 87 7	7 8 000,09	87 7	7		+				100.0+0.0/-0.0	100.0+0.0/-0.0		100.0 +0.0/-0.0 at 59 mo					
All-cause 100.0											100.0+0.0+	99.9		99.3 +0.1/-0.1 at 59 mo					
All-cause 100.0 99.9 93.8 99.4 99.1 415/mo 415/mo	KSR901, Jan-02 36,000 24,000 28 1 + KSR903, KSR906	36,000 24,000 28 1	24,000 28 1	28 1	_						100.0+0.0/-0.0	100.0+0.0/-0.0		99.9 +0.1/-0.3 at 57 mo					
Malfunction 100.0													+0.2/-0.2	99.1 +0.2/-0.3 at 57 mo					
Malfunction	KVDD901 Jan-02 1,000 400 0 0 +	1,000 400 0	400 0 0	0	0						100.0+0.0/-0.0		0.0	100.0 +0.0/-0.0 at 50 mo					
## All-cause 100.0											100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0+	100.0 +0.0/-0.0 at 50 mo					
All-cause 100.0 99.8 99.5 98.1 97.1 97.1 97.1 97.1 97.1 97.1 97.1 97.1 97.1 97.2 99.6	KDR921 Jan-02 16,000 11,000 60 1 +	16,000 11,000 60 1	11,000 60	60 1	_									100.0 +0.0/-0.1 at 56 mo					
Malfunction-free 99.9 +0.0/-0.0 99.8 +0.0/-0.0 99.7 +0.0/-0.0 99.7 +0.0/-0.0 99.7 +0.0/-0.0 99.7 +0.0/-0.0 99.7 +0.0/-0.0 99.8 +0.0/-0.0 99.7 +0.0/-0.0 99.8 +0.0/-0.0 99.7 +0.0/-0.0 99.8 +0.0/-0.0 99.6 +0.0/-0.0 99.6 +0.0/-0.0 99.6 +0.0/-0.0 99.6 +0.0/-0.0 99.6 +0.0/-0.0 99.6 +0.0/-0.0 99.6 +0.0/-0.0 99.6 +0.0/-0.0 99.7 +0.0/-0.0 99.9 +0.0/-0.0 99.9												01		97.1 +0.6/-0.7 at 56 mo					
All-cause 99.9 big. 100.0 99.7 big. 100.0 99.7 big. 100.0 99.7 big. 100.0 99.7 big. 100.0 99.9 big. 100.0<	8416, Aug-89 57,000 3,000 2,603 — 8417, 8417M, 8418, 8419	57,000 3,000 2,603	3,000 2,603	2,603		I		I	145			999.8							99.6 +0.1/-0.1 at 200 mc
Malfunction-free 100.0 100.0 100.0 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.5 99.5 99.5 99.5 99.5 99.5 99.5 99.5 99.5 99.5 99.7 99.5 99.5 99.7 99.7 99.5 99.2 98.8 98.1 97.2 94.8 89.2 83.3 75.3 #0.0/-0.0 #0.0/-0.0 #0.1/-0.1 #0.1/-0.1 #0.1/-0.1 #0.1/-0.1 #0.1/-0.2 #0.3/-0.2 #0.3/-0.6 #0.6/-0.6 #10/-1.1															97.2		0.6/-0.6		55.2 +1.7/-1.8 at 200 mc
99.9 99.7 99.5 99.2 98.8 98.8 98.1 97.2 94.8 89.2 89.3 75.3 75.3 +0.0/-0.0 +0.0/-0.0 +0.1/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 +0.3/-0.3 +0.4/-0.4 +0.6/-0.6 +1.0/-1.1	8424, Nov-91 59,000 6,000 1,671 — 8426, 8427	29,000 6,000 1,671	1,671 000,6	1,671		1		I	37			100.0+0.0/-0.0			9.99		0.0-/0.0	0.0-/0.0	99.9 +0.0/-0.0 at 177 mo
										 99.9	99.7					0.2/-0.2	89.2		72.2 +1.8/-1.9 at 177 mo

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		16 y	99.9 0 +0.0/-0.0 at 210 mo	75.0 +2.4/-2.7 at 210 mo	100.0 +0.0/-0.1 at 173 mo	72.4 +2.3/-2.4 at 173 mo										
		14 yr	99.9	81.2 +0.7/-0.7	100.0	73.8 +1.9/-2.0										
		12 yr	99.9 0.0-/0.0+	83.9 +0.6/-0.6	100.0+	82.7 +1.0/-1.1			100.0 +0.0/-0.0 at 123 mo	68.2 +3.1/-3.3 at 123 mo	100.0 +0.0/-0.1 at 121 mo	81.0 +2.5/-2.8 at 121mo				
		10 yr	9.99.9	87.2 +0.5/-0.5	100.0 +0.0/-0.1	89.3 +0.7/-0.8	99.9 +0.1/-0.9 at 105 mo	89.4 +3.2/-4.5 at 105 mo	100.0	73.2 +2.1/-2.2	100.0+0.0/-0.1	82.2 +2.0/-2.3	100.0 +0.0/-0.0 at 104 mo	82.1 +4.4/-5.6 at 104 mo	99.9 +0.1/-0.4 at 119 mo	95.9 +1.2/-1.7 at 119 mo
		8 yr	99.9	91.9	100.0	94.7 +0.5/-0.5	99.9	92.2 +2.3/-3.2	100.0+0.0/-0.0	93.7 +0.4/-0.5	100.0	93.2 +0.6/-0.7	100.0+0.0/-0.0	89.1 +2.8/-3.7	99.9 +0.1/-0.4	97.7
		7 yr	99.9	95.2 +0.3/-0.3	100.0+0.0/-0.1	96.9 +0.3/-0.4	99.9	92.9 +2.1/-3.0	100.0+0.0/-0.0	96.8 +0.3/-0.3	100.0+	95.3 +0.5/-0.5	100.0+0.0/-0.0	93.8 +1.9/-2.7	99.9 +0.1/-0.4	98.4
		6 yr	99.9	97.7 +0.2/-0.2	100.0	98.2 +0.2/-0.3	99.9	96.4	100.0+0.0/-0.0	98.1 +0.2/-0.2	100.0	97.6 +0.3/-0.4	100.0+0.0/-0.0	96.9	99.9 +0.1/-0.4	99.1
		5 yr		98.7	100.0	98.9	99.9	98.3 +0.8/-1.4	100.0+0.0/-0.0	99.0	100.0+0.0/-0.1	98.6 +0.2/-0.3	100.0+0.0/-0.0	97.8 +0.9/-1.7	99.9 +0.1/-0.4	99.2 +0.3/-0.6
ility (%)		4 yr	99.9	99.2 +0.1/-0.1	100.0+0.0/-0.1	99.5	99.9	98.3 +0.8/-1.4	100.0+0.0/-0.0	99.5	100.0+0.0/-0.1	99.3 +0.1/-0.2	100.0+0.0/-0.0	99.4 +0.4/-0.9	100.0+0.0/-0.0	99.8
Survival Probability (%)	plant	3 yr	99.9	99.5	100.0	99.8	99.9	99.1 +0.5/-1.2	100.0	99.7 +0.1/-0.1	100.0	99.6 +0.1/-0.1	100.0	99.4 +0.4/-0.9	100.0	99.8
	Years After Implant	2 yr	99.9	99.7	100.0	100.0+0.0/-0.0	99.9	99.7 +0.2/-0.8	100.0	99.9 +0.0/-0.1	100.0	99.9 +0.0/-0.1	100.0+0.0/-0.0	99.7 +0.2/-0.8	100.0	99.9
Device	Years /	l yr	100.0+0.0/-0.0	99.9	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	99.9 +0.0/-0.1	100.0+0.0/-0.0	99.7 +0.2/-0.8	100.0+0.0/-0.0	99.9
			ion- free	Se	ion- free	Se	ion- free	S S	ion- free	e e	ion- free	9	ion- free		ion- free	
			Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause	Malfunction- free	All-cause
	ļŧ	:toT	49 Malfunctio	– All-cau	4 Malfunctio	All-cau	1 Malfunctio	All-cau	3 Malfunction from	All-caus	1 Malfunction from	All-caus	0 Malfunction fro	All-cau	1 Malfunctio	All-cau
tions	rapy ction Not npromised al	Fun	Malfunct	— — All-саи	Malfunct	All-cau	Malfunct	All-cau	Malfunct	All-cau:	Malfunct	All-caus	Malfunct	All-cau	Malfunct	All-cau
Malfunctions	to'n Not npromised	The onu Toon	49 Malfunct	— — АІІ-саг	Malfunct	All-cau	Malfunct	All-cau	Malfunct	All-cau:	Malfunct	All-caus	Malfunct	All-cau:	Malfunct	All-cau
Malfunctions	npromised rapy ction Not npromised	Dep The Con The Tund	49 Malfunct	1	— 4 Malfunct	All-cau	— 1 Malfunct	All-cau	— 3 Malfunct	All-cau	Malfunct	All-caus	— 0 Malfunct	All-cau:	— 1 Malfunct	All-cau
Malfunctions	repy Function repy Function repy ction Not repy	Acti Imp Nor Dep The Con Fund	- 49 Maifunct	1	4 Malfunct	All-cau	— — I Malfunct	All-cau	— 3 Malfunct	All-cau:	— — J Malfunct	All-caus	— — 0 Malfunct	All-cau:	— — J Malfunct	All-cau
Malfunctions	iye US lants mal Battery letions rapy Function promised rapy respy respy respy respy respy respy	Esti Acti Imp Nor Dep The Con	1,446 — — 49 Malfunct	1	552 — — 4 Malfunct	All-cau	200 19 — — 1 Malfunct	All-cau	628 — — 3 Malfunct	All-cau:	288 — — 1 Malfunct	All-caus	200 32 0 Malfunct	All-cau:	19 — — I Malfunct	All-cau
Malfunctions	mated Sue Sive US Instance US	Regg USI Esti Imp Nor Imp The Con	58,000 5,000 1,446 — — 49 Malfunct	1	2,000 552 — — 4 Malfunct	All-cau	1,000 200 19 — — 1 Malfunct	All-cau	26,000 7,000 62 <mark>8</mark> — — 3 Malfunct	All-cau;	18,000 4,000 288 — — 1 Malfunct	All-caus	32 — — 0 Malfunct	All-cau;	1,000 19 — — 1 Maifunct	All-cau
Malfunctions	sase mplants mated sive US sive US sive US sive US mal Battery mal Battery letions repy Function repy Function repy Romised	USI Regular Mor Imp Mor The Con The Fun	5,000 1,446 — — 49 Malfunct		17,000 2,000 552 — — 4 Malfunct	All-cau	200 19 — — 1 Malfunct	All-cau	7,000 628 — — 3 Malfunct	All-cau;	4,000 288 — — 1 Malfunct	All-caus	1,000 200 32 — — 0 Malfunct	All-cau;	4,000 1,000 19 — — 1 Maifunct	All-cau

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					E	Malfunctions	ctions		E	Device	Surviva	Device Survival Probability (%)	ility (%)								
	as.	rket		sn	l Battery ions	onised omised	yo toM not bəsimo			>		4									
Family	ləboM dmuM	US Mai Releas	stegiste US Imp	smits∃ AvitoA nslqml	Norma Deplet		Therap Functio Tompr	Total		rears A	rears Arter Implant I vr 2 vr 3 vr	plant 3 vr	4 vr	5 vr	6 vr	7 vr	× × ×	10 vr	12 vr	14 vr	16 vr
ProdigyD	7864, 7865, 7866	Oct-95		00		1	I	0	Malfunction- free	0:0	0.0-/0.0	100.0	0.0	0.0	0.0	0.0	0.0	0	9.0		
									All-cause	99.9 +0.1/-0.2	99.7 +0.2/-0.3	99.4	98.8 +0.4/-0.6	98.6	97.7	97.1	95.9	82.6 +3.3/-3.9	82.6 +3.3/-3.9 at 121 mo		
ProdigyDR	7860, 7861, 7862	Oct-95	37,000	000,11	868	1	I	=	Malfunction- free	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0+0.0/-0.0+	100.0	100.0	100.0+	100.0+	100.0 +0.0/-0.1 at 126 mo		
									All-cause	99.9	99.9	99.8	99.5	99.0	98.2 +0.2/-0.2	96.7	93.3	76.9	71.0 +3.1/-3.4 at 126 mo		
Prodigy S	8164, 8165, 8166	Oct-95	2,000	400	22	1	I	0	Malfunction- free	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0+0.0/-0.0+	100.0+	100.0+	100.0+	100.0 +0.0/-0.0 at 119 mo			
									All-cause	99.9	99.9	99.8	99.2	99.2	99.2	98.9	97.2 +1.0/-1.6	91.3 +2.6/-3.5 at 119 mo			
Prodigy SR	8158, 8160, 8161, 8162	Oct-95	22,000	5,000	354	1	T	5	Malfunction- free	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 124 mo		
									All-cause	99.9	99.7 +0.1/-0.1	99.4	99.0	98.3	97.4 +0.3/-0.3	96.0 +0.4/-0.4	93.6 + 0.6/-0.6	81.4 +2.0/-2.2	78.0 +2.8/-3.1 at 124 mo		
Sensia DR	SEDRO1,	90-In(2,000	1,000	0	+	0	0	Malfunction- free	100.0 +0.0/-0.0 at 2 mo											
									All-cause	100.0 +0.0/-0.0 at 2 mo											
Sensia SR	SESRO1, SESO1	90-In(1,000	1,000	0	+	0	0	Malfunction- free	100.0 +0.0/-0.0 at 2 mo											
									All-cause	100.0 +0.0/-0.0 at 2 mo											
Sigma 100 S	SS103, SS106	Aug-99	1,000	200	33	+	0	0	Malfunction- free	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0+0.0/-0.0+	100.0 +0.0/-0.0 at 70 mo						
	Advisorie: of Interco	s: see page nnect Wire	155 – 2005 s	Advisories: see page 155 – 2005 Potential Separation of Interconnect Wires	oaration	(0) + (0) (advisory-rel	(0) = (0) y-related subset)	(0) ubset)	All-cause	100.0	100.0+0.0/-0.0	99.5	99.5	98.4	98.4 +1.0/-3.0 at 70 mo						

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Device Survival Summary continued

					ŀ	Malfunctions	ı	Device	Device Survival Probability (%)	l Probab	ility (%)								
Ylir	uper qel	Market ease	ristered stnslqml	bətsmi SU əvi: stnsk	mal Battery snoiteld	erapy Function mpromised erion Mot ction Mot mpromised		Years /	After Implant	plant									
Fam	ooM nuM		N2 I Ke§	tɔΑ		Cor The		l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Sigma 200 DR	SDR203	Aug-99	16,000	8,000	23	2 + 1 = 3	Malfunction- free	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 83 mo					
	Advisorie of Interco	Advisories: see page 15 of Interconnect Wires	155 – 2005 I	Advisories: <u>see page 155</u> – 2005 Potential Separation of Interconnect Wires	aration	(0) + (0) = (0) (advisory-related subset)	All-cause	100.0	99.9	99.9 +0.0/-0.1	99.8	99.6 +0.1/-0.2	99.2	98.8 +0.4/-0.6 at 83 mo					
Sigma 200 SR	SSR203	Sep-99	12,000	5,000	E	2 + 0 = 2	Malfunction- free	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0	100.0+0.0/-0.1	100.0+0.0/-0.1	100.0 +0.0/-0.1 at 83 mo					
	Advisorie of Interco	s: see page onnect Wire	155 – 2005 I	Advisories: <u>see page 155</u> – 2005 Potential Separation of Interconnect Wires	aration	(2) + (0) = (2) (advisory-related subset)	All-cause	100.0+0.0/-0.1	99.9 +0.1/-0.1	99.8	99.8	99.6 +0.1/-0.2	99.5	99.5 +0.2/-0.3 at 83 mo					
Sigma 300 DR	SDR303, SDR306	Aug-99	102,000	64,000	81	43 + 4 = 47	Malfunction- free	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	99.9	99.9	99.9	99.9	99.9 +0.0/-0.0 at 86 mo				
	Advisorie of Interco	Advisories: see page 15 of Interconnect Wires	155 – 2005 I	Advisories: <u>see page 155</u> – 2005 Potential Separation of Interconnect Wires	aration	(20) + (0) = (20) (advisory-related subset)	All-cause	100.0+0.0/-0.0	99.9	99.9	99.7 +0.0/-0.1	99.5	99.3	98.8	98.8 +0.3/-0.4 at 86 mo				
Sigma 300 SR	SSR303, SSR306	Sep-99	51,000	26,000	44	7 + 1 = 8	Malfunction- free	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0					
	Advisorie of Interco	s: see page onnect Wire	155 – 2005 l	Advisories: see page 155 – 2005 Potential Separation of Interconnect Wires	aration	(5) + (0) = (5) (advisory-related subset)	All-cause	100.0	9.99	99.9	99.7 +0.1/-0.1	99.5	99.0	98.5					
Sigma 300 VDD	SVDD303	Sep-99	1,000	300	0	0 = 0 + 0	Malfunction- free	100.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0 +0.0/-0.0 at 68 mo						
	Advisorie of Interco	s: see page onnect Wire	155 – 2005 I	Advisories: see page 155 – 2005 Potential Separation of Interconnect Wires	oaration	(0) + (0) = (0) (advisory-related subset)	All-cause	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0	100.0+0.0/-0.0						
Thera D	7944, 7945, 7946	Jan-95	2,000	2	175		Malfunction- free	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.7 +0.3/-1.3 at 111 mo			
							All-cause	99.9	99.8 +0.2/-0.4	98.9	97.3 +0.8/-1.0	93.5 +1.3/-1.6	90.0	82.8 +2.3/-2.6	66.7 +3.5/-3.8	47.2 +4.9/-5.0 at 111 mo			
Thera DR-40	7940, 7941, 7942	Jan-95	30,000	2	2,998	37	Malfunction- free	100.0	100.0+0.0/-0.0	99.9	99.9	99.8	99.8	99.8	99.8	99.8 +0.0/-0.1 at 113 mo			
							All-cause	100.0+0.0/-0.0	99.7 +0.1/-0.1	98.5 +0.2/-0.2	96.5	93.5	88.8	80.7+0.6/-0.6	66.2	19.3 +2.7/-2.5 at 113 mo			

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					ŀ	Malfuncti	tions		Į	Device	Survival	Device Survival Probability (%)	lity (%)								
γliı	jel nber	Market sase	bətətsi stnslqm	bətsm 2U əvi stnsi	mal Battery eletions	rapy Function npromised	rapy ction Mot npromised ,	Įŧ		Years A	After Implant	plant									
Fam	ooM nuM			tοΑ		Con	Fund	:toT		l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Thera DR-50	7950, 7951, 7952	Jan-95	2,000	1,000	203	T	I	_	Malfunction-	100.0 + 0.0/-0.1	100.0+	100.0+	100.0+	100.00+	100.0+	100.0+	100.0+	100.0	100.0 +0.0/-0.1 at 138 mo		
						ı	ı		All-cause	100.0+	100.0+	99.7	99.5	99.2 +0.3/-0.4	98.5	97.3	95.9	86.7	60.2 +4.3/-4.6 at 138 mo		
Thera S	8944, 8945, 8946	Jan-95	3,000	100	8	1	1	8	Malfunction- free	100.0+	100.0+	99.9	99.8	99.8	99.8	99.8	99.8	99.8	99.8 +0.2/-0.5 at 131mo		
									All-cause	100.0+	99.9	99.5	98.4 +0.5/-0.8 +	96.7	95.9	93.2	88.5	70.0	68.0 +4.4/-4.9 at 131mo		
Thera SR	8940, 8941, 8942	Jan-95	14,000	300	812	T	I	N 91	Malfunction-	100.0+	99.9	99.9	99.8	99.8	99.8	99.8	99.8	99.8	99.8 +0.1/-0.1 at 136 mo		
						1	ı		All-cause	99.8	99.5	99.0	97.7	96.2	93.3 +0.6/-0.6	87.7 +0.8/-0.9	77.2	53.8 +2.2/-2.2	46.6 +2.7/-2.8 at 136 mo		
Thera-iD	7964i, 7965i, 7966i	Oct-95	3,000	1,000	86	T	T	_	Malfunction-	100.0+	100.0	100.0	100.0	100.0 +0.0/-0.2	100.0	100.0	100.0	100.0	100.0 +0.0/-0.2 at 127 mo		
									All-cause	100.0+	99.9	99.6	99.5	99.1	97.5	96.3	93.7	80.1	75.9 +3.6/-4.1 at 127 mo		
Thera-iDR	7960i, 7961i, 7962i	Oct-95	122,000	28,000	4,217	T	I	20 N	Malfunction-	100.0	100.0+	100.0+	100.0+	0.001	99.9	9.99	99.9	99.9	99.9 +0.0/-0.0 at 132 mo		
									All-cause	100.0+	99.9	99.7	99.5	99.0	98.2 +0.1/-0.1	96.6	93.2	75.0	54.0 +3.2/-3.3 at 132 mo		
Thera-i DR	7968i	96-In(4,000	200	061	1	I	3 N	Malfunction-	100.0 + 0.0-/0.0+	100.0+	99.9	99.9	99.9	99.9	99.9	99.9	99.9 +0.1/-0.2 at 109 mo			
									All-cause	100.0+	99.8	99.5	98.6 +0.4/-0.6 +	97.0 +0.6/-0.8	94.2	89.0	78.0 +2.3/-2.5	59.2 +4.3/-4.6 at 109 mo			
Thera-i S	8964i, 8965i, 8966i	Oct-95	4,000	1,000	38	T.	I	_	Malfunction-	100.0+	100.0+	100.0+	100.0+	100.0+	100.0 + 0.0/-0.3 +	100.0+0.0/-0.3	100.0	100.0	100.0 +0.0/-0.3 at 127 mo		
									All-cause	99.9	99.9	99.8	99.3	98.9	98.2 +0.5/-0.8	97.5	96.3	93.7	92.0 +1.9/-2.5 at 127 mo		

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		16 yr						
		14 yr						
		12 yr 14 yr	100.0 +0.0/-0.0 at 131mo	75.7 +2.3/-2.5 at 131mo	100.0 +0.0/-0.0 at 125 mo	86.7 +3.2/-4.1 at 125 mo		
		10 yr	100.0 100.0	100.0 99.9 99.7 99.4 98.9 98.2 97.1 94.9 84.1 75.7 10.0,-0.0 10.0,-0.0 10.1,-0.1 10.1,-0.1 10.2,-0.2 10.2,-0.2 10.3,-0.3 10.8,-0.9 13.13.1mo	100.0	100.0 998 99.6 99.6 99.3 99.2 99.2 98.4 89.1 86.7 +0.0.0/-0.1 +0.1/-0.2 +0.1/-0.3 +0.2/-0.3 +0.2/-0.4 +0.3/-0.4 +0.3/-0.4 +0.3/-0.4 +0.4/-0.6 +2.4/-3.0 +3.2/-4.1 at 125 mo		
		8 yr	100.0	94.9	100.0	98.4 +0.4/-0.6		
		7 yr	100.0	97.1	100.0	99.2		
		6 yr	100.0	98.2	100.0	99.2		
(0		5 yr	100.0	98.9 +0.1/-0.1	100.0	99.3		
Device Survival Probability (%)		4 yr	100.0	99.4 +0.1/-0.1	100.0 +0.0/-0.0	99.6 +0.2/-0.3		
al Proba	nplant	2 yr 3 yr	100.0	99.7	100.0	99.6		
e Surviv	Years After Implant	2 yr	100.0	99.9	100.0	99.8		
Device	Years	1 yr	100.0+0.0/-0.0	100.0	100.0		100.0 +0.0/-0.0 at 2 mo	100.0 +0.0/-0.0 at 2 mo
			Malfunction- free +0.0/-0.0	All-cause	Malfunction-free 100.0	All-cause	Malfunction- free +0.0/-0.0 at 2 mo	All-cause 100.0 +0.0/-0.0 at 2 mo
	ין	stoT	7 Malfunction- free	All-cause	0 Malfunction- free	All-cause	0 Malfunction- free	All-cause
nctions	yqs toM noit: bəsimonqı lı	Fund	- 7 Malfunction- free	All-cause		All-cause		All-cause
Malfunctions	toV noits besimorqi	Their Fund Ton	7 Malfunction- free	All-cause	0	All-cause	0	All-cause
Malfunctions	promised rapy tion Not dromised	Dep Thei Thei Thei Thei	7 –	All-cause	0	All-cause	0 –	All-cause
Malfunctions	rapy Function rapy Function rapy rapy tion Not bezimony	Acti Mori Dep Thei Com Thei Fund	7 - 7	All-cause	0	All-cause	0	All-cause
Malfunctions	nat Battery mal Battery letions rapy Function promised yqsy yqsy yqsy yqsy yqsy yqsy yqsy	USIII Estii Acti Impi Morri Dep Thee Com The	920 – 7	All-cause	49 - 0	All-cause	0 0	All-cause
Malfunctions	mplants mplants ve US ve US ants mal Battery letions rapy Function promised rapy rapy rapy rapy rapy rapy rapy rapy	Reggard Moring M	10,000 920 - 7	All-cause	1,000 49 — — 0	All-cause	2,000 0 0	All-cause
Malfunctions	Asrket asse mplants mplants ve US ants ants letions rapy Function promised vapy vapy vapy vapy vapy vapy vapy	US N Region US II US II Novi Movi Inpp Ther Ther Ther	50,000 10,000 920 - 7	All-cause	5,000 1,000 49 0	All-cause	2,000 2,000 0 0	All-cause



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The longevity estimates shown here assume a lower rate of 60 ppm, 100% pacing, and pulse width of 0.4 ms unless noted otherwise. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates. The elective replacement time is indicated via telemetry indication, and rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet), unless noted otherwise.

		Estimated Long	evity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Adapta DR	ADDR01, ADDR03, ADDR06, ADD01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.3 6.0	**
Adapta DR	ADDRS1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**
Adapta DR	ADDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.1 7.4 5.4	10.1 9.0 7.3	**
Adapta SR	ADSR01, ADSR03, ADSR06	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**
Adapta VDD	ADVDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.5 4.4	6.5 6.2 5.4	**
AT500	AT501, 7253	Low 2.0 V (A, RV) Nominal 3.0 V (A, RV) High 5.0 V (A, RV)	7.7 5.8 3.7	8.3 7.0 5.2	Telemetry indication. Pacing mode and rate (magnet and non-magnet) as programmed.
Elite	7074, 7075, 7076, 7077	Low 2.5 V, 0.36 ms (A, RV) Nominal 3.3 V, 0.36 ms (A, RV) High 5.0 V, 0.36 ms (A, RV)	11.8 8.6 6.7	13.2 11.0 9.4	**
EnPulse DR	EIDR01, EIDR03, EIDR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse DR	EIDR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR01, E2DR03, E2DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse 2 DR	E2DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR31, E2DR33	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.4 5.2	10.1 9.1 7.1	**
EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 6.3 4.8	7.7 7.3 6.1	**
EnPulse 2 VDD	E2VDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.1 5.5 4.3	6.5 6.2 5.4	**
EnRhythm DR	P1501DR	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.6 8.0 5.4	12.3 10.3 7.8	Telemetry indication. Pacing mode and rate (magnet and non-magnet) as programmed.
Kappa 400 DR	KDR401, KDR403	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.8 6.4 5.1	8.5 7.5 6.5	**
Kappa 400 SR	KSR401, KSR403	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.9 6.9 5.8	8.4 7.7 7.0	**

^{**}Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

		Estimated Long	evity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Kappa 600 DR	KDR601, KDR603, KDR606	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 600 DR	KDR651, KDR653	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Карра 700 D	KD701, KD703, KD706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR701, KDR703, KDR706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR721	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.2	**
Kappa 700 SR	KSR701, KSR703, KSR706	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 4.9	7.9 7.5 6.2	**
Kappa 700 VDD	KVDD701	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.3	**
Kappa 800 DR	KDR801, KDR803	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR901, KDR903, KDR906	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 920 DR	KDR921	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.3	**
Kappa 900 SR	KSR901, KSR903, KSR906	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 4.9	7.9 7.4 6.1	**
Kappa 900 VDD	KVDD901	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.4	**
Legend	8416, 8417, 8417M, 8418, 8419	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	15.6 11.3 9.0	17.7 14.5 12.5	If programmed to non-rate responsive mode (e.g. VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g. VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Legend II	8424, 8426, 8427	Low 2.5 V, 0.36 ms (RV) Nominal 3.3 V, 0.36 ms (RV) High 5.0 V, 0.36 ms (RV)	12.9 9.4 7.8	14.5 11.8 10.5	If programmed to non-rate responsive mode (e.g. VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g. VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Minix	8340, 8341, 8341M, 8342	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	14.9 10.2 7.9	17.3 13.6 11.3	Telemetry indication. Rate decrease of 10% from programmed rate.
Minix ST	8330, 8331, 8331M	Low 2.5 V (RV) Nominal 5.0 V (RV) High 8.0 V (RV)	14.9 7.9 4.0	17.3 11.4 7.0	Telemetry indication. Rate decrease of 10% from programmed rate.
Minuet	7107, 7108	Low 2.5 V, 0.36 ms (A, RV) Nominal 4.0 V, 0.36 ms (A, RV) High 5.0 V, 0.36 ms (A, RV)	12.5 7.7 4.7	15.6 10.9 7.6	**
Preva D	7068	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.0 7.4 5.4	11.4 9.5 7.6	**

 $^{{\}rm **Telemetry\ indication.\ Rate\ and\ mode\ change\ to\ 65\ ppm\ and\ VVI\ respectively\ (VOO/65\ with\ magnet)}.$



Reference Chart continued

		Estimated Lon	gevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Preva DR	7088, 7089	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Preva SR	8088, 8089	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Preva ST DR	7078	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Prevail S	8085, 8086	Low 2.5 V, 0.42 ms (RV) Nominal 3.3 V, 0.42 ms (RV) High 5.0 V, 0.42 ms (RV)	16.4 10.8 8.6	19.4 14.4 12.4	Telemetry indication. Rate decrease of 10% from programmed rate.
Prodigy D	7864, 7865, 7866	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.0 7.4 5.4	11.4 9.5 7.6	**
Prodigy DR	7860, 7861, 7862	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Prodigy S	8164, 8165, 8166	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.0 8.1 6.4	10.9 9.6 8.2	**
Prodigy SR	8158, 8160, 8161, 8162	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Sensia DR	SEDR01, SED01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**
Sensia DR	SEDRLI	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.1 7.4 5.4	10.1 9.0 7.3	**
Sensia SR	SESR01, SES01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**
Sigma 100 S	SS103, SS106	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	vie sie
Sigma 200 DR	SDR203	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 200 SR	SSR203	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 DR	SDR303, SDR306	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 300 SR	SSR303, SSR306	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	vie sie
Sigma 300 VDD	SVDD303	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	8.9 7.3 5.8	9.7 8.6 7.4	**
Thera D	7944, 7945, 7946	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.6 5.5 3.7	8.8 7.1 5.6	**
Thera DR-40	7940, 7941, 7942	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.6 5.5 3.7	8.7 7.0 5.6	**
Thera DR-50	7950, 7951, 7952	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	12.2 9.1 6.7	14.0 11.6 9.3	**

 $[\]star\star$ Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

		Estimated l	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Thera S	8944, 8945, 8946	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.5 6.1 4.8	8.2 7.2 6.2	**
Thera SR	8940, 8941, 8942	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.0 4.8	8.0 7.1 6.1	**
Thera-i D	7964i, 7965i, 7966i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.0 7.4 5.4	11.4 9.5 7.6	**
Thera-i DR	7960i, 7961i, 7962i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Thera-i DR	7968i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 5.4 3.9	8.3 6.9 5.5	**
Thera-i S	8964i, 8965i, 8966i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.0 8.1 6.4	10.9 9.6 8.2	**
Thera-i SR	8960i, 8961i, 8962i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Thera-i VDD	8968i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	11.5 9.6 7.7	12.4 11.1 9.7	**
Versa DR	VEDR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**

 $^{{\}rm **Telemetry\ indication.\ Rate\ and\ mode\ change\ to\ 65\ ppm\ and\ VVI\ respectively\ (VOO/65\ with\ magnet)}.$

Method for Estimating Lead Performance

Medtronic CRDM has tracked lead survival for over 20 years with its multicenter chronic lead studies.

Leads Performance Analysis

The human body is a hostile environment for an implantable device. Typically, the human body will attack and attempt to isolate or destroy any foreign object, including leads. Additionally, implanted leads are subjected to bending and twisting associated with heart motion, body motion, and patient anatomy, which can cause a lead to wear out.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. While IPGs and ICDs have a battery that will deplete after a predictable length of time, a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. Therefore, regular monitoring while implanted, and evaluation of lead integrity upon IPG or ICD replacement, is necessary to determine if lead may be approaching the end of its service life.

Returned Product Analysis Shortfalls

All leads and lead segments returned to Medtronic are analyzed to determine whether or not they meet performance limits established by Medtronic. Although returned product analyses are valuable for gaining insight into lead failure mechanisms, this data cannot be used by itself for determining the survival probability of leads because only a small fraction of leads are explanted and returned for analysis. Additionally, those leads which are returned cannot be assumed to be statistically representative of the performance of the total population for a given lead model. Partial or total lead extraction can result in significant damage to a lead, making a definitive analysis of a suspected failure and its cause impossible. Thus, lead survival probabilities are more appropriately determined through a clinical surveillance study. Although laboratory analysis results are presented in this report, Medtronic tracks lead survival through its System Longevity Study.

System Longevity Study (SLS)

The SLS is a prospective, multicenter study designed to monitor the performance of market-released cardiac therapy products. The SLS is the unification of the Chronic Lead Study (CLS) for pacing leads and the Tachyarrhythmia Chronic Systems Study (TCSS) for ICD leads, which have been ongoing in several geographies since 1983 and 1991, respectively. More than 35 centers participating as CLS study sites or TCSS study sites, or both, are expected to complete the unification to become SLS study sites in 2007. Through these studies, Medtronic has over 20 years of lead data from over 70,000 leads studied. More than 19,000 of these leads are currently active.

Patients are eligible for enrollment in the study if

- 1 They are within 6 months post-implant of a Medtronic market-released lead connected to a market-released CRT, ICD, or IPG device, and the lead is used for a pacing, sensing, or defibrillation application, or
- 2 They participated in a qualifying study of a market-released Medtronic cardiac therapy product; complete implant and follow-up data are available; and the data is appropriately and legally released for use in the study.

Lead Complications

The SLS complication criteria are defined below. These criteria do not, however, enable a lead integrity or "hardware" failure to be conclusively differentiated from other clinical events such as an undetected lead dislodgement, exit block, or concurrent pulse generator failure manifested as a sensing or capture problem.

A lead-related complication is considered to have occurred if at least one of the following clinical observations is reported and at least one of the following clinical actions is made 30 days or more after the implant.

Clinical Observations

- Failure to capture
- Failure to sense/undersensing
- Oversensing
- Abnormal pacing impedance (based on lead model, but normal range is typically 200-3000 ohms)
- Abnormal defibrillation impedance (based on lead model, but normal range is typically 20-200 ohms)
- Insulation breach, observed visually, that has degraded system performance

Method for Estimating Lead Performance continued

The Standard Actuarial Method is used to determine estimates of lead survival.

- Conductor fracture, observed visually or radiographically
- Extracardiac stimulation
- Cardiac perforation
- Lead dislodgement

Clinical Actions

- Lead surgically abandoned/capped
- Lead electrically abandoned/capped
- Lead explanted
- Lead replaced
- Polarity reprogrammed (i.e., bipolar to unipolar; unipolar to bipolar)
- Lead use continued based on medical judgment despite a known clinical performance issue
- Other lead-related surgery performed (e.g., lead mechanical alteration or unsuccessful repositioning)

Note: Successful lead repositioning is not a qualifying action.

Methods

The performance of leads is expressed in terms of lead survival estimates, where "survival" refers to the function of the lead, not the survival of the patient. These survival estimates are intended to illustrate the probability that a lead will survive for a given number of years without a lead-related complication.

The survival estimates are determined from the analysis of the data collected through the SLS. These data are presented graphically and numerically.

The SLS protocol requires regular follow-up reporting on all leads actively followed in the study. Each study center must inform Medtronic whenever a lead complication has occurred or when a patient is no longer participating in the study. Under the study protocol, each lead is assumed to be normally active unless a lead-related complication is confirmed, the lead is electively abandoned or explanted, or the patient is no longer available for follow-up. The data analyses assume that the patient is still part of the study and there are no lead complications at the time of the report cutoff date unless specifically reported by the center or by correlation with returned product analysis. Implant times are calculated from the implant date to the earlier of the complication date, out-of-service date (for example, patient leaves the study or the lead is no longer being used), or the cutoff date of the report.

If a lead experiences more than one complication, the first is used to calculate survival time; although all complications associated with a lead are reported in PPR tables.

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of lead survival. This method is commonly used by medical researchers and clinicians.

On the following pages, each graph includes a survival curve where events include qualifying lead-related complications. This survival estimate is a good representation of the probability a lead will survive a period of time without a lead-related complication. For example, if a survival probability is 95% after 5 years of service, then the lead has a 5% chance of experiencing a lead-related complication in the first 5 years following implant.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the number of leads entering an interval is less than 50 leads. When the number of leads entering an interval reaches 50, the next data point is added to the survival curve.

Although the report provides tabular data in one year intervals, the curves are actually computed and plotted using three-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have 1 or more complications. This occurs because even with the complications, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Method for Estimating Lead Performance continued

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the patients successfully enrolled in the SLS as of the report cutoff date. The number of enrolled implants is listed for each model.

This sample based on SLS enrollments is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

In general, a model or model family will be included in this report when more than 100 leads have been enrolled and no fewer than 50 leads followed for at least 6 months. Models will remain in the report as long as Medtronic estimates at least 500 leads remain active in the United States, based on estimated US implants.

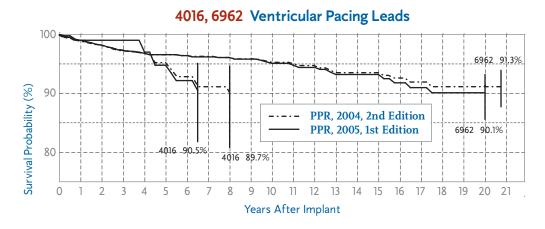
Chronic Lead Data Resolution

Because an accurate estimate of lead survival depends on an accurate estimate of the number of leads in service, it is important not to overstate the number of devices in service. Since the inception of the CLS and TCSS studies, the mechanism of patient follow-up has changed due to evolution in hospital follow-up practices and extrinsic issues such as the impact of the Health Insurance Portability and Accountability Act for US centers. As a result, some patients who were thought to be active participants in the study are actually no longer available for study follow-up. Therefore, Medtronic has initiated an additional data resolution process to verify lead status for all active study patients. This process is ongoing and is expected to conclude in 2007. Combined with our

prospective study monitoring practices, this process aligns with our continuous efforts to improve product performance reporting. The survival curves in this edition of the Product Performance Report reflect this additional process.

This data resolution process can change survival estimates when patients in whom leads were thought to be active at the time of the previous analysis have since been determined to no longer be available for follow-up. This has the effect of shortening the curve if leads that were previously presumed to be among those with the longest survival are no longer active at that time. Such a determination also decreases the number of leads remaining in the analysis cohort, which generally lowers the estimated probability of survival.

As the data resolution process proceeds, survival curves can change from one issue of the PPR to the next. For example, as noted in the figure below, the curve for the ventricular lead model 4016 extends to 8 years with an estimated survival probability of 89.7% in the 2004 Second Edition PPR, but extends to 6.5 years with an estimated survival probability of 90.5% in the 2005 First Edition. In contrast, the curve for the ventricular lead model 6962 extends to 20.75 years with an estimated survival probability of 91.3% in the 2004 Second Edition, but extends to 20 years with an estimated survival probability of 90.1% in the 2005 First Edition. The confidence intervals at the ends of the curves are included here for consistency with those in the rest of the report. In general, these confidence intervals are not statistically comparable for assessing whether survival probability has changed between different editions of the PPR.



Method for Estimating Lead Performance continued

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

Laboratory Analysis Results

Every lead or lead portion returned to Medtronic receives an analysis. Although the laboratory analysis data is not used to generate the survival estimates, the data provides valuable insight into the causes of lead malfunction.

For reporting laboratory analysis results, Medtronic CRDM considers a lead as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction for laboratory results reporting, the lead must have been returned to Medtronic and analyzed.

Lead malfunctions are divided into three categories: Implant Damage, Electrical, and Other. Typical examples of implant damage are stylet perforation, cut or torn insulation, bent or distorted conductors, over-retracted helixes, and conductor fracture due to overtorquing. An electrical malfunction is defined as a hardware malfunction resulting in a break in the insulation or a break in the conductor that could affect the electrical performance of the lead. A break in the insulation is defined as a breach allowing entry of body fluids, or inappropriate current flow between the conductors, or between the conductor and the body. Examples include cuts, tears, depressions. environmental stress cracking (ESC), and metal ion oxidation (MIO). A break in the conductor of a lead is defined as the loss of continuity in the metallic components that could interrupt the current flow or voltage. Examples include fractured conductors and defective crimps.

Leads damaged after explant or damaged due to failure to heed warnings or contraindications in the labeling are not considered device malfunctions.

A lead subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

For leads designed for either ventricular or atrial use, the numbers listed in the Laboratory Results tables include both.

Estimated Number of Implanted and Active Leads in the United States

In addition to providing the number of leads enrolled in the SLS, this report also provides estimates for the number of leads implanted in the United States and the number remaining active in the United States. The number of US implants is estimated based on the total number of leads sold in the United States. The number of active implants is estimated using the total number of leads sold and projections for normal patient mortality, elective replacement, and lead failure. The number of implanted leads and active leads is adjusted for underreporting of patient mortality, elective replacement, and lead failure.

The numbers of malfunctions listed in the Laboratory Results tables are the actual numbers confirmed in the laboratory. The numbers of complications listed in the complications tables are the actual numbers observed in the SLS.

Some lead models do not have a survival curve presented in this report. These lead models do not have a survival curve because they have insufficient sample size in the System Longevity Study. Laboratory results for these models are included here for reference and comparison.

Left-Heart Leads

2187 Attain

Product Characteristics

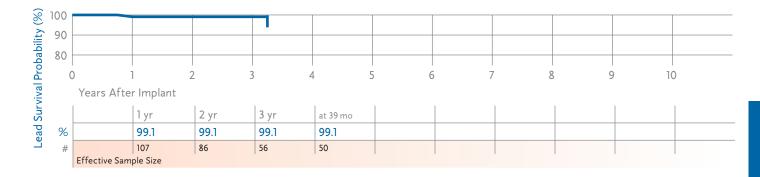
US Market Release	Aug-01	Serial Number Prefix	LEY	Laboratory Analysis	
Estimated US Implants	17,100	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Continuous Curve	Implant Damage	7
Estimated US Active	11,200	Polarity	Unipolar	Electrical Malfunction Other	0 16
Advisories	None	Steroid	No	o their	

Prospective Clinical Study Results

Qualifying Complications 1 Total

Nur	nber o	f Lea	ads Ei	nrolled ir	1 Study	132	Failure to Capture	1
_	1		- 1	C = 11		4.0.40		

Cumulative Months of Follow-Up 4,943



2188 Attain

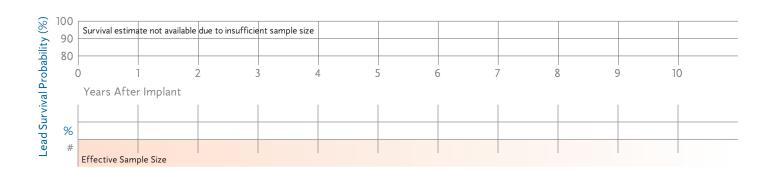
Product Characteristics

US Market Release	Aug-01	Serial Number Prefix	LEB	Laboratory Analysis
Estimated US Implants	2,800	Type and/or Fixation	Transvenous, Coronary Sinus/ Cardiac Vein, Canted	Implant Damage
Estimated US Active	1,600	Polarity	Bipolar	Electrical Malfunction Other (
Advisories	None	Steroid	No	o inci

Prospective Clinical Study Results

Qualifying Complications 1 Total

Number of Leads Enrolled in Study	14	Extra Cardiac Stimulation	1
Cumulative Months of Follow-Up	490		



Left-Heart Leads continued

4193 Attain

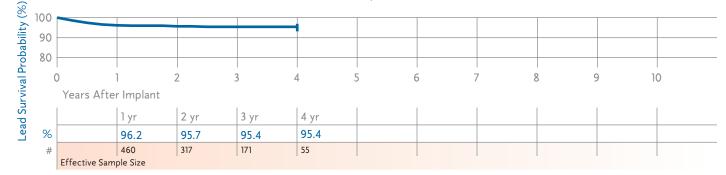
Product Characteristics

US Market Release	May-02	Serial Number Prefix	BAA	Laboratory Analysis	
Estimated US Implants	99,000	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Double Curve	Implant Damage	
Estimated US Active	76,800	Polarity	Unipolar	Electrical Malfunction Other	15 63
Advisories	None	Steroid	Yes	Other	03

Prospective Clinical Study Results

Qualifying Complications 26 Total

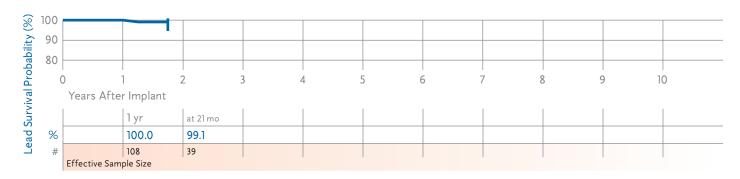
Number of Leads Enrolled in Study	665	Conductor Fracture	1
Cumulative Months of Follow-Up	16,560	Extra Cardiac Stimulation Failure to Capture	4 9
		Lead Dislodgement	9
		Unspecified Clinical Failure	3



4194 Attain

Product Characteristics

	1000111			T TO GUICE CITE	ar acteriotic				
	US Market Release	Aug-04		Serial Numbe	r Prefix	LFG		Laboratory Analysis	
	Estimated US Implants	46,600		Type and/or I	ixation	Transvenous, Left Cardiac Vein, Dista		Implant Damage	55
	Estimated US Active	41,800		Polarity		Bipolar		Electrical Malfunction Other	1 6
	Advisories	None		Steroid		Yes			
Prospec	tive Clinical Study Result	S			Qualifyir	ng Complications	2 Total		
Number of Leads Enrolled in Study Cumulative Months of Follow-Up 3		273	'3		Failure to Capture	1			
		3,296		L	ead Dislodgement	1			



Left-Heart Leads continued

Lead Survival Summary (95% Confidence Interval)

Model Number	Family	US Market Release	Leads Enrolled	ualifying omplications	Cumulative Months of Follow-Up in Study	Years A	Survival I	lant	, I	l -		l -	l a	l.	
Σž	r _e	5 %		οŭ	⊒. ರ್ ರ	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
2187	Attain	Aug-01	132	1	4,943	99.1 +0.8/-5.3	99.1 +0.8/-5.3	99.1 +0.8/-5.3	99.1 +0.8/-5.3 at 39 mo						
2188	Attain	Aug-01	14	1	490	Survival e	stimate no	t available (due to insuf	ficient sam	ıple size				
4193	Attain	May-02	665	26	16,560	96.2 +1.3/-1.9	95.7 +1.4/-2.0	95.4 +1.5/-2.2	95.4 +1.5/-2.2						
4194	Attain	Aug-04	273	2	3,296	100.0	99.1 +0.8/-5.5 at 21 mo								

Source: System Longevity Study Data as of January 31, 2007

Laboratory Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
2187	Attain	Aug-01	17,100	11,200	7	0	16
2188	Attain	Aug-01	2,800	1,600	1	1	0
4193	Attain	May-02	99,000	76,800	58	15	63
4194	Attain	Aug-04	46,600	41,800	55	1	6

Source: Returned Product Analysis Data as of January 31, 2007

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
2187	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
2188	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1BI
4193	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
4194	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)/ Silicone (4719)	MP35N	Platinum Alloy	IS-1 BI

Defibrillation Leads

6721, 6921 Epicardial Patch

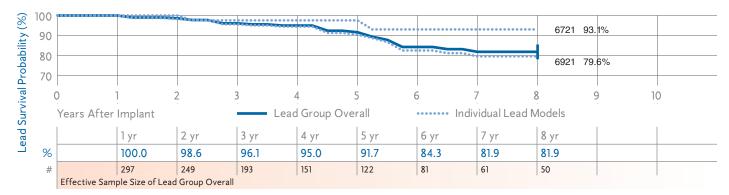
Product Characteristics

US Market Release	Feb-93	Serial Number Prefix	TBH, TBG, TBB, TAD, TAC, or TAB	Laboratory Analysis	
Estimated US Implants	8,900	Type and/or Fixation	Epicardial Defib Patch, Suture		
Estimated US Active	2,100	Polarity	Defib Electrode only	Implant Damage Electrical Malfunction	5 79
Advisories	None	Steroid	No	Other	0

Prospective Clinical Study Results

Qualifying Complications 29 Total

Number of Leads Enrolled in Study	407	Conductor Fracture	21
Cumulative Months of Follow-Up	18,127	Failure to Capture Impedance Out of Range	2
		Insulation (not further defined)	3



6930 Sprint Fidelis

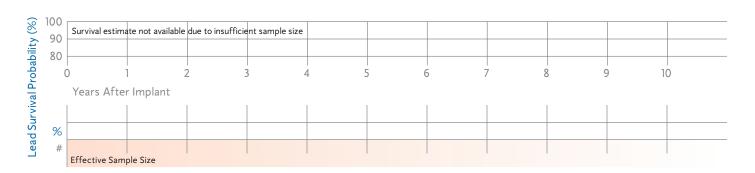
Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFK	Laboratory Analysis
Estimated US Implants	200	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage
Estimated US Active	200	Polarity	True Bipolar/One Coil	Electrical Malfunction Other
Advisories	None	Steroid	Yes	Other

Prospective Clinical Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	0
Cumulative Months of Follow-Up	0



6931 Sprint Fidelis

Product Characteristics

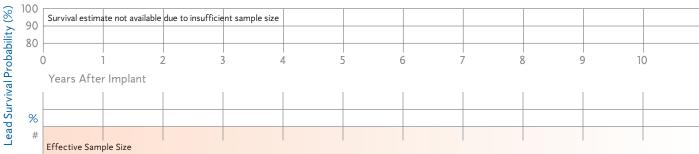
US Market Release	Sep-04	Serial Number Prefix	LFL	Laboratory Analysis	
Estimated US Implants	5,400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Screw-in	Implant Damage	12
Estimated US Active	4,900	Polarity	True Bipolar/One Coil	Electrical Malfunction Other	22
Advisories	None	Steroid	Yes	0	•

Prospective Clinical Study Results

Qualifying Complications 1 Total

Number of Leads Enrolled in Study	152	Lead Dislodgement	1
Cumulative Months of Follow-Up	1,050		

Cumulative Months of Follow-Up



6932 Sprint

Product Characteristics

US Market Release	Aug-96	Serial Number Prefix	TCA	Laboratory Analysis	
Estimated US Implants	15,300	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage	16
Estimated US Active	6,800	Polarity	True Bipolar/One Coil	Electrical Malfunction Other	37 7
Advisories	None	Steroid	Yes	Other	,

Prospective Clinical Study Results

Qualifying Complications 7 Total

Number of Leads Enrolled in Study	411	Extra Cardiac Stimulation	1
Cumulative Months of Follow-Up	19,204	Failure to Capture	2
		Failure to Sense	2
		Oversensing	2



6933, 6937, 6937A, 6963 SVC/CS **Product Characteristics US Market Release** Dec-93 Serial Number Prefix TAT, TBU, or TAF Laboratory Analysis Estimated US Implants 17,300 Type and/or Fixation Transvenous CS or SVC Defib Implant Damage 31 **Estimated US Active** 5,800 Polarity One Defib Coil Electrical Malfunction 192 Advisories None Steroid No Other **Prospective Clinical Study Results Qualifying Complications** 23 Total Number of Leads Enrolled in Study 966 Conductor Fracture Lead Dislodgement Failure to Capture Unspecified Clinical Failure 3 1 Cumulative Months of Follow-Up 46,981 2 Impedance Out of Range Insulation (not further defined) 100 Lead Survival Probability (%) 90 6937 91.9% 80 3 5 6 8 9 10 11 15 16 17 18 19 20 21 12 13 Years After Implant Lead Group Overall ····· Individual Lead Models 1 yr | 2 yr | 3 yr | 4 yr | 5 yr 6 yr | 7 yr | 8 yr | 9 yr | 10 yr | 11 yr | 138 mo 96.4 95.2 94.6 93.9 98.6 97.0 92.8 92.8 92.8 720 596 410 328 248 183 137 98 63 Effective Sample Size

6936, 6966 Transvene

Product Characteristics

	US M	arket R	Release		Dec	:-93		Seri	al Num	ber Pr	efix	TAV	or TA	L					Labo	ratory	Analys	is
	Estim	nated U	IS Impla	ants	24,6	500		Туре	e and/o	or Fixat	ion		nsveno e/Sens			ib and		•			t Damag	
	Estim	nated U	S Activ	/e	6,2	200		Pola	rity			True	e Bipola	ar/One	Coil				Elect	rical M	alfunctio Oth	
	Advis	ories			No	one		Ster	oid			No									Oth	. 12
rospect	tive Cl	inical S	Study I	Result	S					Q	ualifyi	ng Co	mplica	itions	139	Total						
	Num	ber of l	_eads E	nrolled	d in Stu	dy	1,349				(Conduc	ctor Fra	acture	16					Ov	ersensir	ng 89
	Cumi	ulative	Month	s of Fo	llow-Up	5	66,564				Extra		c Stimu		2			Uns	pecifie		cal Failu	
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Lead Survival Probability (%) 00 00 00 00 00 00 00 00 00 00 00 00 00											•											
2n 50									6936	67.1%												
N O		1 2	2 3	2 .	4 5	 = 4	1 1 6 7	8		l 9 10	l l	1 1:) 2 1	l 2 1	4	5	1 16	17	18	19	20	1 21
Lea					+ ~	,	0 /	_		p Ove			د ا. ••••••		4 vidual			17	10	15	20	∠ I
	rears	After												iriai	viuuai	Leau	ivioue	15				
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 135 mo									
%				97.1	96.1	92.9	87.7	80.1	76.0	70.4	66.9	66.0	66.0									
#		1,043		714	585	478	358	250	192	137	90	65	55									
	Effect	ive Sam	ple Size																			

6939, 6999 Sub-Q Patch

Product Characteristics

US Market Release	Dec-93	Serial Number Prefix	TBA or TAP	Laboratory Analysis	
Estimated US Implants	4,300	Type and/or Fixation	Subcutaneous Defib Patch, Suture		
Estimated US Active	1,000	Polarity	Defib Electrode Only	Implant Damage Electrical Malfunction	4 32
Advisories	None	Steroid	No	Other	1

Prospective Clinical Study Results

Qualifying Complications 20 Total

	Number of Leads Enrolled in Study	384	Conductor Fracture	10	
	Cumulative Months of Follow-Up	17,628	Failure to Capture Insulation (not further defined)	2	
			Unspecified Clinical Failure	2	
^					
U			and the same of th		6030 027%



6942 Sprint

US Market Release

Jul-97

Product Characteristics

TCB

Serial Number Prefix

								-aboratory Arialysis	
	Estimated US Imp	lants 18,100		Type and/or Fixation	on Transvenous, Ve Pace/Sense, Tine		_	Implant Damage	
	Estimated US Acti	ive 8,700		Polarity	Polarity Integrated Bipolar/Two			Electrical Malfunction Other	
	Advisories	None		Steroid	Yes			Other	
ospec	tive Clinical Study	Results		Qι	ualifying Complications	7 Total			
	Number of Leads	Enrolled in Study	353		Conductor Fracture	1			
	Cumulative Month	s of Follow-Up	14,509		Failure to Sense				
					Lead Dislodgement				
				11	Oversensing nspecified Clinical Failure				
				O	nispecinica cinnicari anare	•			
100						4			
90									
0.0									
80									
80	0 1	2	3	4 5	6	7 8		9 10	
80	0 1 Years After Imp	_	3	4 5	6	7 8		9 10	
	-	_	3 3		6 5 yr 6 yr	7 8 8		9 10	
80 (%	Years After Imp	lant 2 yr		4 yr				9 10	
% #	Years After Imp	lant 2 yr	3 yr	4 yr 97.2	5 yr 6 yr	7 yr		9 10	

Laboratory Analysis

6943 Sprint

Product Characteristics

US Market Release	Oct-97	Serial Number Prefix	TCE	Laboratory Analysis	
Estimated US Implants	21,300	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Implant Damage	50
Estimated US Active	10,400	Polarity	True Bipolar/One Coil	Electrical Malfunction Other	61 8
Advisories	None	Steroid	Yes	Other	Ŭ

Prospective Clinical Study Results

Qualifying Complications 40 Total

Number of Leads Enrolled in Study	1,300	Conductor Fracture	7	Lead Dislodgement	1
Cumulative Months of Follow-Up	56.795	Failure to Capture	4	Oversensing	19
		Failure to Sense	3	Unspecified Clinical Failure	3
		Impedance Out of Range	2		
		Insulation (not further defined)	1		



6944	Sprint Quattro		Pi	roduct Characteristics	5			
	US Market Release	Dec-00	Se	erial Number Prefix	TDC		Laboratory Analysis	
	Estimated US Implants	28,300	Ty	ype and/or Fixation	Transvenous, Vent Pace/Sense, Tines	•	Implant Damage	23
	Estimated US Active	19,400	Po	olarity	True Bipolar/Two C	Coils	Electrical Malfunction Other	29 8
	Advisories	None	St	teroid	Yes		o their	Ü
Prospec	tive Clinical Study Result	S		Qualifyin	g Complications	3 Total		
	Number of Leads Enrolled	d in Study	170		Oversensing	2		
	Cumulative Months of Fo	llow-Up	5,104	Unspecif	ied Clinical Failure	1		



1 yr

99.6

907

Effective Sample Size

2 yr

99.1

741

3 yr

99.0

622

4 yr

98.3

498

6945 Sprint

Lead Survival Probability (%)

Product Characteristics

	US Market Release	Sep-97		Serial Number	Prefix TDA		Laboratory Analysis	
	Estimated US Implants	44,000		Type and/or Fix	xation Transvenous, Ve Pace/Sense, Scr		Implant Damage	196
	Estimated US Active	22,900		Polarity	Integrated Bipol	lar/Two Coils	Electrical Malfunction Other	85 11
	Advisories	None		Steroid	Yes		Other	
Prospect	tive Clinical Study Result	ts			Qualifying Complications	s 20 Total		
	Number of Leads Enrolled in Study Cumulative Months of Follow-Up		1,153		Conductor Fracture	e 2	Impedance Out of Range	2
			50,639	Ex	Extra Cardiac Stimulation Failure to Capture		Oversensing Unspecified Clinical Failure	9
					Failure to Sense		onspecified Cliffical Fallure	'
<u>@</u> 100								
90 <u>It</u>								
val Probability								
2 /) 1	2	3	4	5 6	7 8	9 10	

5 yr

97.4

395

6 yr

96.9

257

7 yr

96.9

116

8 yr

95.2

47

6947 Sprint Quattro Secure **Product Characteristics US Market Release** Nov-01 Serial Number Prefix TDG Laboratory Analysis Estimated US Implants Type and/or Fixation 126,400 Transvenous, Vent, Defib and Implant Damage 218 Pace/Sense, Screw-in Electrical Malfunction 82 Polarity **Estimated US Active** 92,700 True Bipolar/Two Coils Other 12 Advisories Steroid None **Prospective Clinical Study Results Qualifying Complications** 12 Total Number of Leads Enrolled in Study 1,348 Lead Dislodgement Conductor Fracture 2 3 Oversensing Failure to Sense 2 Cumulative Months of Follow-Up 43,062 Impedance Out of Range Unspecified Clinical Failure Insulation (not further defined) Lead Survival Probability (%) 100 90 80 2 3 5 9 10 Years After Implant 1 yr 2 yr 3 yr 4 yr at 57 mo 98.7 % 99.3 99.3 99.0 98.7 1,064 907 570 249 56

Effective Sample Size

6948 Sprint Fidelis

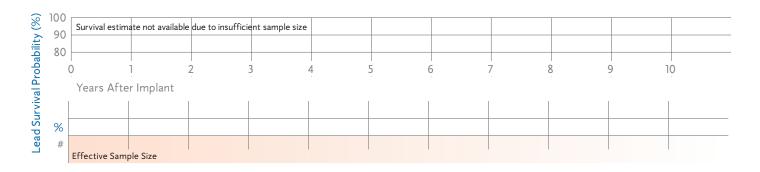
Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFH	Laboratory Analysis	
Estimated US Implants	7,500	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage	5
Estimated US Active	6,900	Polarity	True Bipolar/Two Coils	Electrical Malfunction Other	3
Advisories	None	Steroid	Yes	o inci	_

Prospective Clinical Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	19
Cumulative Months of Follow-Up	169



6949 Sprint Fidelis

Product Characteristics

	US Market Release	Sep-04		Serial Number Prefix	LFJ		Laborato	ory Analysis	
	Estimated US Implants	144,300		Type and/or Fixation	Transvenous, Ven Sense, Screw-in	t, Defib and Pace/	Imp	ant Damage	
	Estimated US Active	129,000		Polarity	True Bipolar/Two	Coils	Electrical	Malfunction Other	21:
	Advisories	None		Steroid	Yes			Other	٠,
pec	tive Clinical Study Resul	ts		Qualify	ving Complications	4 Total			
	Number of Leads Enrolle	d in Study	487		Failure to Capture	1			
	Cumulative Months of Fo	•	6,156		Oversensing	3			
		•	6,156			3			
100 90 80		•	6,156			3			
90 80		ollow-Up		4 5	Oversensing		9	10	
90 80	Cumulative Months of Fo	•	6,156	4 5		7. 8.	9	10	
90 80	Cumulative Months of Fo	ollow-Up		4 5	Oversensing		9	10	
90 80	Cumulative Months of Fo	ollow-Up		4 5	Oversensing		9	10	

Effective Sample Size

6996 Sub-Q Lead

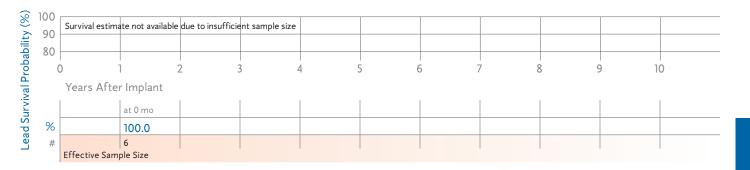
Product Characteristics

US Market Release	Jun-01	Serial Number Prefix	TCR	Laboratory Analysis	
Estimated US Implants	1,900	Type and/or Fixation	Subcutaneous Defib Coil, Suture		
Estimated US Active	1,600	Polarity	One Defib Coil	Implant Damage Electrical Malfunction	0
Advisories	None	Steroid	No	Other	0

Prospective Clinical Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	6
Cumulative Months of Follow-Up	103



Lead Survival Summary (95% Confidence Interval)

				Qualifying Complications	Cumulative Months of Follow-Up in Study	Device S	iurvival Pr	obability	(%)						
Model Number	źį.	US Market Release	Leads Enrolled	llifying 1plica	nulativ ollow- tudy	Years Af	ter Impla	nt							
Mod	Family	US P Rele	Lead	O no	Cun of F	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
6721, 6921	Epicardial Patch	Feb-93	407	29	18,127	100.0	98.6 +0.9/-2.3	96.1 +1.8/-3.3	95.0 +2.1/-3.7	91.7 +3.1/-5.0	84.3 +5.0/-6.9	81.9 +5.6/-7.7	81.9 +5.6/-7.7		
6930	Sprint Fidelis	Sep-04	0	-	0	Survival es	timate not a	vailable due	to insuffic	ient sample	size				
6931	Sprint Fidelis	Sep-04	152	1	1,050	Survival es	timate not a	vailable due	to insuffic	ient sample	size				
6932	Sprint	Aug-96	411	7	19,204	99.4 +0.4/-1.8	98.4 +0.9/-2.3	98.4 +0.9/-2.3	98.4 +0.9/-2.3	97.8 +1.2/-2.9	97.8 +1.2/-2.9	97.8 +1.2/-2.9	96.2 +2.3/-5.5		
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	966	23	46,981	99.6 +0.3/-0.8	99.2 +0.4/-1.0	99.2 +0.4/-1.0	98.6 +0.7/-1.4	97.0 +1.2/-2.0	96.4 +1.4/-2.2	95.2 +1.8/-2.8	94.6 +2.0/-3.0	92.8 +2.8/-4.5	92.8 +2.8/-4.5 at 138 mo
6936, 6966	Transvene	Dec-93	1,349	139	66,564	99.2 +0.4/-0.7	98.5 +0.6/-1.0	97.1 +0.9/-1.3	96.1 +1.1/-1.6	92.9 +1.7/-2.1	87.7 +2.4/-3.0	80.1 +3.4/-3.9	76.0 +3.9/-4.4	66.9 +5.0/-5.7	66.0 +5.2/-5.9 at 135 mo
6939, 6999	Sub-Q Patch	Dec-93	384	20	17,628	99.1 +0.6/-2.0	98.7 +0.8/-2.3	98.2 +1.1/-2.6	98.2 +1.1/-2.6	94.2 +2.6/-4.8	91.2 +3.5/-5.7	87.8 +4.6/-7.1	84.6 +5.7/-8.6		
6942	Sprint	Jul-97	353	7	14,509	98.9 +0.8/-2.2	98.9 +0.8/-2.2	97.8 +1.3/-3.1	97.2 +1.6/-3.6	96.4 +1.9/-4.2	96.4 +1.9/-4.2	96.4 +1.9/-4.2			
6943	Sprint	Oct-97	1,300	40	56,795	98.8 +0.5/-0.8	98.0 +0.7/-1.0	97.0 +0.9/-1.2	96.4 +1.0/-1.4	95.5 +1.3/-1.7	95.3 +1.3/-1.8	95.3 +1.3/-1.8	95.3 +1.3/-1.8 at 93 mo		
6944	Sprint Quattro	Dec-00	170	3	6,104	100.0	100.0	98.9 +0.9/-6.5	97.6 +1.8/-7.1	95.7 +2.9/-8.7 at 54 mo					
6945	Sprint	Sep-97	1,153	20	50,639	99.6 +0.2/-0.7	99.1 +0.4/-0.9	99.0 +0.5/-1.0	98.3 +0.7/-1.3	97.4 +1.0/-1.6	96.9 +1.1/-1.9	96.9 +1.1/-1.9	95.2 +2.5/-5.2		
6947	Sprint Quattro Secure	Nov-01	1,348	12	43,062	99.3 +0.3/-0.7	99.3 +0.3/-0.7	99.0 +0.4/-0.9	98.7 +0.6/-1.2	98.7 +0.6/-1.2 at 57 mo					
6948	Sprint Fidelis	Sep-04	19	0	169	Survival es	timate not a	vailable due	to insuffic	ient sample	size				
6949	Sprint Fidelis	Sep-04	487	4	6,156	98.9 +0.7/-1.8	98.9 +0.7/-1.8								
6996	Sub-Q Lead	Jun-01	6	0	103	Survival es	timate not a	vailable due	to insuffic	ient sample	size				

Laboratory Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
6721, 6921	Epicardial Patch	Feb-93	8,900	2,100	5	79	0
6930	Sprint Fidelis	Sep-04	200	200	0	0	0
6931	Sprint Fidelis	Sep-04	5,400	4,900	12	22	0
6932	Sprint	Aug-96	15,300	6,800	16	37	7
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	17,300	5,800	31	192	13
6936, 6966	Transvene	Dec-93	24,600	6,200	90	456	19
6939, 6999	Sub-Q Patch	Dec-93	4,300	1,000	4	32	1
6942	Sprint	Jul-97	18,100	8,700	31	36	5
6943	Sprint	Oct-97	21,300	10,400	50	61	8
6944	Sprint Quattro	Dec-00	28,300	19,400	23	29	8
6945	Sprint	Sep-97	44,000	22,900	196	85	11
6947	Sprint Quattro Secure	Nov-01	126,400	92,700	218	82	12
6948	Sprint Fidelis	Sep-04	7,500	6,900	5	3	2
6949	Sprint Fidelis	Sep-04	144,300	129,000	350	213	33
6996	Sub-Q Lead	Jun-01	1,900	1,600	0	2	0
0,00	Sub-Q Lead	juii oi	1,500	1,000			

Reference Chart

Model			Pin Conf	figuration	Lead Body	Insulation,	
Number	Family	Туре	Pace/ Sense	High Voltage	Diameter	Lead Body	Fixation, Steroid
6721	Epicardial Patch	Epi Patch	_	DF-1	S, M, L	Silicone, Single Lumen	Suture
6921	Epicardial Patch	Epi Patch	_	6.5 mm	S, M, L	Silicone, Single Lumen	Suture
6930	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6931	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6932	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6933	SVC/CS	Endo SVC/CS Coil	_	DF-1	7 Fr	Silicone, Single Lumen	Passive
6934S	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	12 Fr	Silicone, Coaxial	Passive, Steroid
6936	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	10 Fr	Polyurethane, Coaxial	Active
6937	SVC/CS	Endo SVC Coil	_	DF-1	5.5 Fr	Silicone, Single Lumen	Passive
6937A	SVC/CS	Endo SVC Coil	_	DF-1	7.5 Fr	Silicone with Polyurethane Overlay, Single Lumen	Passive
6939	Sub-Q Patch	SQ Patch	_	DF-1	One Size	Silicone, Single Lumen	Suture
6942	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6943	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6944	Sprint Quattro	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6945	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6947	Sprint Quattro Secure	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6948	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6949	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6963	SVC/CS	Endo SVC/CS Coil	-	6.5 mm	7 Fr	Silicone, Single Lumen	Passive
6966	Transvene	Endo RV True Bipolar Sensing	3.2 mm L.P.	6.5 mm	10 Fr	Polyurethane, Coaxial	Active
6996	Sub-Q Lead	SQ Coil	-	DF-1	7.5 Fr	Silicone, Single Lumen	Passive
6999	Sub-Q Patch	SQ Patch	_	6.5 mm	One Size	Silicone, Single Lumen	Suture

Pacing Leads

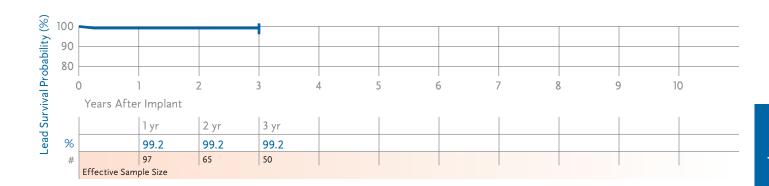
3830 SelectSecure

Product Characteristics

US Market Release	Aug-05	Serial Number Prefix	LFF	Laboratory Analysis
Estimated US Implants	4,800	Type and/or Fixation	Transvenous, V or A, Screw-in	
Estimated US Active	4,400	Polarity	Bipolar	Implant Damage 12 Electrical Malfunction
Advisories	None	Steroid	Yes	Other

Atrial Placement

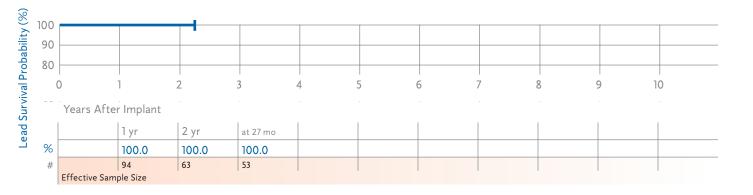
Prospective Clinical Study Results Qualifying Complications 1 Total Number of Leads Enrolled in Study 127 Failure to Sense Cumulative Months of Follow-Up 3,716



Ventricular Placement

Prospective Clinical Study Results Qualifying Complications 0 Total

Number of Leads Enrolled in Study	129
Cumulative Months of Follow-Up	3,597



4003, 4003M CapSure

Product Characteristics

US Market Release	Jul-86	Serial Number Prefix	IH or LAX	Laboratory Analysis
Estimated US Implants	40,000	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	7,500	Polarity	Unipolar	Implant Damage 24 Electrical Malfunction 57
Advisories	None	Steroid	Yes	Other 2

Ventricular Placement

Prospective Clinical Study Results

Qualifying Complications 10 Total

Number of Leads Enrolled in Study	711	Extra Cardiac Stimulation	2
Cumulative Months of Follow-Up	44.116	Failure to Capture	6
	,	Oversensing	2



4004, 4004M CapSure

Product Characteristics

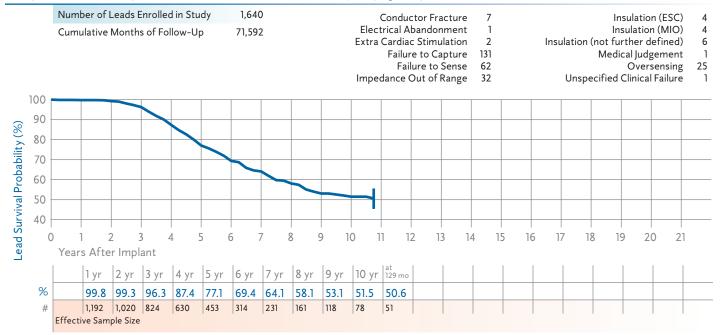
US Market Release	Feb-89	Serial Number Prefix	PS or LAV	Laboratory Analysis
Estimated US Implants	74,500	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	3,100	Polarity	Bipolar	Implant Damage 55 Electrical Malfunction 683
Advisories	1	Steroid	Yes	Other 19
see page 160 – 1993 Lead Survival				

Ventricular Placement

Prospective Clinical Study Results

Below Expectations

Qualifying Complications 276 Total



4011 Target Tip

Product Characteristics

US Market Release	Nov-82	Serial Number Prefix	IB	Laboratory Analysis
Estimated US Implants	64,000	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	7,600	Polarity	Unipolar	Implant Damage 29 Electrical Malfunction 141
Advisories	None	Steroid	No	Other 5

Ventricular Placement

Prospective Clinical Study Results

Qualifying Complications 25 Total

	Numb	oer of L	_eads E	inrolled	l in Stu	dy	85	1					tor Fra		1					0	/ersen	sing	
	Cumi	ılative	Months	s of Fol	low-Uր	0	54,343	54,343 Extra Cardiac Stimulation 4 Failure to Capture 9 Insulation (not further defined) 10															
100																							
90																+							_
80																							
()	1 :	2 :	3	4	5	6	7	8 9	9 1	0 1	1 1	2 1	3 1	4 1	5 1	6 1	7	18	19	20	21	
	Year	s Afte	r Impl	ant																			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	at 183 mo						
%		99.4	99.2	99.1	98.8	97.6	96.4	96.0	96.0	96.0	95.0	93.6	92.8	91.9	91.9	91.9	91.9						
#		626	556	475	414	353	299	250	219	189	165	134	109	81	71	55	50						_

4012 Target Tip

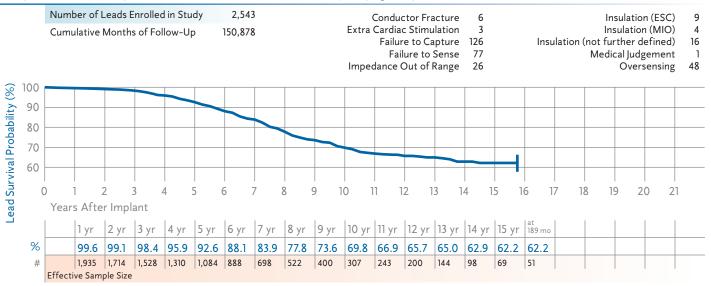
Product Characteristics

US Market Release	Jul-83	Serial Number Prefix	HQ	Laboratory Analysis
Estimated US Implants	96,800	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	6,100	Polarity	Bipolar	Implant Damage 50 Electrical Malfunction 820
Advisories	1	Steroid	No	Other 34
see page 161 – 1991 Lead S Below Expectations	Survival			

Ventricular Placement

Prospective Clinical Study Results

Qualifying Complications 316 Total



4023 CapSure SP

Product Characteristics

US Market Release	Aug-91	Serial Number Prefix	LAK	Laboratory Analysis
Estimated US Implants	43,700	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	15,700	Polarity	Unipolar	Implant Damage 48 Electrical Malfunction 19
Advisories	None	Steroid	Yes	Other 6

Ventricular Placement

Prospective Clinical Study Results Qualifying Complications 19 Total Number of Leads Enrolled in Study 1,157 Lead Dislodgement Extra Cardiac Stimulation 1 2 Failure to Capture 14 Cumulative Months of Follow-Up 58,076 Impedance Out of Range Insulation (not further defined) 100 Lead Survival Probability (%) 90 80 2 6 18 19 10 11 12 13 14 15 16 17 20 21 Years After Implant 1 yr | 2 yr | 3 yr | 4 yr | 5 yr | 6 yr | 7 yr | 8 yr | 9 yr | 10 yr | 126 mo

95.2

96.4 96.4 95.2

65

82

%

99.9 | 99.3 | 98.8 | 98.6 | 98.6 | 98.1

593

454

313

765

Effective Sample Size

96.9

142

213

4024 CapSure SP

Product Characteristics

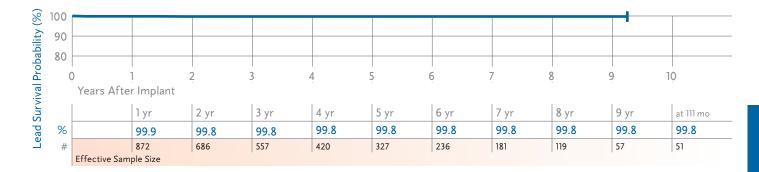
US Market Release	Oct-91	Serial Number Prefix	LAJ	Laboratory Analysis
Estimated US Implants	229,200	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	88,700	Polarity	Bipolar	Implant Damage 264 Electrical Malfunction 100
Advisories	None	Steroid	Yes	Other 34

Ventricular Placement

Prospective Clinical Study Results Qualifying Complications 3 Total

Numl	ber o	f Leads En	rolled in	Study	1,215	Failure to Capture	3

Cumulative Months of Follow-Up 50,950



4033 CapSure Z

Product Characteristics

US Market Release	n/a	Serial Number Prefix	LCA	Laboratory Analysis
Estimated US Implants	n/a	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	n/a	Polarity	Unipolar	Implant Damage 2 Electrical Malfunction 0
Advisories	None	Steroid	Yes	Other 0

Ventricular Placement

Prospective Clinical Study Results Qualifying Complications 9 Total

Number of Leads Enrolled in Study	541	Conductor Fracture	1
Cumulative Months of Follow-Up	27.807	Failure to Capture	8



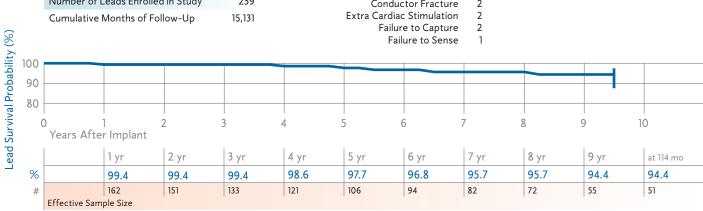
4057, 4057M Screw-In

Product Characteristics

US Market Release	Aug-88	Serial Number Prefix	XQ or LAN	Laboratory Analysis	
Estimated US Implants	12,100	Type and/or Fixation	Transvenous, V or A, Screw-in	Invalent Damas	20
Estimated US Active	2,900	Polarity	Unipolar	Implant Damage Electrical Malfunction	39 6
Advisories	None	Steroid	No	Other	4

Ventricular Placement

Prospective Clinical Study Results Qualifying Complications 7 Total Number of Leads Enrolled in Study 259 Conductor Fracture 2



4058, 4058M Screw-In

Product Characteristics

US Market Release	Jan-89	Serial Number Prefix	ZY or LAW	Laboratory Analysis
Estimated US Implants	111,100	Type and/or Fixation	Transvenous, V or A, Screw-in	
Estimated US Active	27,300	Polarity	Bipolar	Implant Damage 388 Electrical Malfunction 227
Advisories	None	Steroid	No	Other 23

Atrial Placement

Lead Survival Probability (%)

Prospective Clinical Study Results

Oualifying Complications 31 Total

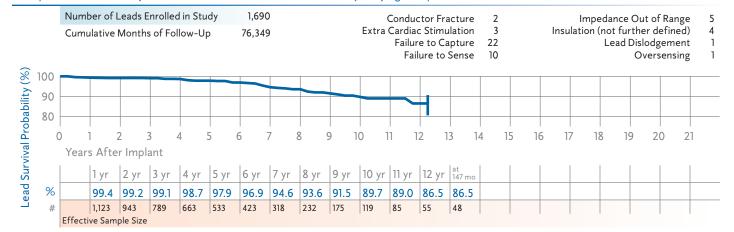
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			_eads E Months			,	2,363 130,73					Failur Fail	c Stimu e to Ca lure to S Out of I	pture Sense	1 15 7 3		Insu	lation		Dislo	defin dgem ersens	ent	1 3 1
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- () .	1 .	2 .	3	4	5	6 .	7 :	8 !	9 1	0 1	' 1 1	2 1	3 1	ı ⊿ 1	5 16	i 5 1:	' 7 1	8	19	20	21	
		s Afte	r Impl		7	,	Ÿ .	′. '			y i		÷ 1.	ا د	7	, ,	9 1	, ı	Ģ	<i>ب</i> ا	20	۲,۱	
5		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	at 171 mo							
%		99.9	99.6	99.5	99.1	98.7	98.3	98.2	97.5	97.5	96.4	96.4	96.4	95.4	95.4	95.4							
í #		1,756	1,547	1,336	1,156	993	791	611	457	338	224	155	117	83	55	50							

Ventricular Placement

Prospective Clinical Study Results

Effective Sample Size

Qualifying Complications 48 Total

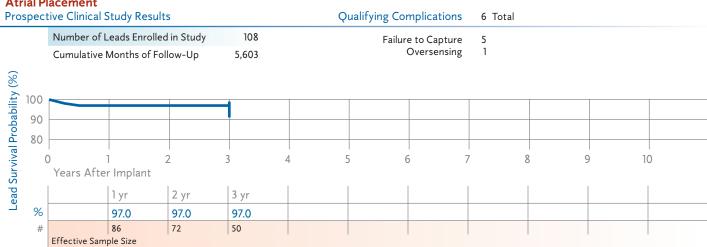


4067 CapSureFix

Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LCV	Laboratory Analysis	
Estimated US Implants	1,300	Type and/or Fixation	Transvenous, V or A, Screw-in		
Estimated US Active	500	Polarity	Unipolar	Implant Damage Electrical Malfunction	3
Advisories	None	Steroid	Yes	Other	i

Atrial Placement



4068 CapSureFix

Product Characteristics

US Market Release	Mar-96	Serial Number Prefix	LCE	Laboratory Analysis
Estimated US Implants	131,700	Type and/or Fixation	Transvenous, V or A, Screw-in	, ,
Estimated US Active	60,500	Polarity	Bipolar	Implant Damage 406 Electrical Malfunction 78
Advisories	None	Steroid	Yes	Other 11

Atrial Placement

Prospective Clinical Study Results

Qualifying Complications 48 Total

bility (%)		Number of Leads Enrolled in Study Cumulative Months of Follow-Up			2,394 109,765		Extra Car Fa	Conductor Fracture Extra Cardiac Stimulation Failure to Capture Failure to Sense Impedance Out of Range		Un	Insulation (ESC) Lead Dislodgement Oversensing Unspecified Clinical Failure		2 8 3 1
Lead Survival Probability	90											1	
urviva	80	0	1 :	2	3	4	5	6	7	8	9	10	
ad S		Years Afte	r Implant										
L			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 117 mo)
	%		99.0	98.8	98.3	98.0	97.5	97.3	97.1	96.2	95.7	95.7	
	#		1,890	1,611	1,326	1,019	721	490	345	226	134	59	
		Effective Sam	ple Size										

Ventricular Placement

Prospective Clinical Study Results

Qualifying Complications 30 Total

		Number of L	eads Enrolled	d in Study	1,799			ctor Fracture	2			
Lead Survival Probability (%)		Cumulative	Months of Fol	low-Up	78,005		Failur Fai Impedance (c Stimulation re to Capture lure to Sense Out of Range Oversensing	2 18 3 3 2			
babi	100											
Pro	90											
vival	80											
Sur	(i 1 :	2	3	4	5	6	7	8	9	10
ead		Years Afte	r Implant									
ĭ			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 111 mo
	%		99.3	98.8	98.8	98.4	97.9	97.5	96.8	96.1	93.4	93.4
	#		1,428	1,219	999	702	498	297	175	93	57	44
		Effective Sam	ple Size									

4073 CapSure Sense

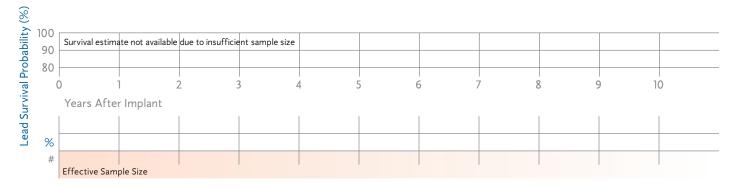
Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBF	Laboratory Analysis
Estimated US Implants	500	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	400	Polarity	Unipolar	Implant Damage 1 Electrical Malfunction 0
Advisories	None	Steroid	Yes	Other 0

Atrial Placement

Prospective Clinical Study Results Qualifying Complications 0 Total

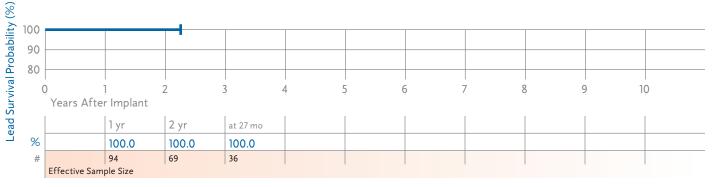
Number of Leads Enrolled in Study Cumulative Months of Follow-Up 28



Ventricular Placement

Prospective Clinical Study Results Qualifying Complications 0 Total

Number of Leads Enrolled in Study 100 Cumulative Months of Follow-Up 2,778



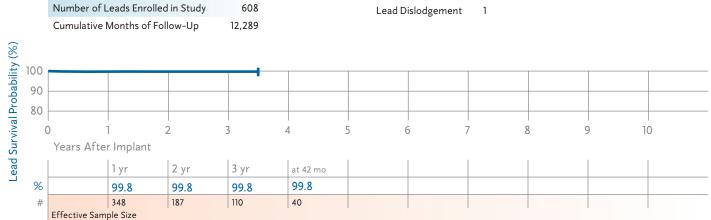
4074 CapSure Sense

Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBD	Laboratory Analysis
Estimated US Implants	43,500	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	35,600	Polarity	Bipolar	Implant Damage 11 Electrical Malfunction 3
Advisories	None	Steroid	Yes	Other 1

Ventricular Placement





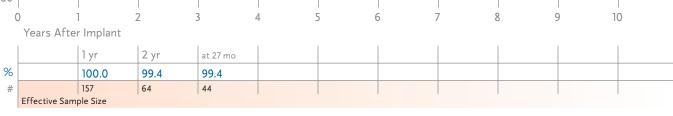
4076 CapSureFix Novus

Product Characteristics

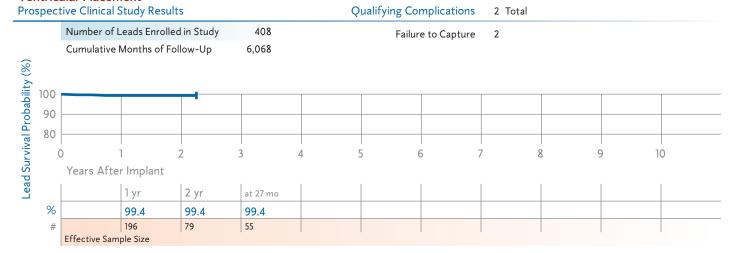
US Market Release	Feb-04	Serial Number Prefix	BBL	Laboratory Analysis	
Estimated US Implants	96,600	Type and/or Fixation	Transvenous, V or A, Screw-in		
Estimated US Active	85,700	Polarity	Bipolar	Implant Damage Electrical Malfunction	47 3
Advisories	None	Steroid	Yes	Other	5

Atrial Placement

rospec	tive Clinical	Study Res	ults			Qualifyir	ng Complicat	ions 1 To	1 Total					
	Number of	Leads Enro	lled in Study	289			Failure to Cap	oture 1]					
	Cumulative	Months of	Follow-Up	4,536										
100														
90			•											
80														
	0	1	2	3	4	5	6	7	8	9	10			
	-	er Implant	_											
90 80		1 yr	2 yr	at 27 mo										
ر الا		100.0	00.4	00.4										



Ventricular Placement



4081 Target Tip

Product Characteristics

US Market Release	Jul-89	Serial Number Prefix	LAC	Laboratory Analysis
Estimated US Implants	4,100	Type and/or Fixation	Transvenous, Vent., Tines	, ,
Estimated US Active	900	Polarity	Unipolar	Implant Damage 4 Electrical Malfunction 5
Advisories	None	Steroid	No	Other 0

Ventricular Placement

Lead Survival Probability (%)

Prospective Clinical Study Results Qualifying Complications 3 Total

	Number of	Leads Enro	olled in Study	260		(Conductor Fractu	re 1				
	Cumulative	Months of	f Follow-Up	9,749			Failure to Sen	se 2				
100												
100												
90						-						
80												
(0	1	2	3	4	5	6	7	8	9	10	
`	Years Afte	er Implant	t -			J	Ü	•				
	ı	1_		L	1.	1_	ı	ı	1	ı	1	

80											
80											
C)]	1 2	2	3 4	1 5	5 6	5 7	8	9) 1(0
	Years After	r Implant									
		1 yr	2 yr	3 yr	4 yr	5 yr	at 63 mo				
%		100.0	100.0	100.0	100.0	100.0	98.2				
#		191	156	116	81	56	48				
	Effective Sami	ole Size						·			•

4092 CapSure SP Novus

Product Characteristics

	Sep-98	Serial Number Prefix	LEP	Laboratory Analysis	
	34,800	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	31
Estimated US Active 8 Advisories	89,800 None	Polarity Steroid	Bipolar Yes	Electrical Malfunction Other	11 5

Ventricular Placement

Prospective Clinical Study Results Qualifying Complications 16 Total Number of Leads Enrolled in Study 1,142 Conductor Fracture 2 Extra Cardiac Stimulation Cumulative Months of Follow-Up 43,905 Failure to Capture 8 Impedance Out of Range Lead Dislodgement 4 Lead Survival Probability (%) 100 90 2 3 4 5 6 8 10 Years After Implant 2 yr 3 yr 5 yr 1 yr 4 yr at 69 mo % 99.0 98.9 98.8 98.4 97.8 97.8 944 837 618 384 182 46 Effective Sample Size

4503, 4503M CapSure

Product Characteristics

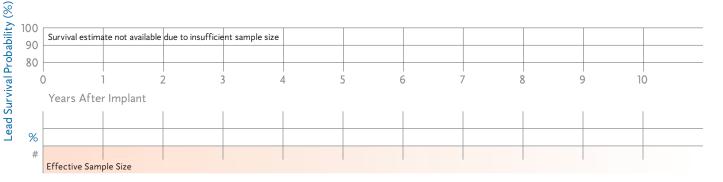
US Market Release	Jul-86	Serial Number Prefix	MQ, LAY	Laboratory Analysis
Estimated US Implants	9,000	Type and/or Fixation	Transvenous, Atrial-J, Tines	
Estimated US Active	1,500	Polarity	Unipolar	Implant Damage 2 Electrical Malfunction 11
Advisories	None	Steroid	Yes	Other 0

Atrial Placement

Prospective Clinical Study Results Qualifying Complications

Number of Leads Enrolled in Study	59	Failure to Sense
C LC M d CE II U	2 217	

Cumulative Months of Follow-Up 3,317



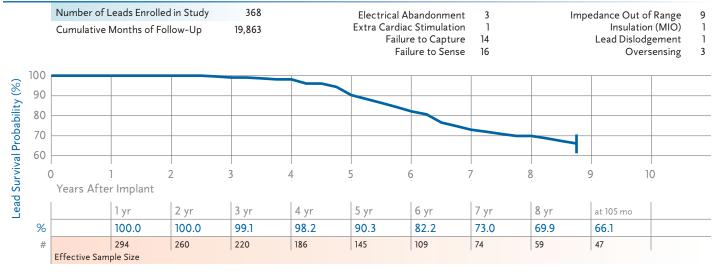
4504, 4504M CapSure

Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	QM or LBA	Laboratory Analysis
Estimated US Implants	16,600	Type and/or Fixation	Transvenous, Atrial-J, Tines	, ,
Estimated US Active	1,700	Polarity	Bipolar	Implant Damage 5 Electrical Malfunction 171
Advisories	1	Steroid	Yes	Other 4
see page 159 – 1996 Lead Below Expectations	Survival			

Atrial Placement

Prospective Clinical Study Results Qualifying Complications 48 Total



4512 Target Tip

Product Characteristics

US Market Release	Jul-83	Serial Number Prefix	PF	Laboratory Analysis
Estimated US Implants	11,600	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage 4
Estimated US Active	1,100	Polarity	Bipolar	Implant Damage 4 Electrical Malfunction 83
Advisories	None	Steroid	No	Other 8

Atrial Placement

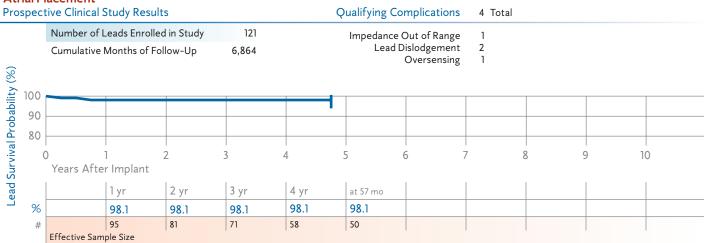
Prospe	ctive	Clir	nical S	itudy l	Result	S					Q	ualifyi	ng Co	mplica	tions	35 T	otal							
						d in Stu low-Up	,	600 39,702					Failur Fail dance (bandor e to Ca lure to Out of I ulation	pture Sense Range	1 6 14 3 2		Inst	ulation		furth ad Dis	ation (Ner defi lodgen verser	ned) nent	4 2 1 2
Lead Survival Probability (%)	o —		2		3	4 !	5 (5 7	7	8 9	9 1	0 1	1 1	2 1	3 1	4 1:	5 10	6 1	7	18	19	20	21	
ad Sur	Y	1		1mpl	ant 3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 vr	11 vr	12 yr	13 vr	at				ı	ı			
9 %	6	-		99.6	99.1	-	96.7	95.6	94.7	91.5	89.7	87.5	-	84.8	-							+		
7	# Eff			410 ole Size	370	326	272	224	190	157	129	105	88	71	53	49								

4523 CapSure SP

Product Characteristics

US Market Release	Aug-91	Serial Number Prefix	ZE	Laboratory Analysis
Estimated US Implants	12,000	Type and/or Fixation	Transvenous, Atrial-J, Tines	
Estimated US Active	3,700	Polarity	Unipolar	Implant Damage 5 Electrical Malfunction 2
Advisories	None	Steroid	Yes	Other 1

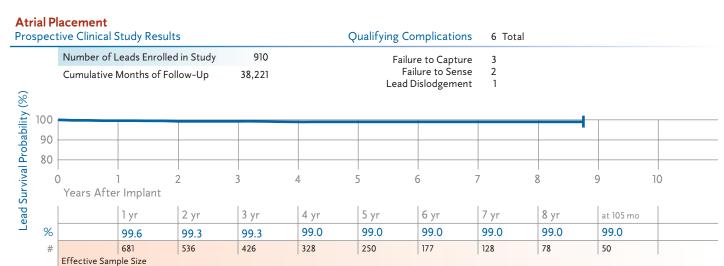
Atrial Placement



4524 CapSure SP

Product Characteristics

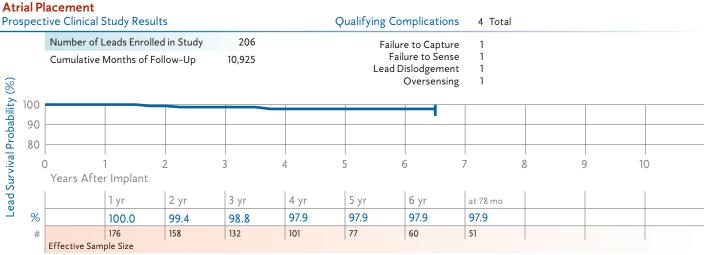
US Market Release	Oct-91	Serial Number Prefix	LAR	Laboratory Analysis	
Estimated US Implants	106,900	Type and/or Fixation	Transvenous, Atrial-J, Tines		
Estimated US Active	40,100	Polarity	Bipolar	Implant Damage Electrical Malfunction	47 21
Advisories	None	Steroid	Yes	Other	8



4533 CapSure Z

Product Characteristics

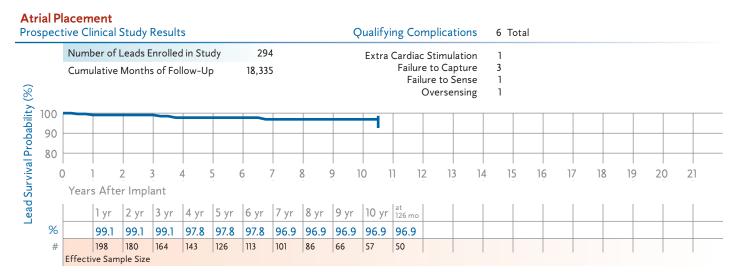
US Market Release	n/a	Serial Number Prefix	LCB	Laboratory Analysis	
Estimated US Implants	n/a	Type and/or Fixation	Transvenous, Atrial-J, Tines		_
Estimated US Active	n/a	Polarity	Unipolar	Implant Damage (Electrical Malfunction (ე ი
Advisories	None	Steroid	Yes	Other C	0



4557, 4557M Screw-In

Product Characteristics

US Market Release	Aug-88	Serial Number Prefix	VQ or LAM	Laboratory Analysis	
Estimated US Implants	22,500	Type and/or Fixation	Transvenous, Atrial, Screw-in		
Estimated US Active	5,500	Polarity	Unipolar	Implant Damage Electrical Malfunction	53 14
Advisories	None	Steroid	No	Other	4



4558M Screw-In

Product Characteristics

US Market Release	Nov-94	Serial Number Prefix	LDC	Laboratory Analysis	
Estimated US Implants	21,000	Type and/or Fixation	Transvenous, Atrial-J, Screw-in		
Estimated US Active	6,500	Polarity	Bipolar	Implant Damage Electrical Malfunction	111
Advisories	None	Steroid	No	Other	1

Atrial Placement

	tive Clinical			500			Complications					
		Leads Enrolle	,	539			al Abandonment			Ov	ersensing	2
	Cumulative	Months of Fo	ollow-Up	21,822			ailure to Capture Failure to Sense					
						Impedan	ce Out of Range	2				
9					In	sulation (not	further defined)) 1				
Lead Survival Probability												
90												
80												
	0	1	2	3	4	5	6	7	8	9	10	
5	Years Afte	er Implant										
5		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 105 mo		
%		99.3	99.3	99.3	99.3	99.3	97.6	96.5	96.5	93.3		
#		353	296	249	191	139	96	83	63	51		

4568 CapSureFix

Product Characteristics

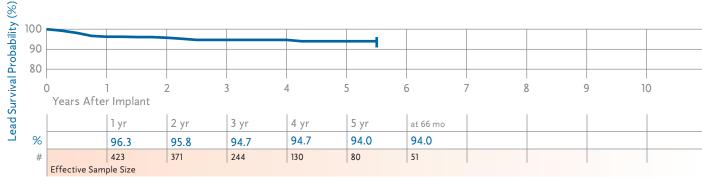
US Market Release	Jan-97	Serial Number Prefix	LDD	Laboratory Analysis
Estimated US Implants	72,800	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	, ,
Estimated US Active	40,200	Polarity	Bipolar	Implant Damage 197 Electrical Malfunction 5
Advisories	None	Steroid	Yes	Other 4

Atrial Placement

Prospective Clinical Study Results

Qualifying Complications 28 Total

Number of Leads Enrolled in Study	573	Failure to Capture	19
Cumulative Months of Follow-Up	19,435	Lead Dislodgement Medical Judgement	8



4574 CapSure Sense

Product Characteristics

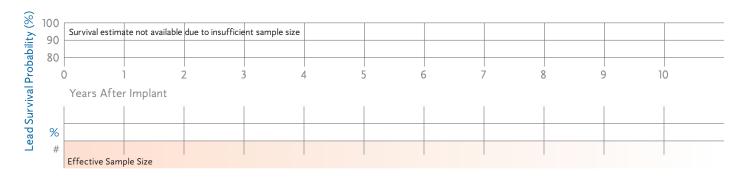
US Market Release	Jun-02	Serial Number Prefix	BBE	Laboratory Analysis
Estimated US Implants	27,900	Type and/or Fixation	Transvenous, Atrial-J, Tines	
Estimated US Active	22,600	Polarity	Bipolar	Implant Damage 5 Electrical Malfunction 1
Advisories	None	Steroid	Yes	Other 0

Atrial Placement

Prospective Clinical Study Results

Qualifying Complications 0 Total

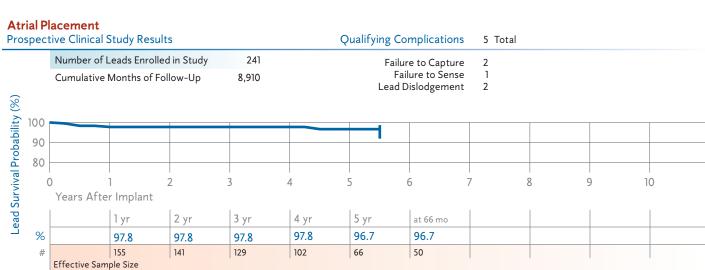
Number of Leads Enrolled in Study Cumulative Months of Follow-Up 107



4592 CapSure SP Novus

Product Characteristics

US Market Release	Oct-98	Serial Number Prefix	LER	Laboratory Analysis
Estimated US Implants	68,700	Type and/or Fixation	Transvenous, Atrial-J, Tines	
Estimated US Active	44,600	Polarity	Bipolar	Implant Damage 12 Electrical Malfunction 3
Advisories	None	Steroid	Yes	Other 0

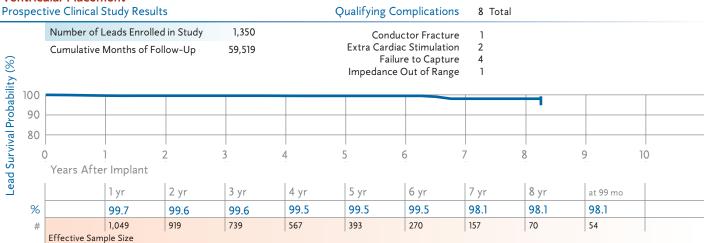


5023, 5023M CapSure SP

Product Characteristics

US Market Release	Nov-88	Serial Number Prefix	SX or LAS	Laboratory Analysis
Estimated US Implants	10,600	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	3,100	Polarity	Unipolar	Implant Damage 15 Electrical Malfunction 7
Advisories	None	Steroid	Yes	Other 0

Ventricular Placement



5024, 5024M CapSure SP

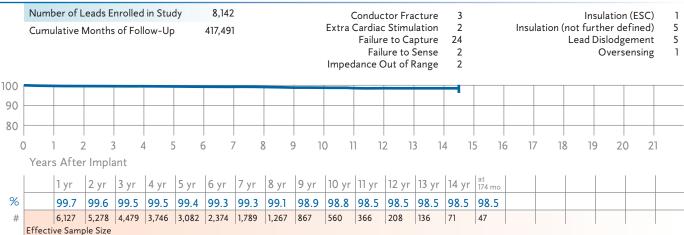
Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	SY or LAT	Laboratory Analysis
Estimated US Implants	211,400	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	76,500	Polarity	Bipolar	Implant Damage 723 Electrical Malfunction 106
Advisories	None	Steroid	Yes	Other 29

Ventricular Placement

Prospective Clinical Study Results

Qualifying Complications 45 Total



5026 CapSure

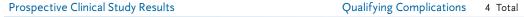
-ead Survival Probability (%)

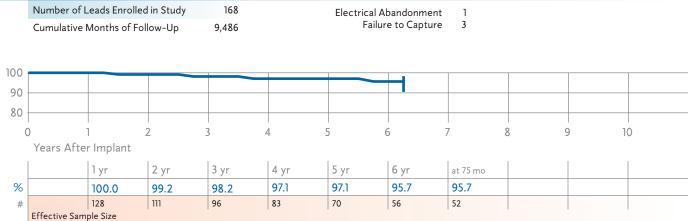
Product Characteristics

US Market Release	Feb-88	Serial Number Prefix	RZ	Laboratory Analysis
Estimated US Implants	7,800	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	1,400	Polarity	Bipolar	Implant Damage 60 Electrical Malfunction 7
Advisories	None	Steroid	Yes	Other

Ventricular Placement

Lead Survival Probability (%)





5033 CapSure Z

Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDK	Laboratory Analysis
Estimated US Implants	2,500	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	1,100	Polarity	Unipolar	Implant Damage 6 Electrical Malfunction 1
Advisories	None	Steroid	Yes	Other 3

Ventricular Placement

Prospective Clinical Study Results

Qualifying Complications 22 Total

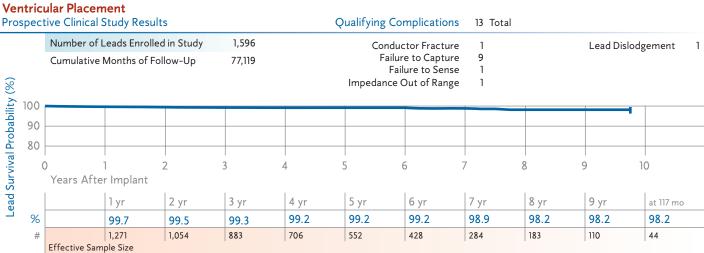
Number of Leads Enrolled in Study 1,901 Cardiac Perforation 1 Cumulative Months of Follow-Up 88,805 Conductor Fracture 4 Failure to Capture 9 Impedance Out of Range 5 Insulation (not further defined) 1 Lead Dislodgement 2				
Failure to Capture 9 Impedance Out of Range 5 Insulation (not further defined) 1	Number of Leads Enrolled in Study	1,901	Cardiac Perforation	1
	Cumulative Months of Follow-Up	88,805	Failure to Capture Impedance Out of Range Insulation (not further defined)	



5034 CapSure Z

Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDF	Laboratory Analysis	
Estimated US Implants	58,700	Type and/or Fixation	Transvenous, Vent., Tines		
Estimated US Active	24,200	Polarity	Bipolar	Implant Damage Electrical Malfunction	85 29
Advisories	None	Steroid	Yes	Other	11



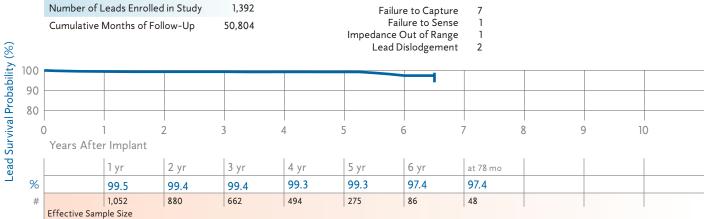
5054 CapSure Z Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEH	Laboratory Analysis
Estimated US Implants	80,400	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	50,300	Polarity	Bipolar	Implant Damage 40 Electrical Malfunction 13
Advisories	None	Steroid	Yes	Other 6

Ventricular Placement

Prospective Clinical Study Results Qualifying Complications 11 Total

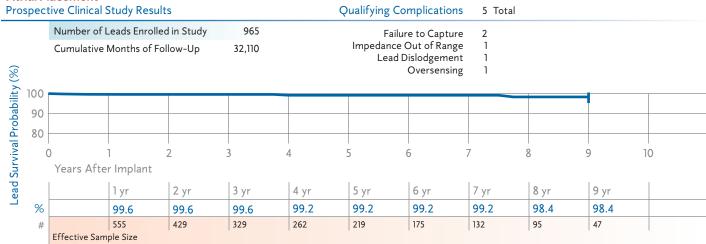


5068 CapSureFix

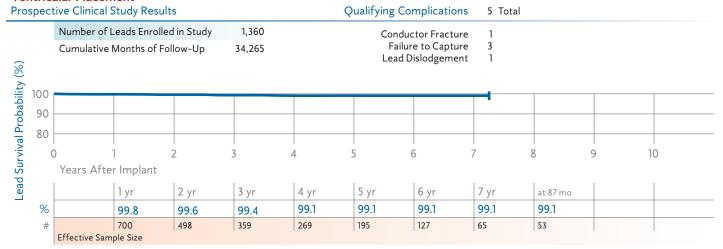
Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDJ	Laboratory Analysis
Estimated US Implants	108,000	Type and/or Fixation	Transvenous, V or A, Screw-in	
Estimated US Active	54,900	Polarity	Bipolar	Implant Damage 455 Electrical Malfunction 59
Advisories	None	Steroid	Yes	Other 15

Atrial Placement



Ventricular Placement



Effective Sample Size

5072 SureFix

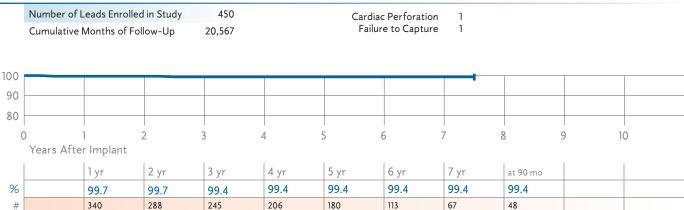
Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEM	Laboratory Analysis
Estimated US Implants	8,800	Type and/or Fixation	Transvenous, V or A, Screw-in	
Estimated US Active	5,200	Polarity	Bipolar	Implant Damage 25 Electrical Malfunction 3
Advisories	None	Steroid	Yes	Other 1

Atrial Placement

Lead Survival Probability (%)

Prospective Clinical Study Results Qualifying Complications 2 Total



5076 CapSureFix Novus

Product Characteristics

US Market Release	Aug-00	Serial Number Prefix	PJN	Laboratory Analysis
Estimated US Implants	766,500	Type and/or Fixation	Transvenous, V or A, Screw-in	, ,
Estimated US Active	584,100	Polarity	Bipolar	Implant Damage 659 Electrical Malfunction 135
Advisories	None	Steroid	Yes	Other 48

Atrial Placement

Prospective Clinical Study Results Qualifying Complications 10 Total Number of Leads Enrolled in Study 1,993 Cardiac Perforation Conductor Fracture 1 Cumulative Months of Follow-Up 55,024 Extra Cardiac Stimulation 2 Failure to Capture 2 Impedance Out of Range Lead Dislodgement 3 Lead Survival Probability (%) 100 90 80 2 5 6 8 9 3 4 10 Years After Implant

5 yr

99.3

148

at 66 mo

99.3

59

Ventricular Placement

%

1 yr

99.6

1,321

Effective Sample Size

2 yr

99.6

985

Prospective Clinical Study Results **Qualifying Complications** 8 Total

3 yr

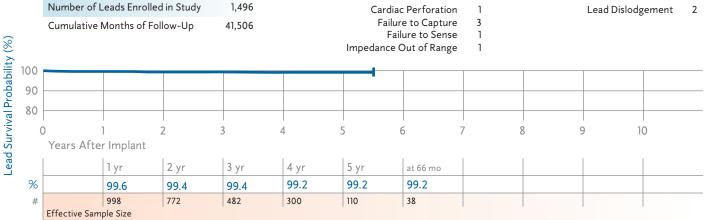
99.5

630

4 yr

99.3

419



5092 CapSure SP Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LET	Laboratory Analysis
Estimated US Implants	101,800	Type and/or Fixation	Transvenous, Vent., Tines	, ,
Estimated US Active	67,700	Polarity	Bipolar	Implant Damage 44 Electrical Malfunction 18
Advisories	None	Steroid	Yes	Other 11

Ventricular Placement

Qualifying Complications Prospective Clinical Study Results 8 Total

		Number of L	eads Enrollec	l in Study	1,171		Extra Cardia	Stimulation	1			
		Cumulative I	Months of Fol	low-Up	35,893			e to Capture islodgement	2 5			
(%)							Lead D	isiougement	3			
	100							_	I		1	
oabi	90							•				
Prof	80											
is s)	1	 	3 4	1 4 !	 5 (1 5 7	 7	8	1 9 1	0
Surv		Years Afte	r Implant									
Lead Survival Probability			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 78 mo			
٣	%		99.6	99.5	99.3	99.0	99.0	99.0	99.0			
	#		777	608	443	300	173	77	49			
		Effective Sam	ple Size									

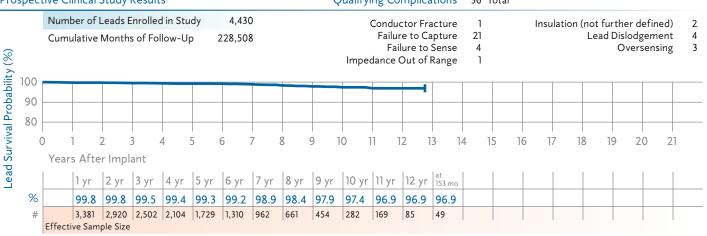
5524, 5524M CapSure SP

Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	XV or LAV	Laboratory Analysis
Estimated US Implants	63,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	
Estimated US Active	24,600	Polarity	Bipolar	Implant Damage 66 Electrical Malfunction 21
Advisories	None	Steroid	Yes	Other 7

Arial Placement

Prospective Clinical Study Results Qualifying Complications 36 Total



5534 CapSure Z

Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDG	Laboratory Analysis
Estimated US Implants	27,700	Type and/or Fixation	Transvenous, Atrial-J, Tines	
Estimated US Active	9,800	Polarity	Bipolar	Implant Damage 29 Electrical Malfunction 6
Advisories	None	Steroid	Yes	Other 5

Atrial Placement Prospective Clinical Study Results Qualifying Complications 6 Total Number of Leads Enrolled in Study 260 Failure to Capture Impedance Out of Range Cumulative Months of Follow-Up 12,176 Lead Survival Probability (%) 100 90 80 2 3 5 6 8 4 9 10 Years After Implant 2 yr 3 yr 4 yr 5 yr 6 yr 1 yr at 78 mo 97.1 97.1 97.1 97.1 97.8 97.8 98.3 203 178 152 102 67 51 48

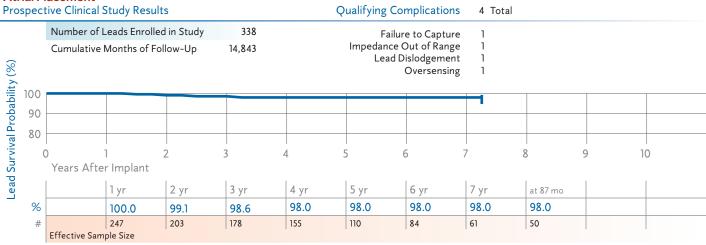
5554 CapSure Z Novus

Effective Sample Size

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEJ	Laboratory Analysis	
Estimated US Implants	51,600	Type and/or Fixation	Transvenous, Atrial-J, Tines		
Estimated US Active	32,500	Polarity	Bipolar	Implant Damage 7 Electrical Malfunction 6	
Advisories	None	Steroid	Yes	Other 4	

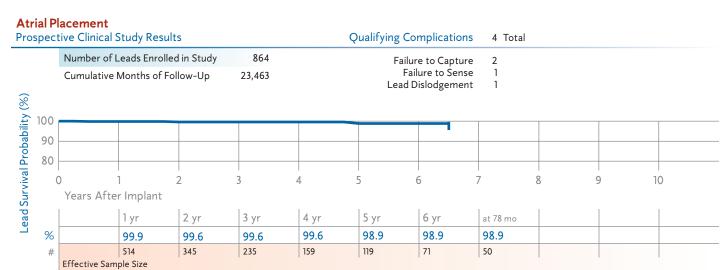
Atrial Placement



5568 CapSureFix

Product Characteristics

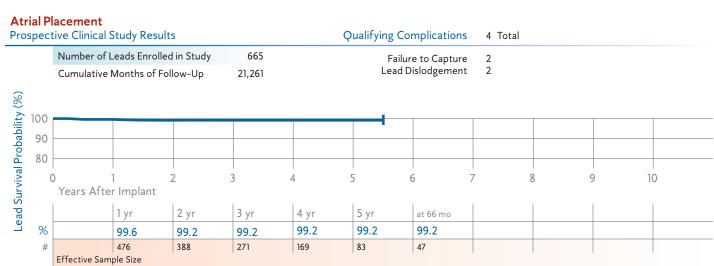
US Market Release	Jan-97	Serial Number Prefix	LDN	Laboratory Analysis
Estimated US Implants	57,700	Type and/or Fixation	Transvenous, A or V, Screw-in	
Estimated US Active	40,200	Polarity	Bipolar	Implant Damage 223 Electrical Malfunction 7
Advisories	None	Steroid	Yes	Other 9



5592 CapSure SP Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEU	Laboratory Analysis
Estimated US Implants	24,200	Type and/or Fixation	Transvenous, Atrial-J, Tines	
Estimated US Active	17,400	Polarity	Bipolar	Implant Damage 5 Electrical Malfunction 2
Advisories	None	Steroid	Yes	Other 0



5594 CapSure SP Novus

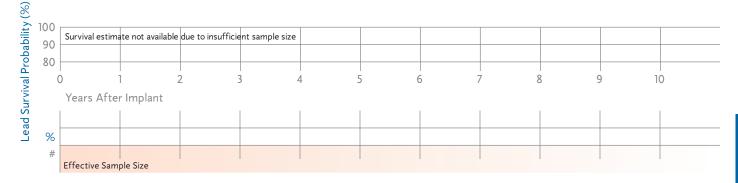
Product Characteristics

US Market Release	Jun-01	Serial Number Prefix	LFD	Laboratory Analysis	
Estimated US Implants	8,500	Type and/or Fixation	Transvenous, Atrial-J, Tines		
Estimated US Active	6,700	Polarity	Bipolar	Implant Damage Electrical Malfunction	0
Advisories	None	Steroid	Yes	Other	0

Atrial Placement

Prospective Clinical Study Results Qualifying Complications 0 Total

Number of Leads Enrolled in Study 10 Cumulative Months of Follow-Up 415

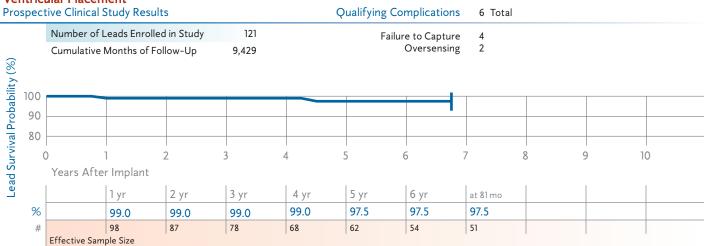


6907R

Product Characteristics

US Market Release	May-79	Serial Number Prefix	FY	Laboratory Analysis	
Estimated US Implants	18,500	Type and/or Fixation	Transvenous, Vent., Flange		
Estimated US Active	900	Polarity	Unipolar	Implant Damage Electrical Malfunction	3 25
Advisories	None	Steroid	No	Other	1

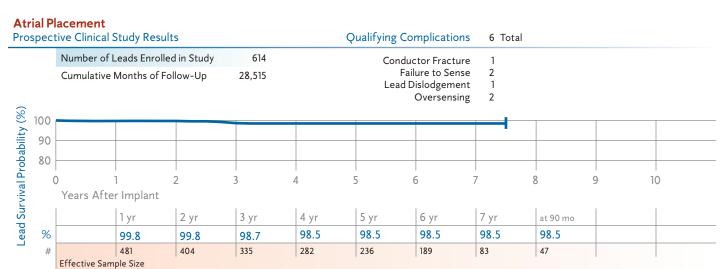
Ventricular Placement



6940 CapSureFix

Product Characteristics

US Market Release	Oct-98	Serial Number Prefix	TCP	Laboratory Analysis
Estimated US Implants	26,600	Type and/or Fixation	Transvenous, A or V, Screw-in	
Estimated US Active	13,600	Polarity	Bipolar	Implant Damage 114 Electrical Malfunction 19
Advisories	None	Steroid	Yes	Other 3



6957 Spectraflex

Product Characteristics

US Market Release	Jul-79	Serial Number Prefix	VC	Laboratory Analysis
Estimated US Implants	29,100	Type and/or Fixation	Transvenous, V or A, Screw-in	Instruct Damage 95
Estimated US Active	3,000	Polarity	Unipolar	Implant Damage 85 Electrical Malfunction 39
Advisories	None	Steroid	No	Other 25

Atrial Placement

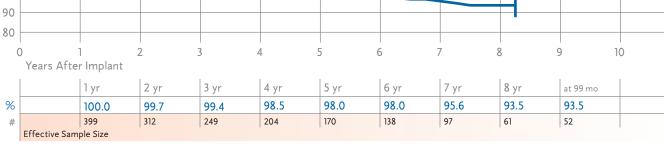
Lead Survival Probability (%)

100

Prospective Clinical Study Results

Qualifying Complications 10 Total

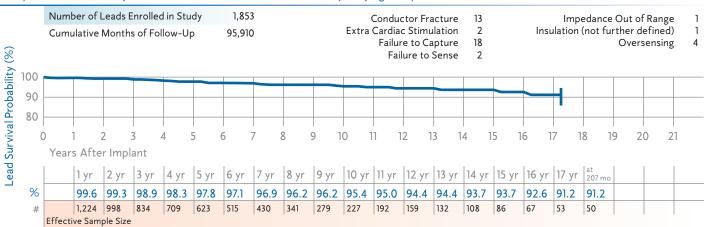
Number of Leads Enrolled in Study	673	Extra Cardiac Stimulation	1
Cumulative Months of Follow-Up	24,255	Failure to Capture Failure to Sense Oversensing	3 5 1



Ventricular Placement

Prospective Clinical Study Results

Qualifying Complications 41 Total



6957] Spectraflex

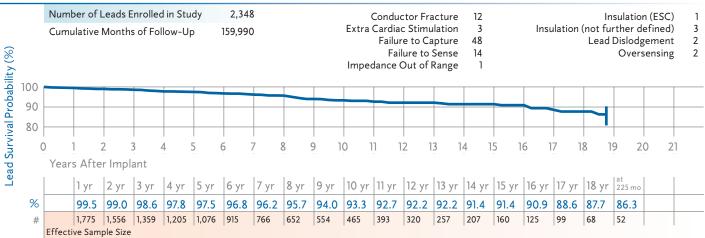
Product Characteristics

US Market Release	Sep-80	Serial Number Prefix	GG	Laboratory Analysis	
Estimated US Implants	30,000	Type and/or Fixation	Transvenous, Atrial-J, Screw-in		
Estimated US Active	2,500	Polarity	Unipolar	Implant Damage 74 Electrical Malfunction 28	
Advisories	None	Steroid	No	Other 30)

Atrial Placement

Prospective Clinical Study Results

Qualifying Complications 86 Total



6961 Tenax

Product Characteristics

US Market Release	Jan-78	Serial Number Prefix	TB	Laboratory Analysis
Estimated US Implants	44,700	Type and/or Fixation	Transvenous, Vent., Tines	
Estimated US Active	1,500	Polarity	Unipolar	Implant Damage 103 Electrical Malfunction 27
Advisories	None	Steroid	No	Other 0

Ventricular Placement

Prospective Clinical Study Results

Qualifying Complications 22 Total

		Numb	ber of L	_eads E	nrolled	l in Stu	dy	627	,			Extra		Stimu		4							
lity (%)		Cumi	ulative	Months	s of Fol	low-Up)	42,879)		Insula		Fail ot furt Lead D	e to Ca ure to S her det islodge Overse	Sense fined) ment	8 6 2 1 1							
oabi	100																						
Prof	90																						
/al	80															•							
Lead Survival Probability (%)	(Year:	l :			4	5 (6	7 8	8 9	9 1	0 1	1 1	2 1	3 1	4 1	5 1	6	17	18	19	20	21
Le			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	at 171 mo						
	%		99.4	99.2	99.2	97.8	97.1	96.4	96.4	95.4	94.9	93.6	93.6	92.9	92.9	90.2	90.2						
	#		466	406	365	322	270	235	209	186	159	140	120	94	76	57	50						
		Effecti	ve Samı	ole Size																			

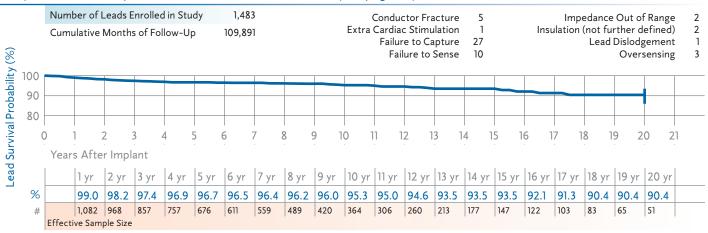
6962 Tenax

Product Characteristics

US Market Release	Jan-78	Serial Number Prefix	UB	Laboratory Analysis
Estimated US Implants	70,600	Type and/or Fixation	Transvenous, Vent., Tines	, ,
Estimated US Active	2,800	Polarity	Bipolar	Implant Damage 170 Electrical Malfunction 84
Advisories	None	Steroid	No	Other 0

Ventricular Placement

Prospective Clinical Study Results Qualifying Complications 51 Total



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C S S S S S S S S S	ylin	,	зшрек	Market ease	pəllo. spe	alifying mplications	shtnoM əvitslum Follow-Wollo Ybust	Device S Years Af	Device Survival Prob Years After Implant	evice Survival Probability (%)	(%)	-	-	-	-	-	-	-	-		
re Attrial Aug-05 177 1 371 99.2 99.2 99.2 99.2 99.2 99.2 99.2 99.2 99.2 99.2 99.3 99.3 98.8 98.8 98.5 97.7 <th< th=""><th>Fan</th><th></th><th>242</th><th>Rel NS</th><th>Fur Enr</th><th>ωQ Coi</th><th>l lo</th><th></th><th></th><th>3 yr</th><th></th><th>5 yr</th><th>6 yr</th><th>7 yr</th><th></th><th>X</th><th></th><th></th><th>16 yr</th><th>18 yr</th><th>20 yr</th></th<>	Fan		242	Rel NS	Fur Enr	ωQ Coi	l lo			3 yr		5 yr	6 yr	7 yr		X			16 yr	18 yr	20 yr
Vert Jul-86 711 10 44,116 99.4 99.4 99.1 99.2 99.3	SelectSe	cure	Atrial	Aug-05	127	_	3,716			99.2 +0.7/-4.8											
Vent Iu-86 71 10 4116 994.1 994.1 991.2<	SelectSe	cure	Vent	Aug-05	129	0	3,597	100.0	100.0	100.0 at 27 mo											
Vent Feb-89 1,540 27/59 99.8 99.3 99.3 99.3 99.3 99.3 99.3 99.3 99.3 99.3 99.3 99.3 99.3 99.3 99.3 99.4 90.4	CapSure		Vent	Jul-86	117	0	44,116		99.4					98.5 +0.8/-1.8	97.7 +1.1/-2.4		97.7 +1.1/-2.4 at 126 mo				
Vent Ind-83 25 4334 994 4 992 0 991 991 2 991 988 8 991 14/4/23 97/412 411/418 414/423 416/24 418/24 418/24 418/24 418/24 950 9 90 90 90 90 90 90 90 90 90 90 90 90	CapSure Advisories	s: see	Vent	Feb-89	1,640 Id Survival	276 Below	71,592		99.3					64.1	58.1 +4.2/-4.5		50.6 +5.0/-5.2 at 129 mo				
Vent Jul-83 2.543 316 150,878 996 991 98.4 95.9 92.6 98.4 92.6 88.1 83.9 77.8 77.8 43.9.43 453.43 Vent Aug-91 1,157 19 58,076 99.3 98.8 98.6 98.1 98.6 98.1 98.6 98.1 98.6 98.1 98.6 98.1 98.6 98.1 98.6 98.1 98.6 98.1 98.6 98.1 98.6 98.1 98.6 98.1 98.6 98.1 98.6 98.6 98.1 98.6 98.1 98.6 98.6 98.1 98.6 98.6 98.1 98.6 98.7 99.4 99.4 99.4 99.6 99.5 99.8 99.8 98.8 98.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 99.8 9	Target	اق ا	Vent	Nov-82	851	25	54,343		99.2 +0.5/-1.0		98.8			96.0	96.0				91.9 +3.1/-4.7 at 183 mo		
Vent Aug-91 1,157 19 58,076 99,3 98,8 98,6 99,8	Target	ے	Vent	Jul-83	2,543	316	150,878	6/-0.3	99.1	98.4 +0.5/-0.7				83.9	77.8				62.2 +4.1/-4.4 at 189 mo		
Vent Aug-91 1,157 19 58,076 99.3 98.8 98.6 98.6 98.1 96.9 96.4 95.2 40.5/-01 40.5/-01 40.5/-01 40.5/-03	Advisorie Expectat	ions	page 161	- 1991 Leac	d Survival E	3elow													200		
Sp Vent Oct-91 1,215 3 50,950 99.8 99.7 90.1/-0.7 40.1/-0.7 </td <th>CapSur</th> <td>e SP</td> <td>Vent</td> <td>Aug-91</td> <td>1,157</td> <td>19</td> <td>58,076</td> <td>9.0-/1</td> <td>99.3 +0.4/-0.9</td> <td>98.8 +0.5/-1.1</td> <td></td> <td></td> <td></td> <td>96.9</td> <td>96.4</td> <td></td> <td>95.2 +2.3/-4.1 at 126 mo</td> <td></td> <td></td> <td></td> <td></td>	CapSur	e SP	Vent	Aug-91	1,157	19	58,076	9.0-/1	99.3 +0.4/-0.9	98.8 +0.5/-1.1				96.9	96.4		95.2 +2.3/-4.1 at 126 mo				
Z Vent Mar-94 541 99.4 99.5 99.4 9	CapSur	e SP	Vent	Oct-91	1,215	3	50,950		99.8 +0.1/-0.7					99.8 +0.1/-0.7		99.8 +0.1/-0.7 at 111 mo					
Vent Auge-8 259 7 15,131 99.4 99.4 99.4 99.4 99.4 99.4 99.4 99.4 99.4 99.4 99.4 99.7 40.5/-3.5 41)/-4.1 416/-4.7 42.0/-5.3 42.5/-5.9 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.8 43.1/-6.9 43.1	CapSur	e Z	Vent	Mar-94	541	6	27,807		99.4 +0.4/-1.4		98.7 +0.8/-1.8			97.7 +1.3/-2.6		95.6 +2.4/-5.3 at 108 mo					
Atrial Jan-89 2,363 31 130,731 99.9 99.6 99.5 99.1 98.7 98.3 98.2 97.5 96.4	Screw-	u i	Vent	Aug-88	259	7	15,131	5/-3.5	99.4	99.4 +0.5/-3.5				95.7 +2.5/-5.9		94.4 +3.1/-6.8 at 114 mo					
Vent Jan-89 1,690 48 76,349 99.4 99.1 99.1 98.7 97.9	Screw-	<u>u</u>	Atrial	Jan-89	2,363	31	130,731		99.6 +0.2/-0.4	10				98.2 +0.6/-1.0	97.5 +0.8/-1.3	96.4			95.4 +2.0/-3.3 at 171mo		
Atrial Mar-96 2,394 48 109,765 97.0 97.0 97.0 97.0 97.0 97.0 98.8 98.3 98.0 97.5 97.3 97.1 96.2 Atrial Mar-96 1,799 30 78,005 99.8 98.8 98.0 97.5 97.3 97.1 96.2 Abrial Mar-96 1,799 30 78,005 99.8 98.8 98.4 97.9 97.5 96.8 96.1 Abrial Mar-96 1,799 30 78,005 99.3 98.8 98.4 97.9 97.5 96.8 96.1	Screw-	u.	Vent	Jan-89	1,690	48	76,349	3/-0.7	99.2 +0.4/-0.7					94.6	93.6 +1.9/-2.6			36.5 -4.2/-6.0 It 147 mo			
Atrial Mar-96 2,394 48 109,765 99.0 98.8 98.3 98.0 97,5 97,3 97,1 96.2 40.8-1.0 40.8-1.0 40.8-1.0 40.8-1.7 40.8-1.0 40.8-1.0 40.8-1.0 40.8-1.1 41.2/-1.7 40.8/-1.7 40.8/-0.8 98.8 98.8 98.8 98.8 98.8 98.8 98.8 9	CapSur	e X X	Atrial	Jan-97	108	9	5,603	97.0	97.0	97.0 +2.0/-5.9											
Vent Mar-96 1,799 30 78,005 99.3 98.8 98.8 98.4 97.9 97.5 96.8 96.1 96.1 1.0.6 1.0.8 1.0.0 1.0.8 1.0.0 1.0.8 1.0.0	CapSur	eFix	Atrial	Mar-96	2,394	48	109,765	99.0	98.8					97.1 +0.8/-1.1		95.7 +1.4/-2.0 at 117 mo					
	CapSur	eFix	Vent	Mar-96	1,799	30	78,005		98.8					96.8		93.4 +3.1/-5.5 at 111 mo					

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tions	olled alifying	Qus Con no Cun Tho	1 0 28 Survival estimate not available due to insufficient sample size	100 0 2,778 100.0 100.0 100.0 at 27 mo	608 1 12,289 99.8 99.8 99.8 99.8 99.8 +0.2/-1.1 +0.2/-1.1 at 42 mo	289 1 4,536 100.0 994 99.8 +0.5/-3.8 +0.5/-3.8 at 27 mo	408 2 6,068 99.4 99.4 99.4 99.4 +0.4/-1.9 +0.4/-1.9 at 27 mo	260 3 9,749 100.0 100.0 100.0 100.0 98.2 +1.5/-10.3 at 63 mo	1,142 16 43,905 99.0 98.9 98.8 98.4 97.8 97.8 97.8 97.8 90.9-1.7 40.9/-1.7 40.9/-1.7 at 69 mo	59 1 3,137 Survival estimate not available due to insufficient sample size	368 48 19,863 100.0 100.0 99.1 98.2 90.3 82.2 73.0 69.9 66.1 457.42 277.42 457.		600 35 39,702 99,6 99,6 99,1 98.0 96,7 96,7 1.8 4.0/-2.0 4.14/-2.4 1.18/-2.8 4.2.0/-3.2 4.2.9/-4.3 4.39/-5.5 44.6/-6.3 4.50/-6.8 4159 mo	121 4 6,864 98.1 98.1 98.1 98.1 98.1 98.1 98.1 98.1	910 6 38,221 996 993 99.3 99.3 99.0 99.0 99.0 99.0 99.0	206 4 10,925 100.0 99.4 98.8 97.9 97.9 97.9 97.9 97.9 97.9 97.9	294 6 18,335 991 991 991 991 978 978 978 96.9 96.9 96.9 96.9 96.9 96.9 96.9 96.	539 11 21,822 99.3 99.3 99.3 99.3 99.3 99.3 99.3 97.6 96.5 96.5 96.5 93.3 97.6 96.5 96.5 94.5 42.1/-5.2 43.7/-8.2 at 105 mo
	tudy ← ea ≻	in S		0.001	99.8	0.001	99.4	100.0	99.0		0.001		99.6	98.1	99.6	0.001	99.1	99.3
ve Months	vitalun	UnD										*						
g	ılifyin	suQ										vival Belo						
	sp	Гез	.02									5 Lead Sur						
1	Narke Sase		rial Jun-02	nt Jun-02	nt Jun-02	Atrial Feb-04	nt Feb-04	nt Jul-89	nt Sep-98	Atrial Jul-86	Atrial Mar-90	159 - 1990	Atrial Jul-83	Atrial Aug-91	Atrial Oct-91	Atrial Mar-94	Atrial Aug-88	Atrial Nov-94
	mber	СРЗ	Atrial	Vent	Vent		× Vent	Vent	P Vent	Atı	Atı	see page					Atı	Atı
	γlir	Fam	CapSure Sense	CapSure Sense	CapSure Sense	CapSureFix Novus	CapSureFix Novus	Target Tip	CapSure SP Novus	CapSure	CapSure	Advisories: se Expectations	Target Tip	CapSure SP	CapSure SP	CapSure Z	Screw-In	Screw-In
	del nber	ooM nuM	4073	4073	4074	4076	4076	4081	4092	4503, 4503M	4504,	4504M	4512	4523	4524	4533	4557, 4557M	4558M

			ţŧ		g suoiti	ve Months -Up	Device S	Device Survival Probability (%)	robability	(%)									
	۱ily	ıəqu	Narke sase	pəjjo sp	ılifyin səildn	nulati ollow tudy	Years At	Years After Implant	ant										
	Fam	Сһа		Lead	suQ no⊃	∃ }o	l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr 18 yr	20 yr
	CapSureFix	Atrial	Jan-97	573	28	19,435	96.3	95.8	94.7	94.7	94.0	94.0 +2.1/-3.1 at 66 mo							
	CapSure Sense	Atrial	Jun-02	4	0	107	Survivale	Survival estimate not available due to insufficient sample size	: available d	ue to insuf	ficient sam	ple size							
1	CapSure SP Novus	Atrial	Oct-98	241	25	8,910	97.8	97.8	97.8	97.8	96.7	96.7 +2.0/-4.8 at 66 mo							
1	CapSure SP	Vent	Nov-88	1,350	∞	59,519	99.7 +0.2/-0.5	99.6	99.6	99.5	99.5	99.5	98.1	98.1	98.1 +1.1/-2.6 at 99 mo				
5024, 5024M	CapSure SP	Vent	Mar-90	8,142	45	417,491	99.7 +0.1/-0.2	99.6	99.5	99.5 +0.1/-0.2	99.4 +0.2/-0.2	99.3 +0.2/-0.2	99.3 +0.2/-0.4	99.1 +0.3/-0.4	98.8 +0.4/-0.7	98.5 +0.6/-0.9	98.5 +0.6/-0.9	98.5 +0.6/-0.9 at 174 mo	
1	CapSure	Vent	Feb-88	168	4	9,486	0.001	99.2	98.2 +1.4/-5.2	97.1 +2.0/-5.9	97.1 +2.0/-5.9	95.7 +2.7/-7.2	95.7 +2.7/-7.2 at 75 mo						
	CapSure Z	Vent	Feb-96	1,901	22	88,805	99.7 +0.2/-0.4	99.6 +0.2/-0.4	99.1 +0.4/-0.7	99.0	98.8 +0.5/-1.0	98.3 +0.7/-1.2	98.1 +0.7/-1.2	97.5 +1.0/-1.6	96.6				
1	CapSure Z	Vent	Feb-96	1,596	13	911,77	99.7 +0.2/-0.4	99.5	99.3	99.2 +0.4/-0.8	99.2 +0.4/-0.8	99.2 +0.4/-0.8	98.9	98.2 +0.9/-1.9	98.2 +0.9/-1.9 at 117 mo				
	CapSure Z Novus	Vent	Jun-98	1,392	Ε	50,804	99.5	99.4	99.4	99.3	99.3	97.4	97.4 +1.5/-3.3 at 78 mo						
i	CapSureFix	Atrial	Jan-97	965	ī	32,110	99.6	99.6	99.6	99.2 +0.5/-1.5	99.2 +0.5/-1.5	99.2 +0.5/-1.5	99.2 +0.5/-1.5	98.4 +1.1/-3.6.	98.4 +1.1/-3.6 at 108 mo				
	CapSureFix	Vent	Jan-97	1,360	2	34,265	99.8 +0.1/-0.6	99.6	99.4 +0.4/-1.1	99.1 +0.5/-1.5	99.1 +0.5/-1.5	99.1 +0.5/-1.5	99.1 +0.5/-1.5	99.1 +0.5/-1.5 at 87 mo					
	SureFix	Atrial	Jun-98	450	2	20,567	99.7 +0.3/-1.5	99.7	99.4 +0.4/-1.9	99.4 +0.4/-1.9	99.4 +0.4/-1.9	99.4 +0.4/-1.9	99.4 +0.4/-1.9	99.4 +0.4/-1.9 at 90 mo					
	CapSureFix Novus	Atrial	Aug-00	1,993	10	55,024	99.6	99.6	99.5	99.3	99.3	99.3 +0.4/-0.9 at 66 mo							
	CapSureFix Novus	Vent	Aug-00	1,496	∞	41,506	99.6	99.4	99.4	99.2	99.2 +0.4/-1.0	99.2 +0.4/-1.0 at 66 mo							
	CapSure SP Novus	Vent	Jun-98	1,171	∞	35,893	99.6	99.5	99.3	99.0	99.0	99.0	99.0 +0.5/-1.3 at 78 mo						
	CapSure SP	Atrial	Mar-90	4,430	36	228,508	99.8 +0.1/-0.2	99.8	99.5 +0.2/-0.3	99.4 +0.2/-0.4	99.3 +0.2/-05	99.2 +0.3/-0.5	98.9 +0.4/-0.6	98.4	97.4 +0.9/-1.5	96.9 +1.2/-2.0	96.9 +1.2/-2.0 at 153 mo		

	l											0		
		20 yr										86.3 +4.0/-5.5 at 225 mo		90.4
		18 yr									91.2 +3.4/-5.4 at 207 mo	87.7 +3.3/-4.5		90.4
		16 yr									92.6 +2.7/-4.2	90.9	90.2 +3.9/-6.4 at 171mo	92.1 +2.4/-3.3
		14 yr									93.7 +2.2/-3.2	91.4 +2.0/-2.4	90.2 +3.9/-6.4	93.5 +1.8/-2.6
		12 yr									94.4 +1.9/-2.7	92.2 +1.7/-2.2	92.9 +2.7/-4.3	94.6 +1.5/-2.0
		10 yr								93.5 +3.1/-5.9 at 99 mo	95.4	93.3 +1.5/-1.8	93.6 +2.5/-3.8	95.3 +1.3/-1.8
		8 yr		98.0 +1.3/-3.2 at 87 mo					98.5 +0.8/-1.9 at 90 mo	93.5 +3.1/-5.9	96.2	95.7 +1.0/-1.3	95.4 +1.9/-3.1	96.2
		7 yr	97.1 +1.6/-3.6 at 78 mo	98.0 +1.3/-3.2	98.9 +0.8/-3.3 at 78 mo			97.5 +1.9/-7.3 at 81mo	98.5 +0.8/-1.9	95.6 +2.3/-4.6	96.9	96.2 +1.0/-1.2	96.4	96.4 +1.0/-1.4
		6 yr	97.1 +1.6/-3.6	98.0 +1.3/-3.2	98.9 +0.8/-3.3	99.2 +0.5/-1.3 at 66 mo	ple size	97.5 +1.9/-7.3	98.5 +0.8/-1.9	98.0 +1.2/-2.9	97.1 +1.0/-1.4	96.8 +0.8/-1.1	96.4	96.5
		5 yr	97.1 +1.6/-3.6	98.0 +1.3/-3.2	98.9	99.2 +0.5/-1.3	due to insufficient sample size	97.5 +1.9/-7.3	98.5 +0.8/-1.9	98.0 +1.2/-2.9	97.8 +0.8/-1.2	97.5 +0.7/-1.0	97.1 +1.3/-2.3	96.7 +0.9/-1.4
(%) ^		4 yr	97.1 +1.6/-3.6	98.0 +1.3/-3.2	99.6 +0.3/-1.3	99.2 +0.5/-1.3	due to insu	99.0	98.5 +0.8/-1.9	98.5 +0.9/-2.5	98.3	97.8 +0.6/-0.8	97.8	96.9 +0.9/-1.2
robabilit	ant	3 yr	97.8	98.6 +0.9/-2.9	99.6	99.2 +0.5/-1.3	t available	99.0	98.7 +0.8/-1.7	99.4 +0.4/-2.0	98.9	98.6 +0.4/-0.7	99.2 +0.5/-1.3	97.4 +0.8/-1.2
ice Survival Probability (%)	rs After Implant	2 yr	97.8	99.1 +0.7/-2.6	99.6	99.2 +0.5/-1.3	Survival estimate not available	99.0	99.8 +0.2/-1.0	99.7 +0.3/-1.6	99.3	99.0	99.2 +0.5/-1.3	98.2 +0.7/-0.9
Device	Years A	l yr	98.3 +1.1/-2.8	0.001	99.9	99.6 +0.3/-1.0	Survivale	99.0	99.8 +0.2/-1.0	0.001	99.6	99.5 +0.2/-0.5	99.4 +0.4/-1.1	99.0
e Months Up	nulativ ollow- tudy	∃ }o	12,176	14,843	23,463	21,261	415	9,429	28,515	24,255	95,910	159,990	42,879	168,801
	gniyìil£ tsoilqn		9	4	4	4	0	9	9	01	14	98	22	15
	pəllo sp	Fur	260	338	864	999	10	121	614	673	1,853	2,348	627	1,483
;	ssse Nsrket		Feb-96	Jun-98	Jan-97	Jun-98	Jun-01	May-79	Oct-98	62-In(62-Inf	Sep-80	Jan-78	Jan-78
	mper	СРЗ	Atrial	Atrial	Atrial	Atrial	Atrial	Vent	Atrial	Atrial	Vent	Atrial	Vent	Vent
	γlir	Fam	CapSure Z	CapSure Z Novus	CapSureFix	CapSure SP Novus	CapSure SP Novus	(no brand name)	CapSureFix	Spectraflex	Spectraflex	Spectraflex	Tenax	Tenax
	del nber	ooM nuN	5534	5554	5568	5592	5594	6907R	6940	6957	6957	6957]	1969	6962

Laboratory Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
3830	SelectSecure	Aug-05	4,800	4,400	12	1	1
4003, 4003M	CapSure	Jul-86	40,000	7,500	24	57	2
4004, 4004M	CapSure	Feb-89	74,500	3,100	55	683	19
4011	Target Tip	Nov-82	64,000	7,600	29	141	5
4012	Target Tip	Jul-83	96,800	6,100	50	820	34
4023	CapSure SP	Aug-91	43,700	15,700	48	19	6
4024	CapSure SP	Oct-91	229,200	88,700	264	100	34
4033	CapSure Z	not US released	_	_	2	0	0
4057, 4057M	Screw-in	Aug-88	12,100	2,900	39	6	4
4058, 4058M	Screw-in	Jan-89	111,100	27,300	388	227	23
4067	CapSureFix	Jan-97	1,300	500	3	1	1
4068	CapSureFix	Mar-96	131,700	60,500	406	78	11
4073	CapSure Sense	Jun-02	500	400	1	0	0
4074	CapSure Sense	Jun-02	43,500	35,600	11	3	1
4076	CapSureFix Novus	Feb-04	96,600	85,700	47	3	5
4081	Target Tip	Jul-89	4,100	900	4	5	0
4092	CapSure SP Novus	Sep-98	134,800	89,800	31	11	5
4503, 4503M	CapSure	Jul-86	9,000	1,500	2	11	0
4504, 4504M	CapSure	Mar-90	16,600	1,700	5	171	4
4512	Target Tip	Jul-83	11,600	1,100	4	83	8
4523	CapSure SP	Aug-91	12,000	3,700	5	2	1
4524	CapSure SP	Oct-91	106,900	40,100	47	21	8
4533	CapSure Z	not US released	_	_	0	0	0
4557, 4557M	Screw-in	Aug-88	22,500	5,500	53	14	4
4558M	Screw-in	Nov-94	21,000	6,500	111	11	1
4568	CapSureFix	Jan-97	72,800	40,200	197	5	4
4574	CapSure Sense	Jun-02	27,900	22,600	5	1	0
4592	CapSure SP Novus	Oct-98	68,700	44,600	12	3	0
5023, 5023M	CapSure SP	Nov-88	10,600	3,100	15	7	0
5024, 5024M	CapSure SP	Mar-90	211,400	76,500	723	106	29
5026	CapSure	Feb-88	7,800	1,400	60	7	1
5033	CapSure Z	Feb-96	2,500	1,100	6	1	3
5034	CapSure Z	Feb-96	58,700	24,200	85	29	11
5054	CapSure Z Novus	Jun-98	80,400	50,300	40	13	6
5068	CapSureFix	Jan-97	108,000	54,900	455	59	15
5072	SureFix	Jun-98	8,800	5,200	25	3	1
5076	CapSureFix Novus	Aug-00	766,500	584,100	659	135	48
5092	CapSure SP Novus	Jun-98	101,800	67,700	44	18	11
5524, 5524M	CapSure SP	Mar-90	63,800	24,600	66	21	7
5534	CapSure Z	Feb-96	27,700	9,800	29	6	5
5554		Jun-98	51,600	32,500	7	6	4
	CapSure Z Novus	<u> </u>					9
5568	CapSureFix	Jan-97	57,700	40,200	223	7	
5592	CapSure SP Novus	Jun-98	24,200	17,400	5	2	0

Laboratory Analysis Summary continued

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
5594	CapSure SP Novus	Jun-01	8,500	6,700	0	1	0
6907R	(no brand name)	May-79	18,500	900	3	25	1
6940	CapSureFix	Oct-98	26,600	13,600	114	19	3
6957	Spectraflex	Jul-79	29,100	3,000	85	39	25
6957J	Spectraflex	Sep-80	30,000	2,500	74	28	30
6961	Tenax	Jan-78	44,700	1,500	103	27	0
6962	Tenax	Jan-78	70,600	2,800	170	84	0

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
3830	SelectSecure	Transvenous V or A Screw-In	Polyurethane/ Silicone (55D,4719)	MP35N 5 Filars/ Cable	1.8 mm Helix/Steroid	IS-1 BI
4003, 4003M	CapSure	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Porous/Steroid	5 mm (4003) IS-1 UNI (4003M)
4004, 4004M	CapSure	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 6/4 Filars	Porous/Steroid	3.2 mm Low Profile (400 IS-1 BI (4004M)
4011	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Target Tip Concentric Grooves	5 mm
4012	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 6/4 Filars	Target Tip Concentric Grooves	3.2 mm Low Profile
4023	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4 Filars	Porous Platinized/ Steroid	IS-1 UNI
4024	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4033	CapSure Z	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4057, 4057M	Screw-In	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 1 Filar	2.0 mm Helix	5 mm (4057) IS-1 UNI (4057M)
4058, 4058M	Screw-In	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/1 Filars	2.0 mm Helix	3.2 mm Low Profile (405 IS-1 BI (4058M)
4067	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 3 Filars	1.8 mm Helix/Steroid	IS-1 UNI
4068	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4073	CapSure Sense	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 5 Filars	TiN Coated Platinum Iridium/Steroid	IS-1 UNI
4074	CapSure Sense	Transvenous Ventricular Tines	Polyurethane/ Silicone (55D, 4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium/ Steroid	IS-1 BI
4076	CapSureFix Novus	Transvenous V or A Screw-In	Polyurethane/ Silicone (55D, 4719)	MP35N 4/6 Filars	TiN Coated Platinum Alloy/Steroid	IS-1 BI
4081	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Target Tip Concentric Grooves	IS-1 UNI w/Removable 5 mm Sleeve
4092	CapSure SP Novus	Transvenous Ventricular Tines	Polyurethane/ Silicone (55D/4719)	MP35N 6/4 Filars	Porous Platinized/ Steroid	IS-1 BI
4503, 4503M	CapSure	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 4 Filars	Porous/Steroid	5 mm (4503) IS-1 UNI (4503M)
4504, 4504M	CapSure	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 3/4 Filars	Porous/Steroid	3.2 mm Low Profile (450 IS-1 BI (4504M)
4512	Target Tip	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 2/4 Filars	Target Tip Concentric Grooves	3.2 mm Low Profile
4523	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	Porous Platinized/ Steroid	IS-1 UNI
4524	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4533	CapSure Z	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4557, 4557M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A)	MP35N 1 Filar	1.5 mm Helix	5 mm (4557) IS-1 UNI (4557M)
4558M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1BI
4568	CapSureFix	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
	CapSure Sense	Transvenous	Polyurethane/ Silicone (55D,4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium	IS-1 BI
4574		Atrial -J Tines				
4574 4592	CapSure SP Novus	Transvenous Atrial-J Tines	Polyurethane/ Silicone (55D/4719)	MP35N 6/3 Filars	Porous Platinized/ Steroid	IS-1 BI

continued

Reference Chart continued

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5024, 5024M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5024) IS-1 BI (5024M)
5026	CapSure	Transvenous Ventricular Tines	Silicone	MP35N 6/4 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile
5033	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
5034	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1BI
5054	CapSure Z Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	CapSure Z Porous/Platinized/ Steroid	IS-1 BI
5068	CapSureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1BI
5072	SureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/5 Filars	1.8 mm Helix/Steroid	IS-1 BI
5076	CapSureFix Novus	Transvenous V or A Screw-In	Silicone (4719)	MP35N 4/6 Filars	Porous Platinized/ Steroid	IS-1 BI
5092	CapSure SP Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5524, 5524M	CapSure SP	Transvenous Atrial-J Tines	Silicone	MP35N 6/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5524) IS-1 BI (5524M)
5534	CapSure Z	Transvenous Atrial Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5554	CapSure Z Novus	Transvenous Atrial-J Screw-In	Silicone (4719)	MP35N 6/5 Filars	CapSure Z Porous Platinized/ Steroid	IS-1 BI
5568	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5592	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5594	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Platinized Platinum/ Steroid	IS-1 BI
6907R	(no brand name)	Transvenous Ventricular Flange	Silicone	MP35N 2 Filars	Ring Tip	5 mm
6940	CapSureFix	Transvenous A or V Screw-in	Silicone	MP35N 3/6 Filars	Platinum Alloy	IS-1 BI
6957	Spectraflex	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 1 Filar	2.0 mm Helix	5 mm
6957J	Spectraflex	Transvenous Atrial-J Screw-In	Polyurethane (80A)	MP35N 1 Filar	1.5 mm Helix	5 mm
6961	Tenax	Transvenous Ventricular Tines	Silicone	MP35N 3 Filars	Ring Tip	5 mm
6962	Tenax	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Ring Tip	5 mm Bifurcated

Epi/Myocardial Pacing Leads

4951, 4951M Spectraflex

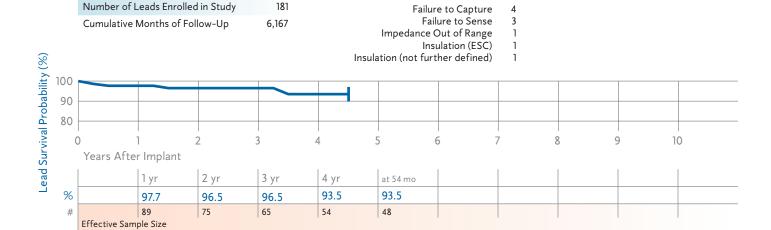
Prospective Clinical Study Results

Product Characteristics

US Market Release	Oct-81	Serial Number Prefix	TF or LBJ	Laboratory Analysis	
Estimated US Implants	25,200	Type and/or Fixation	Myocardial Stab-in, V or A, Peds		
Estimated US Active	3,900	Polarity	Unipolar	Implant Damage Electrical Malfunction	15 95
Advisories	None	Steroid	No	Other	28

Qualifying Complications

10 Total



4965 CapSure Epi

Product Characteristics

		US Market Release	Sep-96		Serial Numbe	r Prefix	LBT			Labora	tory Analysis	
		Estimated US Implan	ts 17,800		Type and/or F	ixation	Epicardial Suture	-On V or A		-		
		Estimated US Active	10,400		Polarity		Unipolar				plant Damage al Malfunction	8 75
		Advisories	None		Steroid		Yes				Other	2
Pros	spec	tive Clinical Study Ro	esults			Qualif	ying Complications	7 Total				
		Number of Leads En	rolled in Study	162			Conductor Fracture	2				
		Cumulative Months	of Follow-Up	3,914			Failure to Capture Failure to Sense					
9							Oversensing					
€ (%	100	_					· ·					
Lead Survival Probability (%)	90											
rob												
<u>Б</u>	80											
<u>\</u>	() 1	2	3	4	5	6	7	8	9	10	
Sur		Years After Implar	1t									
ead		1 yr	2 yr	3 yr								
ĭ	%	98.5	97.1	97.1								
	#	81	68	51								

Effective Sample Size

Epi/Myocardial Pacing Leads continued

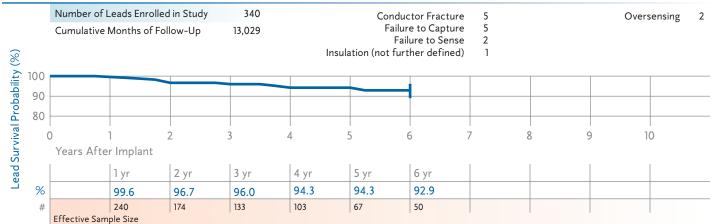
4968 CapSure Epi

Product Characteristics

US Market Release	Sep-99	Serial Number Prefix	LEN	Laboratory Analysis
Estimated US Implants	12,400	Type and/or Fixation	Epicardial Suture-On V or A	
Estimated US Active	9,100	Polarity	Bipolar	Implant Damage 2 Electrical Malfunction 3
Advisories	None	Steroid	Yes	Other 0

Prospective Clinical Study Results

Qualifying Complications 15 Total



5071

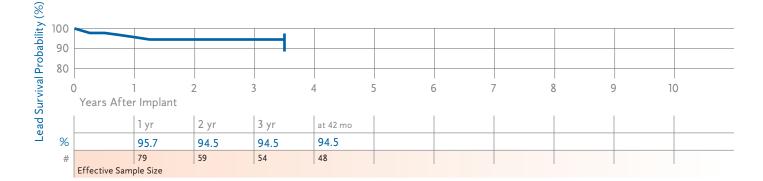
Product Characteristics

US Market Release	Dec-92	Serial Number Prefix	LAQ	Laboratory Analysis	
Estimated US Implants	31,700	Type and/or Fixation	Myocardial Screw-in Vent.		
Estimated US Active	20,100	Polarity	Unipolar	Implant Damage 2 Electrical Malfunction	4
Advisories	None	Steroid	No	Other	i

Prospective Clinical Study Results

Qualifying Complications 7 Total

Number of Leads Enrolled in Study	165	Failure to Capture	7
Cumulative Months of Follow-Up	4,877		

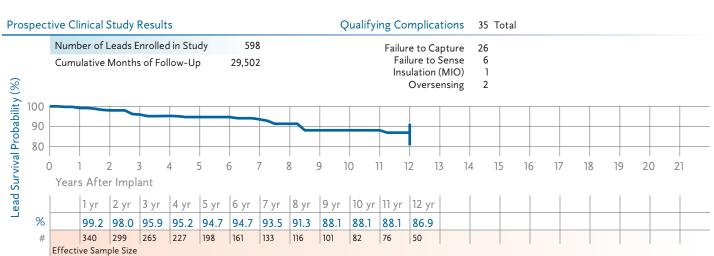


Epi/Myocardial Pacing Leads continued

6917, 6917A Tenax

Product Characteristics

US Market Release	Jun-73	Serial Number Prefix	WV or WC	Laboratory Analysis
Estimated US Implants	180,100	Type and/or Fixation	Myocardial Screw-in Vent.	
Estimated US Active	6,100	Polarity	Unipolar	Implant Damage 115 Electrical Malfunction 42
Advisories	None	Steroid	No	Other 1



Lead Survival Summary (95% Confidence Interval)

		1		_		Device S	urvivalP	Device Survival Probability (%)	(%)								
del nber	γlir	Marke ease	pəllo sp	alifying soilqn	ritatinn wollow- tudy	Years Af	Years After Implant	ant									
oM nuM	Fan		Lea		∃ }o	l yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr 12 yr	12 yr	14 yr	16 yr
4951, 4951M	Spectraflex	Oct-81	181	01	6,167	97.7	96.5 +2.2/-5.7	96.5 +2.2/-5.7	93.5 +3.6/-8.1	93.5 +3.6/-8.1 at 54 mo							
4965	CapSure Epi	Sep-96	162	7	3,914	98.5 +1.1/-4.3	97.1 +2.0/-6.3	97.1 +2.0/-6.3									
4968	CapSure Epi Sep-99	Sep-99	340	15	13,029	99.6	96.7	96.0	94.3 +2.7/-4.9	94.3	92.9 +3.3/-6.1						
5071	(no brand name)	Dec-92	165	7	4,877	95.7 +2.5/-5.9	94.5 +3.0/-6.7	94.5	94.5 +3.0/-6.7 at 42 mo								
6917, 6917A	Tenax	Jun-73	298	35	29,502	99.2	98.0	95.9	95.2	94.7	94.7	93.5 +2.4/-3.9	91.3	88.1	86.9		

Epi/Myocardial Pacing Leads continued

Laboratory Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
4951, 4951M	Spectraflex	Oct-81	25,200	3,900	15	95	28
4965	CapSure Epi	Sep-96	17,800	10,400	8	75	2
4968	CapSure Epi	Sep-99	12,400	9,100	2	3	0
5071	(no brand name)	Dec-92	31,700	20,100	24	4	1
6917, 6917A	Tenax	Jun-73	180,100	6,100	115	42	1

Source: Returned Product Analysis Data as of January 31, 2007

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
4951, 4951M	Spectraflex	Myocardial Stab-In V or A/Peds	Polyurethane (80A)	MP35N 4 Filars	Barb	5 mm (4951) IS-1 UNI (4951M)
4965	CapSure Epi	Epicardial Suture-On V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 UNI
4968	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 B1
5069	(no brand name)	Myocardial Screw-In	Silicone	MP35N Multifilars	3-Turn Helix	IS-1 UNI
5071	(no brand name)	Myocardial Screw-In Ventricular	Silicone	MP35N Multifilars	2-Turn Helix	IS-1 UNI
6917	Tenax	Myocardial Screw-In Ventricular	Silicone	Pt Ir Tinsel Wire	3-Turn Helix	5 mm
6917A	Tenax	Myocardial Screw-In Ventricular	Silicone	Pt Ir Tinsel Wire	2-Turn Helix	5 mm

VDD Single Pass Pacing Leads

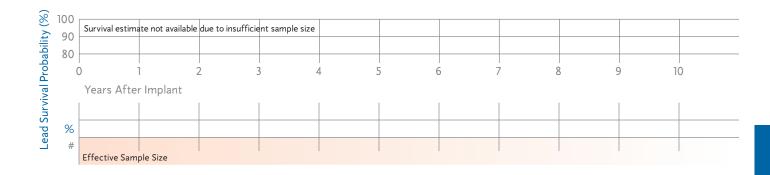
5032 CapSure VDD

Product Characteristics

US Market Release	Mar-96	Serial Number Prefix	LCL, LCN, LCM	Laboratory Analysis	
Estimated US Implants	5,400	Type and/or Fixation	Transvenous, Atr-Vent., Tines		
Estimated US Active	2,200	Polarity	Quadripolar	Implant Damage Electrical Malfunction	12
Advisories	None	Steroid	Yes	Other	0

Prospective Clinical Study Results

Qualifying Complications 1 Total



5038 CapSure VDD-2

Product Characteristics

	US Market Release	Sep-98		Serial Number Prefi	LEE, LEG, or LEF		Laboratory Analysis	
	Estimated US Implants	7,400		Type and/or Fixation	Transvenous, Atr-	-Vent.,Tines		
	Estimated US Active	4,500		Polarity	Quadripolar		Implant Damage Electrical Malfunction	
	Advisories	None		Steroid	Yes		Other	
pect	tive Clinical Study Result	ts		Qua	lifying Complications	4 Total		
	Number of Leads Enrolle	d in Study	545		Conductor Fracture	1		
	Cumulative Months of Fo	llow-Up	18,609		Failure to Capture	1		
	Cumulative Months of Fo	llow-Up	18,609		Failure to Capture Failure to Sense	1 2		
100	Cumulative Months of Fo	llow-Up	18,609			1 2		
100	Cumulative Months of Fo	llow-Up	18,609			1 2		
100 90	Cumulative Months of Fo	illow-Up	18,609			1 2		
	Cumulative Months of Fo	illow-Up	18,609			1 2		
90 80	Cumulative Months of Fo	illow-Up	18,609	4 5	Failure to Sense	7 8	9 10	
90 80				4 5	Failure to Sense		9 10	
90 80	0 1				Failure to Sense		9 10	
90 80	0 1 Years After Implant	2	3	4 yr 5	Failure to Sense		9 10	

VDD Single Pass Pacing Leads continued

Lead Survival Summary (95% Confidence Interval)

Device Survival Probal					Probabilit	y (%)									
Model Number	Family	US Market Release	Leads Enrolled	Qualifying Complicati	Cumulative of Follow-L in Study	Years A	fter Impl 2 yr	ant 3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
5032	CapSure VDD	Mar-96	38	1	1,819	Survival e	stimate not	available d	ue to insuf	ficient sam	ple size				
5038	CapSure VDD-2	Sep-98	545	4	18,609	99.8 +0.2/-1.4	99.8 +0.2/-1.4	99.8 +0.2/-1.4	98.7 +0.9/-3.1	97.9 +1.4/-3.8	97.9 +1.4/-3.8				

Source: System Longevity Study Data as of January 31, 2007

Laboratory Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
5032	CapSure VDD	Mar-96	5,400	2,200	24	12	0
5038	CapSure VDD-2	Sep-98	7,400	4,500	6	2	1

Source: Returned Product Analysis Data as of January 31, 2007

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5032	CapSure VDD	Transvenous V and A Tines	Silicone	MP35N 5/6/1 Filars	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI
5038	CapSure VDD-2	Transvenous Ventricular Tines	Silicone	MP35N	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI

ICD and CRT-D Charge Time Performance

Medtronic continues its commitment to providing updated information on charge time performance.

Introduction

Information on charge time performance of Medtronic is presented in this section of the CRDM Product Performance Report. Medtronic implemented the collection of charge time data on July 1, 1999. The data are collected via our ongoing active clinical study of long-term system performance called the System Longevity Study. The study protocol requests device data be routinely taken and sent to Medtronic at no more than six-month intervals.

In our analysis performed for this report, only charge times resulting from full energy charges are considered. To ensure consistent reporting across devices, the charge time reported at implant represents the last charge time available from date of implant. When more than one charge time is available in a six-month interval, a conservative approach has been adopted whereby only the maximum charge in each 6-month interval is reported. As charge time is directly proportional to the time elapsed since the last capacitor reformation, charges occurring within 15 days of a previous charge are excluded. This precludes the reporting of overly optimistic results.

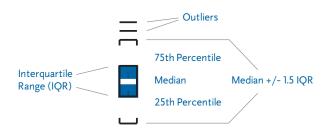
Data from over 20,000 devices contribute to the charge time data in this report. By tracking and reporting this charge time data, Medtronic is able to ascertain the actual performance of its charging circuitry. The insight gained through this information is applied to Medtronic's ongoing efforts to provide charge times that are short and consistent over the life of the product.

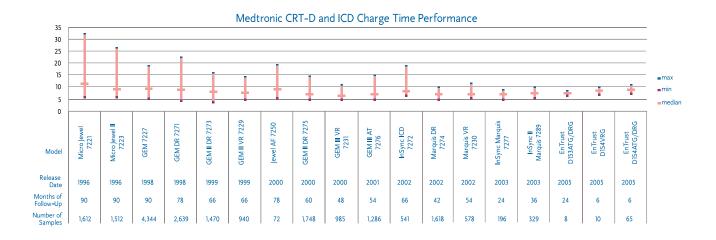
Data Presentation

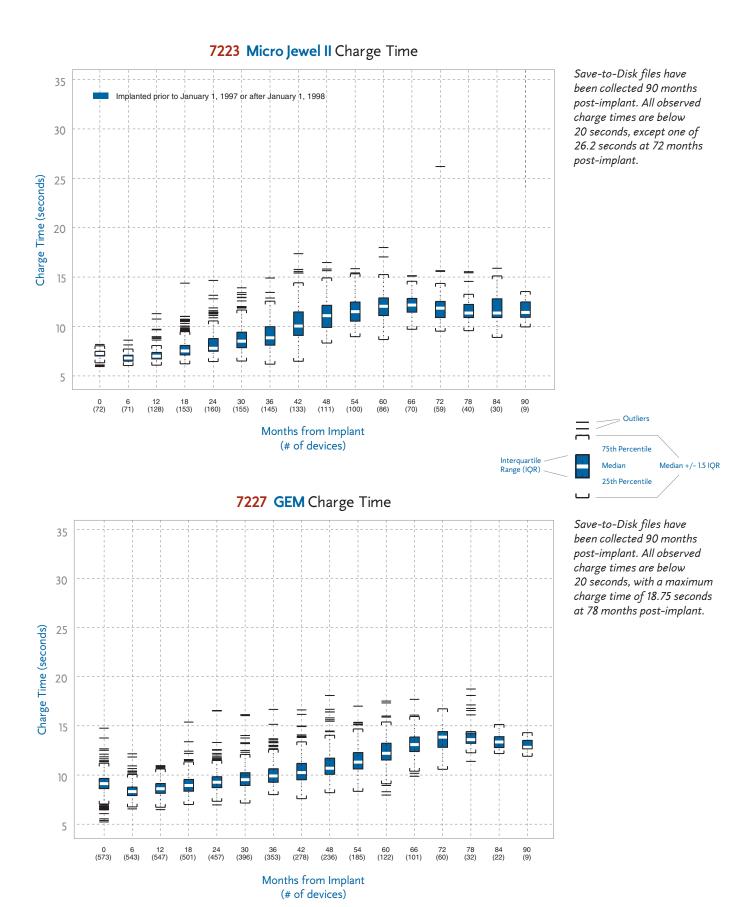
Charge time data for ICD and CRT-D models are presented using boxplots at 6-month intervals. The shaded box on the plots represents the middle half of the data – the Interquartile Range (IQR). The white line in the middle of each box is the median charge time. The top of the box representing the IQR is the 75th percentile (i.e., 75% of all charge times fall below this line), whereas the bottom of the box represents the 25th percentile. The brackets around the box represent the variance in charge times (analogous to a confidence interval), and are calculated as a function of the median and IQR. Individual values falling outside the brackets are labeled as outliers.

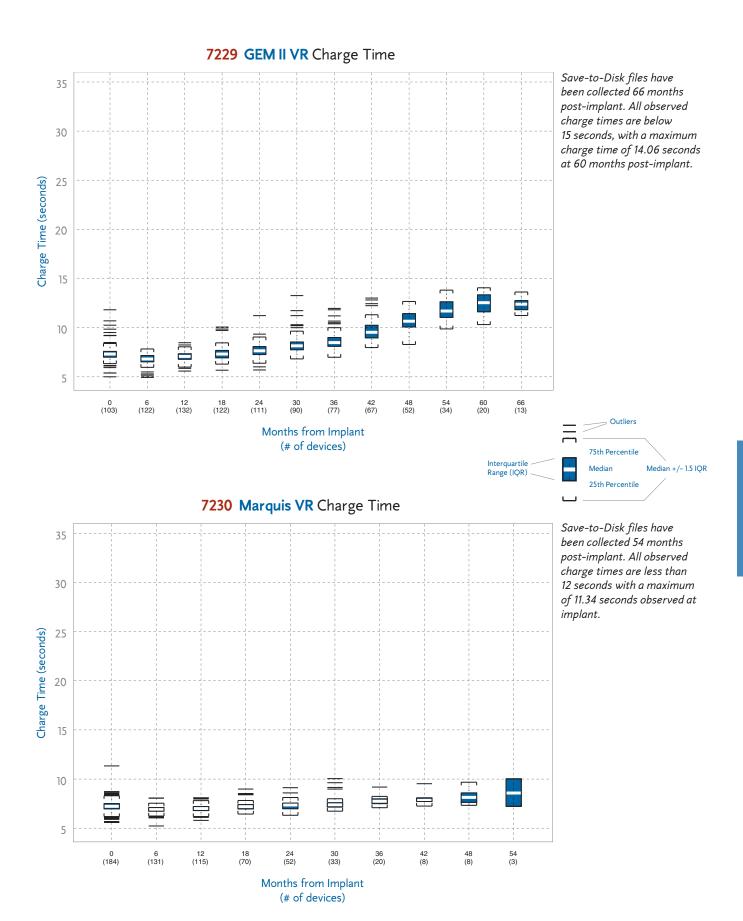
Results

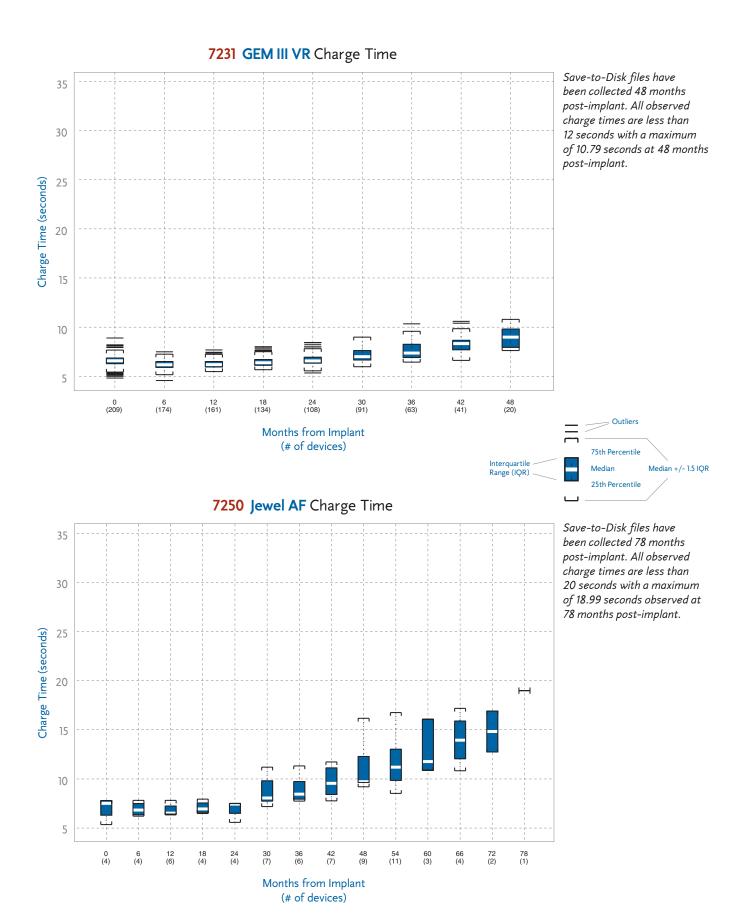
As shown in the graph below, the performance of Medtronic ICD and CRT-D devices has improved. This graph shows the overall maximums, minimums, and medians for Medtronic ICD and CRT-D products, beginning with the 7221 Micro Jewel. A progression toward shorter mean charge times and less variation as occurred between 1996 and 2002. Models released after 2002 have limited experience, but appear to be continuing this performance.

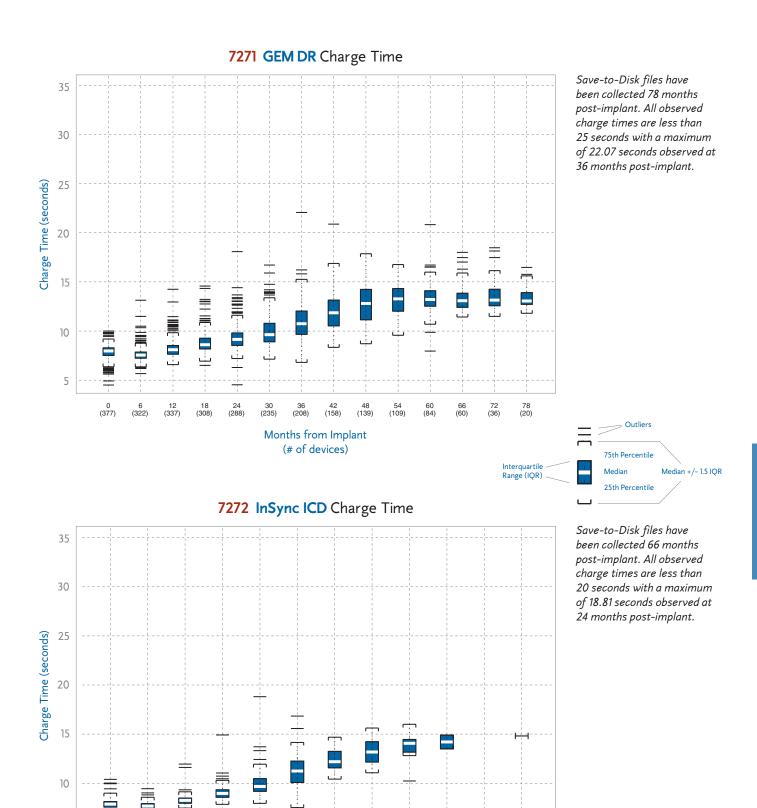








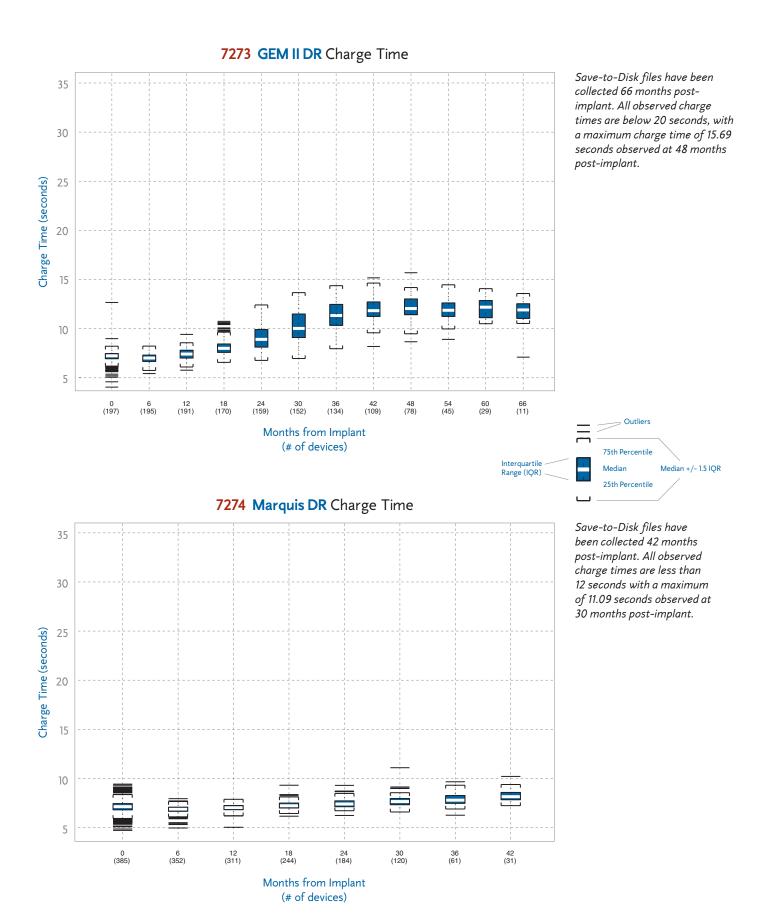


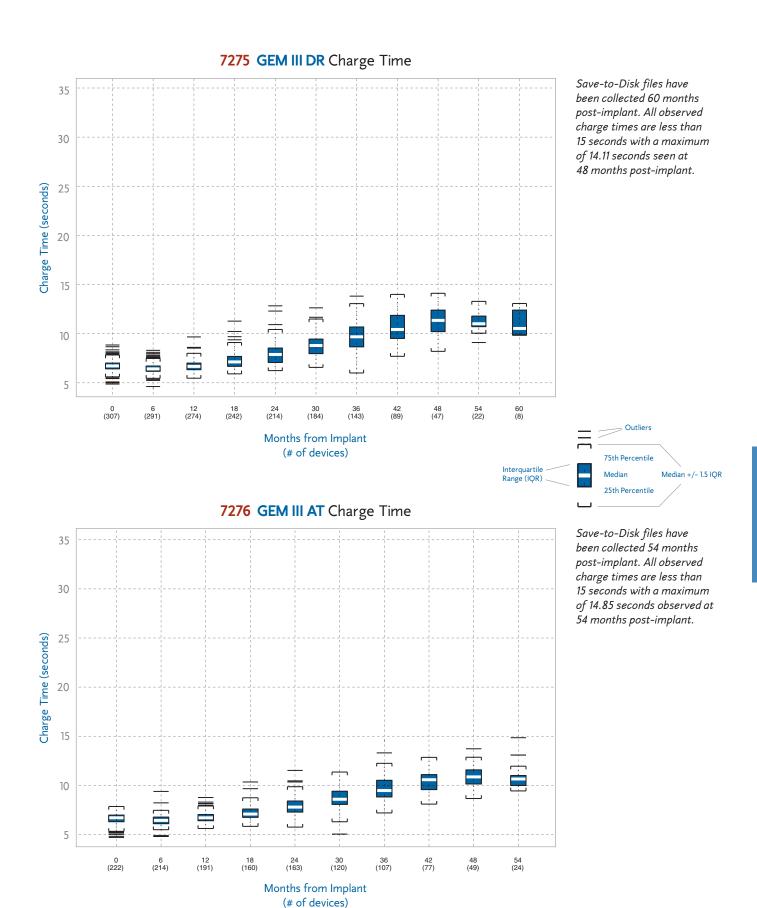


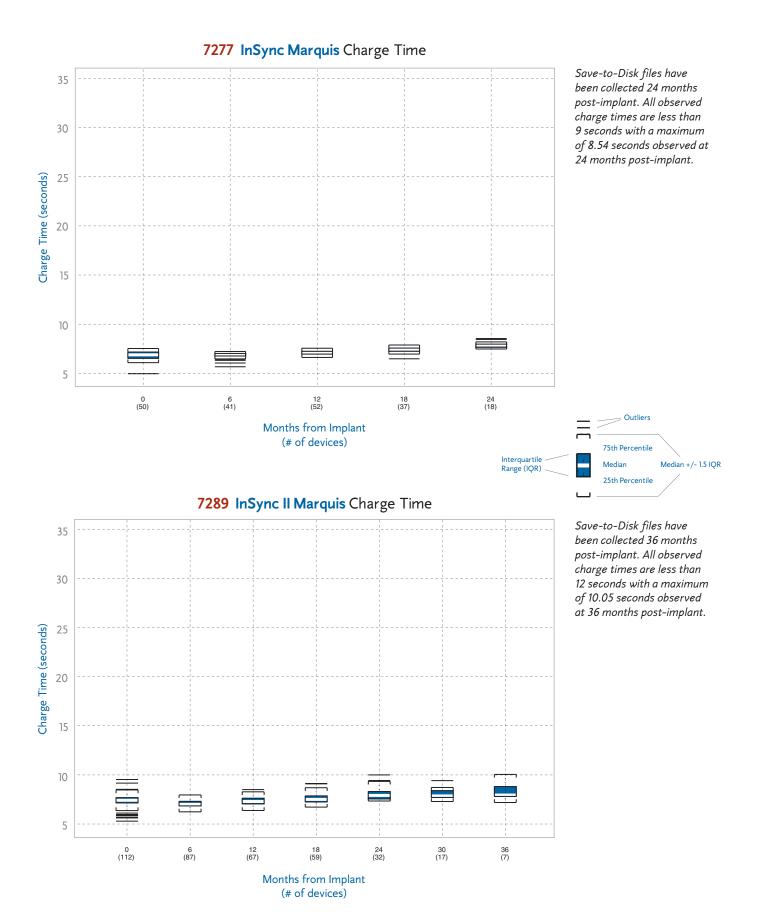
36 (27)

Months from Implant (# of devices)

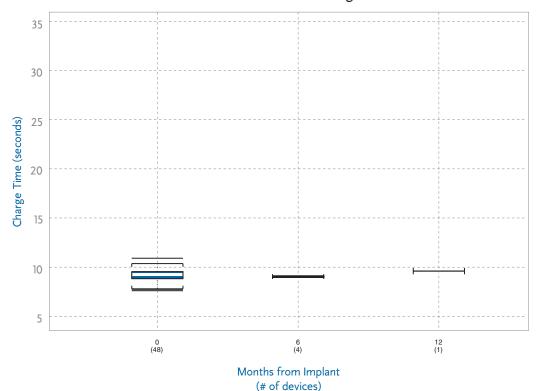
0 (120)





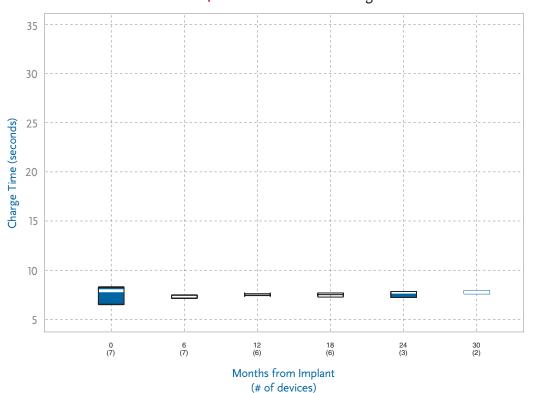






Save-to-Disk files have been collected 12 months post-implant. All observed charge times are less than 12 seconds with a maximum of 10.91 seconds observed at implant.

D153ATG, D153DRG EnTrust Charge Time



Save-to-Disk files have been collected 24 months post-implant. All observed charge times are less than 9 seconds with a maximum of 8.31 seconds observed at implant.

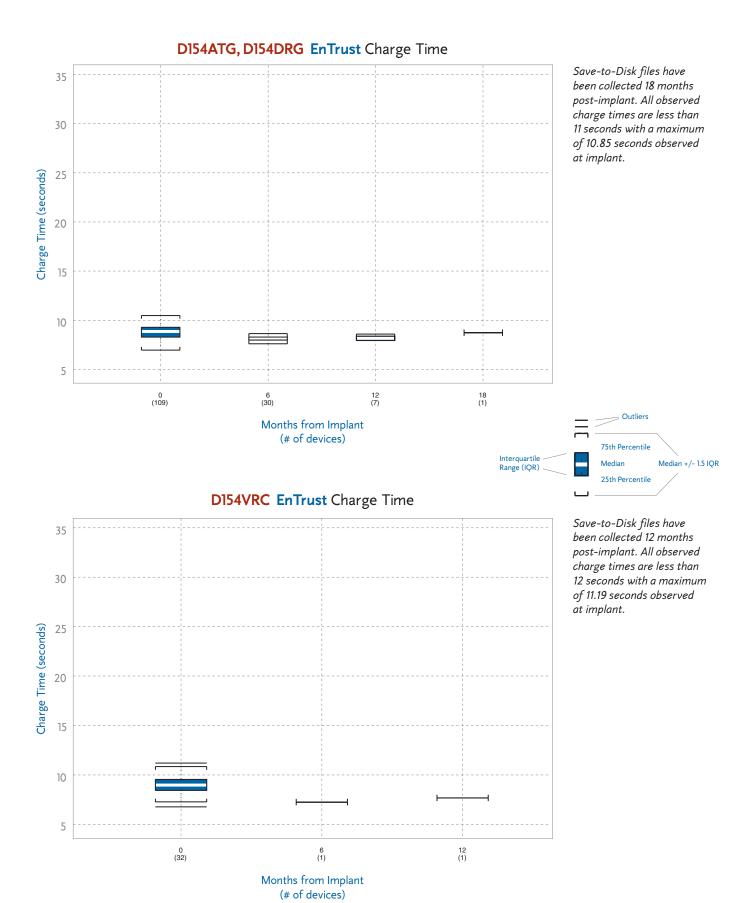
75th Percentile

25th Percentile

Median +/- 1.5 IQR

Interquartile

Range (IQR)



Advisories

Sigma Implantable Pulse Generators

Original Date of Advisory: November 2005

Potential Separation of Interconnect Wires

Product

A specific subset of Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Specific model and serial numbers of affected devices are available online at http://SigmaSNList.medtronic.com.

Advisory

This subset of Sigma series pacemakers that may fail due to separation of interconnect wires from the hybrid circuit may present clinically as loss of rate response, premature battery depletion, intermittent or total loss of telemetry, or no output.

Separation of redundant interconnect wires has been observed on hybrid terminal blocks. Device failure occurs only where both interconnect wires separate from a hybrid terminal block. In October 2005, testing and analysis identified the root cause of these failures and the affected population. Hybrid circuits used in this subset of devices were cleaned during manufacturing with a particular cleaning solvent that could potentially reduce the strength of the interconnect wire bond over time.

Our modeling predicts a failure rate from 0.17% to 0.30% over the remaining lifetime of these pacemakers. No provocative testing can predict which devices may fail.

Patient Management Recommendations

To assist physicians in their patient care and after discussion with physician consultants, Medtronic offers the following recommendations:

- Medtronic does not recommend replacement of these devices prior to normal elective replacement (ERI), based on the low probability of occurrence of a serious event in this population.
- Continue routine follow-up in accordance with standard practice.
- Advise patients to seek attention immediately if they experience return of symptoms (e.g., syncope or light-headedness).
- Determine whether device replacement is warranted on a case-by-case basis based upon consultation with patients, review of the individual

patient's medical history, and consideration of the relative risks of an invasive procedure.

Status Update (January 2007)

The Sigma Family device performance related to the interconnect wires separation mechanism continues to be within Medtronic's engineering projections. As of January 31, 2007, 67 devices out of approximately 40,000 devices worldwide (0.16% incidence) have been confirmed as having experienced interconnect wire separation while implanted. Twenty-four (24) of these devices were returned from the United States. There have been no confirmed serious injuries or deaths due to this issue.

Thirty-four (34) of the 67 devices were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 33 devices were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these devices are conservatively categorized as having experienced interconnect wire separation while implanted.

Implant duration for the 67 devices confirmed as having experienced interconnect wire separation has ranged between 17 and 56 months, with an average of 42 months.

Out of the initial advisory population of 40,000 worldwide, approximately 21,000 remain implanted. Approximately 5,300 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.



7274 Marquis DR 7230 Marquis VR 7278 Maximo DR 7232 Maximo VR

7277 InSync Marquis 7289 InSync II Marquis 7279 InSync III Marquis **7285** InSync III Protect

Original Date of Advisory: February 2005

Potential Premature Battery Depletion Due to Battery Short

Product

The specific subset of Marquis family ICD and CRT-D devices having batteries manufactured prior to December 2003 is affected. Devices manufactured with batteries produced after December 2003 are not affected. Specific model and serial numbers of affected devices are available online at http://MarquisSNList.medtronic.com.

Advisory

Medtronic Marquis family of ICD and CRT-D devices having batteries manufactured prior to December 2003 may experience rapid battery depletion due to a specific internal battery short mechanism. Battery design changes were implemented in December 2003 that eliminate the possibility of this internal shorting mechanism.

Highly accelerated bench testing indicated the rate of this shorting mechanism may increase as the battery is depleted. As of February 2005, the rate of shorting was approximately 1 in 10,000 (0.01%); bench test data indicated the rate may increase to between 0.2% and 1.5% over the second half of device life.

No provocative testing can predict which of these devices will experience this issue. Once a short occurs, battery depletion can take place within a few hours to a few days. After depletion the device ceases to function. It is also possible that as the battery depletes quickly, patients may experience temporary warmth in the area surrounding the ICD.

Patient Management Recommendations

We recommend you consider the following patient management options:

- Conduct quarterly (i.e., every three months) follow-up procedures.
- Inform patients that should they experience warmth in the area surrounding the ICD to seek follow-up care promptly.
- Program Low Battery Voltage ERI Patient Alert to "On-High." This will result in an audible, alternating tone in the limited circumstances where a battery depletes slowly over a number of days. Data indicates most shorts will occur rapidly and will not be detected by this feature.

 Provide a hand-held magnet to patients to check device status and program the Low Battery Voltage ERI Patient Alert to "On-High." Device operation may be monitored periodically (e.g., daily) by patients placing the magnet over the device for 1-2 seconds. If the device is functional, a steady tone will sound for approximately 20 seconds. If no tone is heard, followup care should be sought promptly.

Status Update (January 2007)

The Marquis Family device performance related to the battery shorting mechanism continues to be within Medtronic's engineering projections. As of January 31, 2007, 73 Marquis Family devices have been confirmed as having this internal battery shorting mechanism. Fortythree (43) of these devices were returned from the United States. There have been no confirmed serious injuries or deaths due to this issue.

Of the 73 returns, 29 have been identified by patients reporting warmth in the ICD pocket, 27 by a regularly scheduled follow-up or during a nondevice related hospital visit, 8 by hand-held magnet test or CareLink™ attempt, 5 by return of bradycardia symptoms, and 4 by the Patient Alert sounding.

Implant duration for the 73 devices ranged between 11 to 47 months, with an average of 32 months.

Consistent with Medtronic projections, the observed rate of shorting is higher in the second half of device life than in the first half of device life. Of the devices that have exhibited shorting in the last half of device life, 45% occurred in the last quarter of device life and 31% in the last 10% of device life.

Out of the initial advisory population of 87,000 worldwide, approximately 37,000 remain implanted. Approximately 33.000 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

Warranty

All Marquis devices are subject to a Limited Warranty. Devices returned to Medtronic and determined to be malfunctioning will be replaced or credited in accordance with the warranty terms. In addition, for devices subject to the Marquis advisory, should a physician decide to replace a device for a patient who is pacemaker dependent or who receives frequent VT/VF therapy, Medtronic will, upon receipt of a written statement from the physician setting forth the basis for early replacement of the device, provide a replacement device at no cost. Information as of



Kappa 600, 700 Dual Chamber (D, DR, and VDD) IPGs

Original Date of Advisory: March 15, 2002

Potential Fractured Power Supply Wires

Product

A specific subset of Kappa 700/600 Dual Chamber (D, DR, and VDD) Implantable Pulse Generators have been identified by serial numbers. Hospitals and Physicians were notified. Specific model and serial numbers of affected devices are available by calling US Technical Services at 1 (800) 505-4636.

Advisory

As of March 15, 2002, Medtronic observed 53 related failures (0.02%) in over 255,000 Kappa 700/600 Dual Chamber (D, DR, and VDD) Series devices sold worldwide. Medtronic voluntarily communicated this information to physicians because these failures had been observed in patients having submuscular implants.

These devices have presented with an electrical reset, intermittent output, or no output. Our investigation identified the root cause as fractured wires supplying power to the pacemaker. This has been directly correlated to submuscular placement of these devices. Submuscular implant locations (e.g., subpectoral, abdominal, etc.) can result in additional stress and repetitive flexing on the implanted device causing excessive fatigue on these wires. Of the estimated 4,000 devices implanted submuscular, approximately 200 (5%) may experience this failure. These stresses on the implanted device are unique to submuscular implant sites and do not exist with subcutaneous implants.

Patient Management Recommendations

While there is no provocative testing or time dependency that will predict which submuscular placed device will fail, certain electrical resets may be an indicator that a wire fracture has occurred. Normal electrical resets can occur as a result of electrosurgical procedures such as cautery and ablation or from defibrillation therapy. If none of the normal causes of electrical reset can be confirmed, or if a device serial number presents as "000000" following an electrical reset, this may be an indicator of a wire fracture.

For patients who have submuscular implants of devices within the designated serial number range and who are pacemaker dependent with no underlying rhythm, replacement of the device should be considered. Medtronic will provide the replacement device free-of-charge under the terms of its warranty program if a device is replaced in these patients.

For patients having subcutaneous implants, no change to your current patient care and follow-up is advised.

Status

Device performance related to this advisory continues to be within Medtronic's engineering projections and expectations. Patient management recommendations remain unchanged. As of January 31, 2007, 135 out of approximately 180,000 (0.07% incidence) Kappa family devices worldwide have been confirmed as having fractured power supply wires. Out of the initial implant population of 121,000 in the United States, approximately 57,000 remain implanted.



7227Cx **GEM** 7229Cx GEM II VR

Original Date of Advisory: October 15, 1999

Potential Circuit Overload

Product

Model 7227Cx and Model 7229Cx Implantable Cardioverter Defibrillators supplied before October 15, 1999, with serial numbers ending in an "H." For example, PIPxxxxxxH or PJJxxxxxxH, where x is a variable numeric, may be affected. Specific model and serial numbers of affected devices are available by calling US Technical Services at 1 (800) 723-4636.

IMPORTANT REMINDER:

Medtronic strongly advises physicians who have patients under their care affected by this issue to reprogram the Patient Alert feature "ON" without delay.

Advisory

Manufacturing error in a small percentage of devices may cause circuit overload when $AX \ge B$ High Voltage energy is delivered via an integrated bipolar lead. GEM Model 7227Cx and GEM II VR Model 7229Cx devices with dedicated bipolar sensing leads are not affected by this issue. Devices affected may not be able to subsequently charge to full energy and experience "charge circuit timeout."

Patient Management Recommendations

- Assessment of all patients with the potentially affected devices implanted AND an integrated bipolar ICD lead such as the 6942 and 6945 should take place without delay.
- Reprogram polarity pathway to $B \ge AX$ for all cardioversion and defibrillation therapies.
- Confirm correct device function:
 - Perform a full energy charging sequence.
 - If "charge circuit timeout" is observed, contact your Medtronic representative.
 - If device charges normally, it has not been damaged and will function appropriately with polarity programmed $B \ge AX$.

Recent studies have demonstrated that DFTs are similar or lower in a $B \ge AX$ polarity pathway when compared to $AX \ge B$.

Devices implanted with functional dedicated bipolar leads such as the 6932, 6934S, 6936, 6943, and 6966 are not affected.

Status

Device performance related to this advisory continues to be within Medtronic's engineering projections and expectations. Patient management recommendations remain unchanged. Out of the initial implant population of 10,000 in the United States, approximately 2,900 remain implanted. The devices affected by this advisory are nearing the end of their expected battery longevity.



4504, 4504M CapSure Atrial Lead 4582 Target Tip Atrial Lead

Original Date of Advisory: October 4, 1996

Lead Survival Below Expectations

Product

All Models 4504, 4504M, and 4582 Implantable Pacing Leads

Advisory

Lead survival probability is below expectations and is primarily associated with insulation degradation due to Metal Ion Oxidation (MIO).

Patient Management Recommendations

- Follow patients in accordance with Medicare Guidelines.
- Avoid the use of the AAI or AOO mode.
- During patient evaluation, give careful attention to lead performance such as:
 - Review patient ECG for indications of transient sensing and/or capture abnormalities.
 - Monitor in clinic for impedance less than 250 ohms or a decrease of more than 30% from implant values (or an established baseline using telemetry) which would suggest lead failure.
- Consider the use of unipolar if the pulse generator has this capability.
- At the time of pacemaker system revision (e.g., normal pulse generator or ventricular lead revision), carefully evaluate lead integrity and patient status before choosing to reuse.

Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 17,000 in the United States, approximately 1,700 remain implanted. According to System Longevity Study results, lead survival is estimated to be 66.1% at 8 years, 9 months.



4004, 4004M CapSure Ventricular Lead 4082 Target Tip Ventricular Lead

Original Date of Advisory: October 8, 1993

Lead Survival Below Expectations

Product

All Models 4004/4004M and 4082 Implantable Pacing Leads

Advisory

Lead survival probability is below expectations due primarily to polyurethane insulation failure (MIO) and conductor fracture (associated with "subclavian crush").

Patient Management Recommendations

- Increase, as appropriate, the frequency of patient evaluation through in-clinic visits supplemented with transtelephonic and/or ambulatory monitoring; for example, consistent with Guideline I under Medicare Pacemaker Monitoring Guidelines (50-1 Cardiac Pacemaker Evaluation Services).
- During patient evaluations, give careful attention to lead performance such as:
 - Reviewing patient ECGs carefully for indications of transient sensing and/or capture abnormalities.
 - Monitoring in-clinic for impedances less than 300 ohms or a decrease of more than 30% from implant values (or an established baseline using telemetry) which would suggest lead failure.
 - Eliciting and thoroughly investigating any patient complaints suggestive of lead failure.

- Consider whether prophylactic replacement would be appropriate, especially in patients at high risk, such as pacemaker dependent patients.
- Carefully evaluate lead integrity when performing routine pulse generator replacements. Replace lead if
 - insulation breaches are observed.
 - lead impedance is less than 300 ohms or has decreased by more than 30% from implant values.
 - impedance or voltage threshold measurements vary significantly when multiple readings are taken.
 - if the risk of continued use outweighs the risk associated with implanting a new lead.
- As always, individual circumstances and medical judgment dictate patient care and frequency of follow-up.
- Consider lead replacement during normal pulse generator change-out. Carefully evaluate lead integrity and patient status before choosing to reuse.

Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 97,000 in the United States, approximately 3,100 remain implanted. According to System Longevity Study results, lead survival is 50.6% at 10 years, 9 months.



4012 Target Tip Ventricular Lead

Original Date of Advisory: September 26, 1991

Lead Survival Below Expectations

Product

All Model 4012 Implantable Pacing Leads

Advisory

Lead survival probability beyond 5 years is below expectations due primarily to polyurethane insulation failure (due to ESC and/or MIO) and conductor fracture (associated with "subclavian crush").

Patient Management Recommendations

Consider increasing frequency of monitoring (e.g., from quarterly to bimonthly or monthly). Consider the following activities as part of normal follow-up procedures:

- Monitor for significant changes in impedance which could be an indication of impending failure (pulse generator must have impedance telemetry capabilities).
- Review patient ECGs carefully for indications of transient sensing and/or capture abnormalities. This can be done using transtelephonic or in-clinic monitoring and/or using ambulatory monitoring.
- Elicit any patient complaints suggestive of lead failure and investigate thoroughly lead integrity/per formance characteristics following reports of patient complaints or symptoms using the above techniques.

- Consider whether prophylactic replacement would be appropriate in patients at high risk, such as pacemaker dependent patients.
- Evaluate carefully the integrity of the lead during routine pulse generator replacement before choosing to reuse. Specifically, Medtronic recommends placement of a new lead if:
 - insulation breaches are observed.
 - lead impedance is less than 300 ohms or has decreased by more than 30% from implant values.
 - electrical properties such as impedance and threshold vary significantly when multiple readings are taken.

As always, medical judgment must be used to establish the appropriate schedule and course of care for every individual, particularly pacemaker dependent or other patients at higher risk.

Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 97,000 in the United States, approximately 6,000 remain implanted. The System Longevity Study results show 62.2% lead survival at 15 years, 9 months.



Minix, Minix ST, Micro Minix IPGs

Original Date of Advisory: May 6, 1991

Potential Delayed Restoration of Permanent Settings

Product

All Models of the Minix, Minix ST, and Micro Minix families of Implantable Pulse Generators

Advisory

Possibility of delayed restoration of permanent pacing mode and parameters, after the magnet or programming head is removed under certain conditions.

Patient Management Recommendations

To eliminate any potential risk associated with temporary programming, depress the INTERROGATE KEY and verify successful interrogation before moving the programming head away from the pulse generator. The delay condition can also be terminated by repositioning the programming head and depressing the EMERGENCY VVI key.

Status

Device performance related to this advisory continues to be within Medtronic's engineering projections and expectations. Patient management recommendations remain unchanged. Out of the initial implant population of 65,000 in the United States, approximately 5,300 remain implanted. The devices affected by this advisory are nearing the end of their expected longevity.

Performance Notes

Ensuring the Accuracy of Battery Longevity Estimates

Purpose of This Information

This article is intended to help the clinician understand how Medtronic estimates CRT-D, ICD, and IPG device longevity and Medtronic's performance against these estimates.

Device Longevity and Battery Depletion

The device service life ends when the usable battery capacity is depleted. The time to battery depletion depends on three factors:

- the amount of electrical energy expended in providing therapy to the patient
- the amount of energy consumed by the electronic circuitry to perform the functions of the device (e.g., operating the microprocessor, telemetry, memory, and charging component).
- the energy capacity of the battery

Medtronic has developed a statistical model for device longevity that accounts for each of these factors, and has validated the model with real time clinical performance. During the development of its products, Medtronic engineers characterize device longevity using this model. Testing begins during development and continues after market release to ensure the accuracy of device longevity estimates.

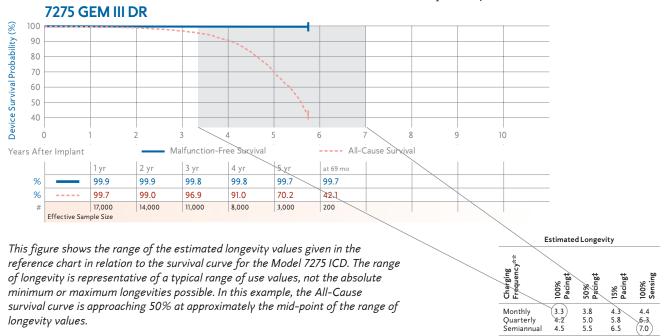
Using Survival Curves to Assess Longevity

The survival curves in the Product Performance Report represent the composite experience of thousands of devices over a wide range of programming options and patient use conditions. While the curves are useful for understanding the overall performance of a population of devices, they cannot be used to accurately predict the longevity of a specific device in a specific patient. To get a longevity prediction for a specific device, the longevity model must be used. The model is available by contacting Medtronic's Technical Services Department.

Because the survival curves are an aggregate result, the Reference pages in the Product Performance Report include several longevity estimates for a range of use conditions. These longevity estimates, originally published in the device Technical Manual, are mean values calculated for the parameters given. This range of longevity estimates can be compared to the all-cause survival curve to assess the overall clinical performance of a device model against the original longevity estimates.

If most of a device model's population is being used at nominal parameters and conditions, the time at which the all-cause survival curve equals 50% should approximate the midpoint in the range of longevity estimates.

If devices tend to be used at conditions that consume more or less energy than nominal, then the time at which the survival curve equals 50% should tend toward the lower or higher end of the range of longevity estimates, respectively.



Interactions between Cardiac Pacing and Ventricular Arrhythmia Initiation.

Purpose of this Information

This article is intended to provide information for consideration when programming pacemaker operation in ICDs and pacemakers.

Background

Right ventricular pacing has been associated with increased risk of appropriate therapy for ventricular tachycardia (VT) and ventricular fibrillation (VF) in ICD patients. Abrupt changes in ventricular cycle lengths (short-long-short, S-L-S) may precede initiation of VT/VF in some instances. S-L-S sequences may be permitted in all forms of cardiac pacing. The pause lengths depend upon pacing mode and lower rate programming.²⁻⁴ Because pauses may be associated with VT/VF initiation, pause suppression algorithms have been developed in ICDs. Although pause suppression may have utility in specific patients with repolarization abnormalities and pause dependent VT, it has not been shown to reduce arrhythmia incidence in the general ICD population.⁵ Conversely, S-L-S sequences may occur with ventricular pacing in a variety of ways, including atrial tracking of premature atrial contractions (PACs) or by terminating pauses with ventricular paced beats.⁶ In some patients, the ectopic depolarization pattern of a ventricular paced beat may be pro-arrhythmic, independent of pause timing. These observations have further enforced the desire to reduce unnecessary ventricular pacing.

Clinical Trial Observations

Medtronic-sponsored clinical trials were retrospectively analyzed to further understand pause-mediated (i.e., S-L-S) scenarios prior to VT/VF. S-L-S onset scenarios were observed in a minority of patients in all pacing modes. Pacemaker interactions prior to VT/VF are dependent on patient conditions, as well as the technical aspects of pacing operation (i.e., pacing mode, lower rate and AV interval). Because a very low frequency of ventricular pacing is observed during Managed Ventricular Pacing (MVP)⁷⁻⁹ or VVI 40 pacing modes¹⁰, the long interval tended to terminate with a ventricular sense. In DDD mode, the long interval tended to be terminated by a ventricular pace. Long intervals of > 1000 ms prior to VT/VF were rare in MVP mode. In these analyses, only an association between cardiac pacing and VT/VF initiation can be observed, causality cannot be established. The ongoing MVP (Managed Ventricular Pacing vs. VVI 40 Pacing) Trial, a 2-year, 1000-patient prospective, randomized trial in ICD patients may offer more insight into the frequency of VT/VF across pacing modes.11

Pacemaker Patients

In pacemaker patients, ventricular pacing has been associated with higher incidence of AT/AF and heart failure hospitalization. 12,13 MVP provides atrial rate support while dramatically reducing ventricular pacing in patients with sinus node dysfunction and transient AV block.9 However, as stated in Medtronic reference manuals, depending upon the patient's intrinsic rhythm and conduction, MVP may allow ventricular cycle variation and occasional pauses of up to twice the lower rate.

DDD pacing with long AV intervals may reduce ventricular pacing and may decrease the potential length of pauses compared to MVP. However, DDD with long AV interval programming does not appear to be as effective as AAI-based pacing modes at reducing ventricular pacing,13,14 may lead to endless loop tachycardia,14,15 and does not completely eliminate pauses. Also, in DDD mode, a higher programmed lower rate or activation of rate response can lead to an increase in AV conduction times and a higher percentage of ventricular pacing. The potential benefits of reducing ventricular pacing must be weighed against the potential for longer ventricular pauses. Therefore, careful consideration should be given to pacemaker mode and lower rate programming, particularly in the setting of frequent AV block and repolarization abnormalities due to congenital Long QT, electrolyte imbalances, and some medications which prolong QT.

Conclusion

Pacemaker operation may interact with VT/VF initiation in a variety of ways. The patient's heart failure status, arrhythmia substrate, medications, and the relative importance of maintaining ventricular synchrony vs. ensuring ventricular rate support must be weighed when choosing optimal hardware (ICD vs. pacemaker) and pacemaker programming (pacing mode, lower rate, etc.).

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AT500 Pacing System Follow-Up Protocol

Purpose of This Information

This article is intended to provide clinical guidance regarding follow-up practice and patient management when the AT500 battery voltage approaches the Elective Replacement Indicator (ERI) level of 2.6 volts.

Background

Many AT500 pacing systems are now reaching their ERI voltage level (2.6 volts). This is expected since the battery used has an approximate longevity of 5-6 years under normal conditions (100% DDD pacing, 3 volts, 0.4 ms).

Technical Services has received reports of battery voltage levels below End-of-Life (EOL of 2.2 volts) where EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary. It is important for physicians and allied professionals to understand battery depletion characteristics between ERI and EOL so that they, in turn, can understand how this affects management of follow-up visits for the AT500 as this device nears the end of its expected longevity.

AT500 Battery and Longevity Information

In contrast to other IPGs, the AT500 does not change its mode, stimulation rate, or any other parameter when the battery voltage drops below the ERI level of 2.6 volts (with or without magnet applied). The Threshold Margin Test (TMT) is also not available.

Therefore, it is not possible to perform trans-telephonic assessment of AT500 battery status. This must be done during an in-clinic follow-up session. A warning will be displayed on the Quick Look screen at the beginning of a programmer (follow-up) session when the ERI battery level occurs. The measured battery voltage will also appear on the programmer display and on printouts.

Battery depletion curves at **common parameter settings** are shown in Figure 1, with special focus on device longevity when programming EGM pre-storage ON or OFF.

Medtronic's review of ongoing AT500 battery life test data matches our original longevity modeling and so meets our expectations. However, when using longer durations between follow-up periods (> 3 months), clinicians should consider the following in setting their remaining longevity expectations.

- Enabling the "EGM Pre-storage On" capability will increase current and reduce device longevity by approximately 9 days for each month pre-storage is ON.
- Longevity decreases with an increase in pacing rate, an increase in pacing amplitude or pulse width, a decrease in pacing impedance, a higher ratio of paced to sensed events, or extended use of the Atrial Preference Pacing, EGM pre-storage, or Holter Telemetry features.

Recommendations

Follow-up frequency should always be accelerated as devices reach ERI voltage levels to ensure device explant/ replacement occurs prior to End-of-Life voltage levels. With the wide variety of follow-up schedules being used, Medtronic recommends a 3-month follow-up frequency for the AT500 pacing systems. This is particularly important for patients in whom EGM pre-storage is programmed ON, or higher outputs and/or pacing rates are necessary.



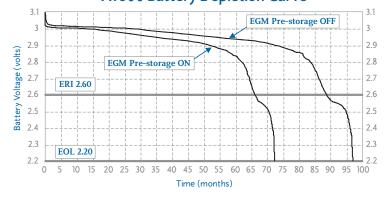


Figure 1

AT500 battery depletion curve for common parameter settings of DDDR, LR 70 ppm, UR 120 ppm, 100% pacing, Atrial - 2 V, 0.4 ms, 600 ohms, Ventricle - 2 V, 0.6 ms, 900 ohms, and EGM Pre-storage ON versus OFF.

Insertion of the Lead into the Device

The implantable system consists of a pulse generator and at least 1 lead. The system operation depends on proper electrical and mechanical operation. With the advent of internationally recognized connector standards the challenge of ensuring proper mechanical fit between the lead and device connectors has been simplified, although the international connector standard does not address all aspects of the procedure for connecting a lead to the device.

If the lead connector is not fully installed, oversensing may result as described in the connector problems section of the technical article, "Clinical Management of High Voltage Lead System Oversensing."

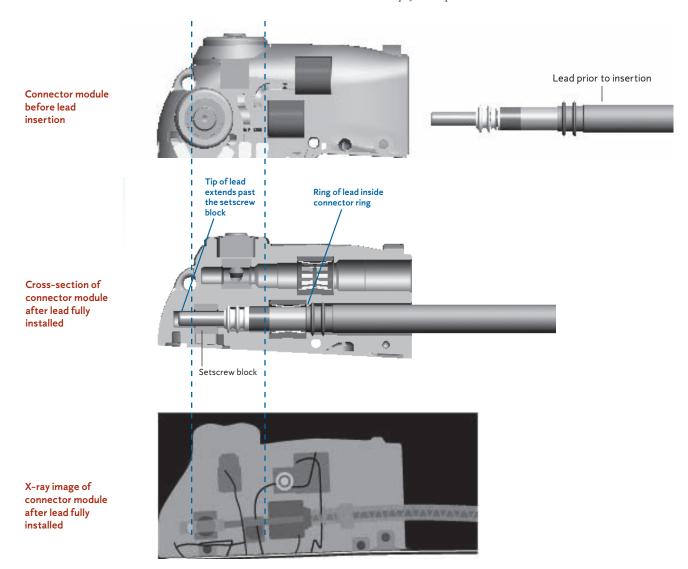
Performing the following steps can be used for each lead connection during the implant procedure.

1 Insert the torque wrench into the appropriate setscrew. For easier lead insertion, insert the lead closest to the device first.

- 2 Look down the connector port to verify that the port is not obstructed. If the port is obstructed, retract the setscrew to clear the bore. Take care not to disengage the setscrew from the connector block.
- **3** Push the lead into the connector port until the lead pin is clearly visible beyond the setscrew block.
- 4 Hold the lead in position while tightening the setscrew until the torque wrench clicks.
- 5 Tug gently on the lead to confirm a secure fit.

Current publications may provide additional information on implant procedures used by others, e.g., radiographic evaluation of the terminal pin beyond the terminal post.1

¹ Pickett RA III, Saavedra P, Ali MF, Darbar D, Rottman JN. Implantable cardioverter-defibrillator malfunction due to mechanical failure of the header connection. J Cardiovasc Electrophysiol. September 2004;15(9):1095-1099.



GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior

Medtronic manufactures and utilizes a unique Lithium/Silver Vanadium Oxide battery in the GEM II/III family of ICDs. This battery has a distinctive voltage discharge with two regions of constant voltage at 3.2 volts and 2.6 volts.

The battery discharge curve (see curve below) is characterized by a significant decrease in the battery voltage approaching Middle-of-Life (MOL), followed by a plateau (MOL to ERI) where the battery voltage remains around 2.6 volts. The transition to the plateau could be easily misinterpreted as the battery rapidly approaches ERI, which occurs at 2.55 volts, when the battery may in fact have several years remaining until ERI.

It is important to understand that this battery voltage decrease in the GEM II/III family of ICDs is a normal

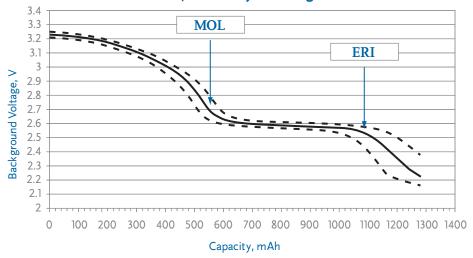
characteristic of the battery function in these devices and should not create a need for additional follow-up or monitoring.

As a general rule of thumb, the longevity from implant to MOL = MOL to ERI.

The design of the recently released Marquis battery has been modified to present a more linear battery discharge curve.

If you are concerned about early ERI in your patient's device, you can utilize the battery trend measurements stored in the save-to-disk file, which can be accessed and interpreted through the Medtronic Technical Services at 1 (800) 723-4636.

GEM II/III Battery Discharge Curve



General Follow-Up and Replacement of ICD Leads

The human body is a hostile environment for an implantable device. Typically, the human body will attack and attempt to isolate or destroy any foreign object. Additionally, implanted leads are subjected to continuous flexural and torsional stresses associated with cardiac activity, body motion, and patient anatomy, which can adversely impact lead integrity.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. Unlike implantable cardioverter defibrillators (ICDs), a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. The determination that a lead may be approaching end of service life requires follow-up of the chronically implanted lead and thorough evaluation of lead integrity at ICD replacement.

Follow-Up of Chronically Implanted Leads

The frequency of follow-up for ICD patients will depend on a number of factors including the patient's medical condition, ICD system implant time, hospital/clinic follow-up practice, and Medicare guidelines. In all cases, it is important to assess the functionality of the ICD system and the integrity. For newly implanted leads, it is beneficial to establish a baseline of chronic performance parameters once the lead has stabilized, generally within 6 to 12 months after implant. These performance parameters should include pacing and sensing thresholds and impedance. During routine patient follow-up, these procedures can be used to evaluate lead integrity.

- Measure pacing and sensing threshold and compare to the chronic baseline. Significant increases or decreases may be indicative of lead failure, dislodgement, perforation, exit block, etc.
- Measure pacing impedance where possible and compare to the chronic baseline. Decreases of 30% or more or pacing impedances below 200-250 ohms may be indicative of insulation failure. Sudden and significant increases in pacing impedance may be indicative of conductor fracture.
- High voltage lead circuit impedance should be between 10-75 ohms at system implant. Chronic measurements below 10 and above 200 ohms may be indicative of high voltage lead circuit failure.
- Carefully review ECGs or the non-sustained detection log on Medtronic ICDs for indications of pacing and/or sensing abnormalities such as oversensing, undersensing, and loss of capture.
- Elicit and investigate any patient complaints/symptoms which may be suggestive of potential lead failure.

Where routine follow-up indicates, additional tools should be used to further evaluate performance. Tools include radiographic data, ICD electrograms, ICD Patient Alert and performance information from the Tachyarrhythmia Chronic Systems Study (TCSS).

The final decision on the functional integrity and continued use of an implanted lead must be a matter of medical judgment based on these factors as well as specific patient conditions.

General Criteria for Lead Replacement

The evaluation of a chronically implanted lead is an important part of the decision to continue to use the lead with a new ICD. However, these results alone do not necessarily predict the future integrity of that lead. With the expected longevity of today's ICDs varying between approximately 5 and 10 years, a physician replacing a device should consider a number of factors, including those listed below.

Factors which should be considered in a decision to replace or continue to use include:

- Pacing and sensing thresholds should be evaluated for the potential to maintain acceptable levels.
- Pacing impedance should be measured. Bear in mind that pacing impedance below 250 ohms results in excessive battery current drain, which may seriously compromise ICD longevity, regardless of lead integrity.
- The physical appearance of the lead should be examined for insulation cracks, breaches, or other indications of lead wear or degradation.
- Medtronic Chronic Systems data should be referenced. Actuarial survival of the lead and the observed lead failure mechanisms are specific factors to consider. Use of a new lead should be considered if failure mechanisms suggest an increased time dependency as suggested in the shape of performance curve for the specific lead model.
- Current publications may provide additional information on the clinical management of leads.^{1,2} Ultimately, the decision to replace an implanted lead involves medical judgment.

¹ Hauser RG, Cannom D, Hayes DL, et al. Long-term structural failure of coaxial polyurethane implantable cardioverter defibrillator leads. PACE. June 2002;25(6):879-882.

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Clinical Management of High Voltage Lead System Oversensing

Appropriate sensing by an ICD system refers to the sensing of cardiac events that may or may not require therapy delivery. ICD systems must sense relatively large QRS complexes while avoiding sensing of smaller T-waves, yet continue to sense often small variable amplitude ventricular fibrillation. Thus ICD systems attempt to dynamically adjust sensing of electrical events, and discriminate between them based on detection algorithms and programmed settings.

Inappropriate sensing can occur when an ICD system classifies events of non-cardiac origin as QRS/VF events, or senses and counts T- and far field P-waves as ventricular depolarizations. This is often referred to as "oversensing," and may result in delivery of inappropriate high voltage therapies. This is due, in part, to the desire to err on the side of delivering life-saving high voltage therapy rather than withholding it. Thus, an ICD system which is experiencing oversensing issues will continue to deliver therapeutic shocks as required, but may also subject the patient to unnecessary shocks.

Oversensing can be difficult to manage, in that the precipitating cause of the oversensing can be problematic to isolate. Oversensing can be caused by many factors, including myopotentials/far field sensing, electromagnetic interference, T-wave sensing, connector issues, incomplete conductor fractures, and insulation breaches. While the individual physician must exercise medical judgment in determination of appropriate clinical management of ICD systems, the chart below may assist in the process of causal factor differentiation and possible intervention.

Phenomenon	Causal Factors	Characteristics	Management/Comments
Myopotentials/ Far Field Sensing	Diaphragmatic muscle potentials in breathing, wide tip-ring (coil on integrated bipolar leads) spacing.	Nonphysiological sensed event on EGM, which may confuse detection potentially resulting in false positive shocks.	Check R-waves for deterioration. Reprogram sensitivity. Try repositioning lead. Consider change- out to true bipolar lead, or if true bipolar lead in use, one with closer tip-ring spacing than current lead.
EMI (Electro-Magnetic Interference)	Arc welders, electrical generators, store walk-through security scanners, poorly insulated electrical equipment.	Multiple and consecutive short intervals (< 140 ms) independent of underlying sinus beats. Associated with proximity to the EMI source.	Avoid EMI areas. True bipolar leads less susceptible.
T-wave Sensing	Drugs, ischemic tissue, exercise, long QT syndrome, electrolyte imbalance.	Sense markers seen on EGM related to T-wave. False positive detection.	Check for R-wave deterioration and characteristics. If R-wave > 3.0 mV, reprogram sensitivity. If R-wave < 3.0 mV, reposition/replace lead. Address causal factor (e.g., drugs [if appropriate/medically viable]).
Connector Problems	Loose setscrew, cross-threaded setscrew, incomplete lead insertion into header.	This is an acute phenomenon seen within 6 months of implant (usually sooner).	Requires invasive check of connections. May be reproducible with pocket manipulation.
Incomplete Conductor Fracture	One or more filars of a multifilar conductor fracturing while leaving enough filars intact to provide a conduction circuit.	Characterized by chaotic oversensing related to motion of the fracture site.	Check EGMs and x-rays. Manipulate lead at suspected fracture site if possible as a provocative test. If confirmed, replace lead.
Lead Insulation Breach	Cuts, tears, metal ion oxidization, abrasion, cold flow, environmental stress cracking.	Characterized by cyclical and/or erratic, intermittent, spontaneous oversensing; often post-pace or post-shock can cause false positives.	Replace lead. If acute, usually secondary to implant damage/ replacement damage. If late, material characteristic.

Technical Services is available at all times to advise clinicians in the troubleshooting and management of Medtronic products. For assistance in the United States, please call 1 (800) 723-4636. In other countries, please contact your local Medtronic representative.

Tests and Observations for Clinical Assessment of Chronic Pacing Leads

Test/Observation	Possible Insulation Failure	Possible Conductor Failure	Possible Other System Failure	Affect on Test/ Observation
Pacing Impedance (Telemetered or Measured Invasively)	Sudden and Significant Decrease	Sudden and Significant Increase	Dislodgement	. Increase or Decrease . Increase or Decrease
Pacing Thresholds (Telemetered/Programmed or Measured Invasively)	Sudden and Significant Increase Especially in Bipolar System	Sudden and Significant Increase	Dislodgement	.Increase .Increase .Increase
Electrograms (Telemetered or Measured Invasively)	Sudden and Significant Decrease in Amplitudes and/or Slew Rates for P- and/or R-Waves	Sudden and Significant Decrease or Disappearance of Amplitudes and/or Slew Rates for P- and/or R- Waves	Dislodgement Perforation Infarct at Electrode Site Electrolyte Imbalance Improper IPG/Lead Connection	Decrease Decrease Decrease
Waveform Analysis (Oscillographs of Pacer Artifact from ECG Electrodes)	Sudden Increase in Ratios of Leading-Edge Voltages to Trailing-Edge Voltages (i.e., over 25% increase)	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)	Improper IPG/Lead Connection	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)
Radiographs (Post-Implant, Recent, Current)	Not Discernible	Visual Observation of Conductor/Connector/ Electrode Fracture (Sometimes Discernible)	Dislodgement or Perforation. Improper IPG/Lead Connection.	Sometimes Discernible
Visual Inspection (Invasive)	Insulation Breach and/or Degradation, or Ligature Cut-Through	Not Easily Discernible	Connector Defect or Connector Pulled Apart. Improper IPG/ Lead Connection.	Sometimes Discernible
Pectoral Muscle Stimulation	Sudden Onset Especially in Bipolar System		Connector Defect in Bipolar or Unipolar. Hypersensitivity to Unipolar Pulse Generator Can. Anti-Stim Coating or Protection Deficient.	
Phrenic Nerve/ Diaphragmatic Stimulation	Sudden Onset in Bipolar or Unipolar Systems		Perforation or Displacement of Atrial Lead (Phrenic Nerve)	
Pacemaker ECG Stimulus Artifact Size and Morphology Change (May Not Be Possible with Digital ECG)	Sudden Onset and Significant Change, Especially in Bipolar System (Increase in Size)	Sudden Changes, Usually a Decrease in Size	Perforation or Dislodgement. Connector Defect. Improper IPG/Lead Connection.	Sometimes Discernible
Oversensing (Intermittent or Continuous)	Sudden Onset, Especially in Bipolar Systems		Physical Contact between the Electrode(s) on the Lead and that of Another Lead. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Undersensing (Intermittent or Continuous)	Sudden Onset in Either Unipolar or Bipolar Systems	Sudden Onset in Either Unipolar or Bipolar Systems	Dislodgement or Perforation. Infarct at Electrode Site. Electrolyte Imbalance. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Loss of Capture	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	

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If you are looking for a model number or family that is not included in this report, you may call US Technical Services (see page 2).

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Mailer Kits Available for Returning Product

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use. The procedures for returning product vary by geographic location.

Mailer kits (pictured right) with prepaid US postage are available for use within the United States to send CRT, ICD, IPG, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of devices from non-clinical sources such as funeral homes, and will assume responsibility for storage and disposal of the product once received. For return of larger quantities of explanted products than the mailer can accommodate, Medtronic has handling and shipping guidelines available upon request.

Both mailers and guidelines can be requested by contacting the Returned Product Lab. For information on how to contact the Lab, refer to Contact Information on page 2 of this report.



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